

Department of Electronics and Communication Engineering

Bachelor of Technology

Electronics and Communication Engineering

Curriculum

University Vision

We visualize Graphic Era (Deemed to be University) as an internationally recognized, enquiry driven, ethically engaged diverse community, whose members work collaboratively for positive transformation in the world, through leadership in teaching, research and social action.

University Mission

The mission of the university is to promote learning in true spirit and offering knowledge and skills in order to succeed as professionals. The university aims to distinguish itself as a diverse, socially responsible learning community with a high-quality scholarship and academic rigor.

Department Vision

The Department visualizes itself to become leading centre of learning in the field of Electronics & Communication Engineering with academic excellence in research to produce self-motivated, creative, and socially responsible engineers and specialists, ready to take up challenges of industrial development with ethics and societal commitment.

Department Mission

M1: To provide high quality contemporary education in the field of Electronics & Communication Engineering and professional ethics to its learners.

M2: To provide creative learning environment for the students to equip them with strong foundation for continuing higher education.

M3: To pursue research and develop insight knowledge of current and emerging technologies in Electronics & Communication Engineering to serve the needs of the society, industry, and scientific community.

M4: To prepare students to have creative and innovative thinking to develop them into socially responsible professionals

Program Educational Objectives (PEOs):

PEO1	Inculcation of an ability to realize and apply the subject-related knowledge to the real-world problems in the areas of electronics and communication engineering.
PEO2	Motivating individuals for team-led effort to investigate and provide ecologically sustainable, and cost-effective solutions to the problems in the subject area.
PEO3	Encouragement of competence in engineering computational and experimental capabilities to pursue research oriented higher education.
PEO4	Establishment of all-round environment for well conversant, socially and ethically responsible individuals with excellent communication skills.

Program Outcomes (POs):

PO1	Engineering knowledge: Apply the knowledge of mathematics, science, engineering fundamentals, and an engineering specialization to the solution of complex engineering problems.
PO2	Problem analysis: Identify, formulate, review research literature, and analyze complex engineering problems reaching substantiated conclusions using first principles of mathematics, natural sciences, and engineering sciences.
PO3	Design/development of solutions: Design solutions for complex engineering problems and design system components or processes that meet the specified needs with appropriate consideration for the public health and safety, and the cultural, societal, and environmental considerations.
PO4	Conduct investigations of complex problems: Use research-based knowledge and research methods including design of experiments, analysis and interpretation of data, and synthesis of the information to provide valid conclusions.
PO5	Modern tool usage: Create, select, and apply appropriate techniques, resources, and modern engineering and IT tools including prediction and modeling to complex engineering activities with an understanding of the limitations.
PO6	The engineer and society: Apply reasoning informed by the contextual knowledge to assess societal, health, safety, legal and cultural issues and the consequent responsibilities relevant to the professional engineering practice.
PO7	Environment and sustainability: Understand the impact of the professional engineering solutions in societal and environmental contexts, and demonstrate the knowledge of, and need for sustainable development.
PO8	Ethics: Apply ethical principles and commit to professional ethics and responsibilities and norms of the engineering practice.
PO9	Individual and teamwork: Function effectively as an individual, and as a member or leader in diverse teams, and in multidisciplinary settings.
PO10	Communication: Communicate effectively on complex engineering activities with the engineering community and with society at large, such as, being able to comprehend and write effective reports and design documentation, make effective presentations, and give and receive clear instructions.
PO11	Project management and finance: Demonstrate knowledge and understanding of the engineering and management principles and apply these to one's own work, as a member and leader in a team, to manage projects and in multidisciplinary environments.
PO12	Life-long learning: Recognize the need for and have the preparation and ability to engage in independent and life-long learning in the broadest context of technological change.

Program Specific outcomes (PSOs):

PSO1	Create an ability to understand theoretical and practical concepts of Electronics and Communication Engineering and apply them in designing, fabrication, and testing of various Electronics & Communication system.
PSO2	The ECE Graduates will be able to analyze and implement engineering system pertaining to communication, Signal Processing, VLSI, Radio Frequency communication, microprocessor; microcontroller-based system design and embedded systems etc.
PSO3	This program enables the student to succeed in competitive exam like GATE, IES etc. and provides foundation for higher education and research.



Program Course Structure (All Semesters)

B. Tech (Electronics and Communication Engineering)

(Batch 2021 onwards)

Semester I & II

COURSE MODULE				TEACHING PERIODS			WEIGHTAGE: EVALUATION			
THEORY SUBJECT			Ŧ	т	р	CWA	MSE	EGE	TOTAL	
CODE	TITLE	COMPONENT	CREDITS		1	Г	CWA	MSE	ESE	TOTAL
TEC 101/201	Basic Electronics Engineering	ESC	3	3	0	0	25	25	50	100
LABORA	TORY									
PEC 151/251	Basic Electronics Engineering Lab	ESC	1	0	0	2	25	25	50	100
	TOTAL		4	3	0	2				200



	COURSE MODULE				ACH ERIO	ING DS	WEIGHTAGE: EVALUATION			
THEOR	RY SUBJECTS		CDEDITS	т	т	Б	CWA	MSE	ESE	тотат
CODE	TITLE	COMPONENT	CREDITS	L	1	Р	CWA		ESE	IOIAL
TEC 301	Electronic Devices and Circuits	PCC	3	3	0	0	25	25	50	100
TEC 302	Digital Electronics	PCC	3	3	0	0	25	25	50	100
TEC 303	Networks Analysis and Synthesis	PCC	3	3	0	0	25	25	50	100
TEC 304	Signals and Systems	PCC	3	3	0	0	25	25	50	100
TMA 310	Advanced Engineering Mathematics	BSC	3	3	0	0	25	25	50	100
XCS 301	Career Skills	HSMC	2	2	0	0	25	25	50	100
LABOR	ATORY AND OTHERS									
PEC 301	Electronics Circuit Lab	PCC	1	0	0	2	25	25	50	100
PEC 302	Digital Electronics Lab	PCC	1	0	0	2	25	25	50	100
PEC 303	Networks Lab	PCC	1	0	0	2	25	25	50	100
GP 301	General Proficiency	GP	1	0	0	0	-	-	-	100
	TOTAL		21	17	0	06				1000



Semester IV

	COURSE M	IODULE		TEACHING PERIODS			WEIGHTAGE: EVALUATION			
THEOR	Y SUBJECTS		CDEDITS	т	т	D	CWA	MSE	FSF	τοται
CODE	TITLE	COMPONENT	CREDIIS	L	I	1	CWA	MSE	LSE	IOIAL
TEC 401	Communication Systems I	PCC	3	3	0	0	25	25	50	100
TEC 402	Analog Integrated Circuits	PCC	3	3	0	0	25	25	50	100
TEC 403	Microprocessor and its Applications	PCC	3	3	0	0	25	25	50	100
TEC 404	Electromagnetic Field Theory	PCC	3	3	0	0	25	25	50	100
TOE	Open Elective I	OEC	3	3	0	0	25	25	50	100
XCS 401	Career Skills	HSMC	2	2	0	0	25	25	50	100
LABOR	ATORY AND OTHERS									
PEC 401	Communication Systems I Lab	PCC	1	0	0	2	25	25	50	100
PEC 402	Analog Integrated Circuits Lab	PCC	1	0	0	2	25	25	50	100
PEC 403	Microprocessor Lab	PCC	1	0	0	2	25	25	50	100
POE	Open Elective Lab-I	OEC	1	0	0	2	25	25	50	100
GP 401	General Proficiency	GP	1	0	0	0	-	-	-	100
	TOTAL		22	17	0	08				1100
Mandato	ry Non - Credit Course									
MC 401	Constitution of India	MC	0	0	0	0	0	0	0	0



Semester V

	COURSE N	IODULE		TEACHING PERIODS			WEIGHTAGE: EVALUATION			
THEOR	Y SUBJECTS		CDEDITS	Ţ	т	Ъ	CWA	MCE	DSE	TOTAL
CODE	TITLE	COMPONENT	CREDITS	L	1	P	CWA	MSE	ESE	IUIAL
TEC 501	Digital Signal Processing	PCC	3	3	0	0	25	25	50	100
TEC 502	Communication Systems II	PCC	3	3	0	0	25	25	50	100
TEC 503	Microcontroller and Embedded Systems	PCC	3	3	0	0	25	25	50	100
TEC 504	Antenna and Wave Propagation	PCC	3	3	0	0	25	25	50	100
TEC	Program Elective I	PEC	3	3	0	0	25	25	50	100
XCS 501	Career Skills	HSMC	2	2	0	0	25	25	50	100
LABOR	ATORY AND OTHERS									
PEC 501	Digital Signal Processing Lab	PCC	1	0	0	2	25	25	50	100
PEC 502	Communication Systems II Lab	PCC	1	0	0	2	25	25	50	100
PEC 503	Microcontroller & Embedded Lab	PCC	1	0	0	2	25	25	50	100
GP 501	General Proficiency	GP	1	0	0	0	-	-	-	100
	TOTAL		21	17	0	06				1000



Semester VI

	COURSE MODULE				ACH ERIO	ING DS	WEIGHTAGE: EVALUATION			
THEOR	Y SUBJECTS			T.	т	р	CINA	MCE	ECE	TOTAL
CODE	TITLE	COMPONENT	CREDITS	Ľ	•	•	CWA	MSE	ESE	IUIAL
TEC 601	Wireless Communication	PCC	3	3	0	0	25	25	50	100
TEC 602	Microwave Engineering	PCC	3	3	0	0	25	25	50	100
TEC 603	VLSI Technology and Design	PCC	3	3	0	0	25	25	50	100
TEC	Program Elective II	PEC	3	3	0	0	25	25	50	100
TOE	Open Elective II	OEC	3	3	0	0	25	25	50	100
XCS 601	Career Skills	HSMC	2	2	0	0	25	25	50	100
LABOR	ATORY AND OTHERS									
PEC 601	CAD of Electronics using CADENCE tool Lab	PCC	1	0	0	2	25	25	50	100
PEC 602	Microwave and Antenna Lab	PCC	1	0	0	2	25	25	50	100
PVL 603	Fading Channels and Mobile Communications	PCC	1	0	0	2	25	25	50	100
POE	Open Elective Lab-II	OEC	1	0	0	2	25	25	50	100
PMP 604	Mini Project	PROJ	1	0	0	2	25	25	50	100
GP 601	General Proficiency	GP	1	0	0	0	-	-	-	100
	TOTAL		23	17	0	10				1200



Semester VII

	COURSE MODULE				ACHI ERIO	ING DS	WEIGHTAGE: EVALUATION			
THEOR	Y SUBJECTS			-	T	n l			ESE	TOTAL
CODE	TITLE	COMPONENT	CREDITS	L	Т	Р	CWA	MSE		TOTAL
TEC 701	Principles of Management	HSMC	3	3	0	0	25	25	50	100
TEC	Program Elective III	PEC	3	3	0	0	25	25	50	100
TEC	Program Elective IV	PEC	3	3	0	0	25	25	50	100
TEC 731	Disaster Management	ESC	2	2	0	0	25	25	50	100
LABOR	ATORY AND OTHERS									
PEC 701	Project Phase-I	PROJ	5	0	0	10	100	-	-	100
SEC 701	Seminar on Industrial Training	PROJ	1	0	0	2	100	-	-	100
GP 701	General Proficiency	GP	1	0	0	0	-	-	-	100
	TOTAL		18	11	0	12				700



Semester VIII

	COURSE MODULE				TEACHING PERIODS			WEIGHTAGE: EVALUATION			
THEORY SUBJECTS			CREDITS	T.	т	Р	CIWA	MSE	DOD	тоты	
CODE	TITLE	COMPONENT	CREDITS	Ľ	T	•	CWA	MSE	ESE	IUIAL	
TOE 	Open Elective III	OEC	3	3	0	0	25	25	50	100	
TEC	Program Elective V	PEC	3	3	0	0	25	25	50	100	
TEC	Program Elective VI	PEC	3	3	0	0	25	25	50	100	
LABOR	ATORY AND OTHERS										
PEC 801	Project Phase-II	PROJ	9	0	0	18	50	-	150	200	
GP 801	General Proficiency	GP	1	0	0	0	-	-	-	100	
	TOTAL		19	9	0	18				600	



Program Elective Courses							
Course Code	Course Name	Semester					
	Program Elective I						
TEC 552	Control Systems						
TEC 553	Electromagnetic Interference and Compatibility	T :64L					
TEC 554	High Speed Communication Circuits	rntn					
TEC 555	Probability and Stochastic Processes						
	Program Elective II						
TEC 651	Data Communication Networks						
TEC 652	Digital VLSI Circuit Design	Sizth					
TEC 653	Semiconductor Materials and Devices	Sixui					
TEC 654	Digital Video Processing						
	Program Elective III						
TEC 751	Optical Fiber Communications						
TEC 752	ASIC Design and FPGA	Soventh					
TEC 753	Radar and Navigation Aids	Seventin					
TEC 754	Organic Electronics Devices and Circuits						
	Program Elective IV						
TEC 755	Wireless Sensor Network						
TEC 756	Fundamentals of Nanotechnology	Soventh					
TEC 757	CMOS Analog Circuit Design	Seventin					
TEC 758	Speech Processing						
	Program Elective V						
TEC 851	Satellite Communications						
TEC 852	Testing of VLSI circuits	Fighth					
TEC 853	Digital System using VHDL						
TEC 854	Digital Image Processing						
	Program Elective VI						
TEC 855	Telecommunication Switching	Eighth					



TEC 856	Neural Networks & Machine Learning	
TEC 857	Mobile Ad hoc Networks	
TEC 858	Adaptive Signal Processing	



	Open Elective Courses				
Course Code	Semester				
	Open Elective-I				
TOE 410	Data Structures with C				
TOE 411	Electrical Machines-I	Fourth			
TOE 412	Computer Based Numerical and Statistical Technique	rourti			
	Open Elective Lab-I				
POE 410	Data Structures with C Lab				
POE 411	Electrical Machines Lab-1	Fourth			
POE 412 CBNST Lab					
Open Elective-II					
TOE 610	Object Oriented Programming with C++				
TOE 611	Power Electronics	Sixth			
TOE 612	Operating Systems				
	Open Elective Lab-II				
POE 610	OOPs with C++ Lab				
POE 611	Power Electronics Lab	Sixth			
POE 612	Operating Systems Lab				
	Open Elective-III				
TOE 810	Computer Architecture				
TOE 811	Electrical and Electronics Measuring Instruments	Eighth			
TOE 812	Biosensors and Bioelectronics				



Abbreviations:

L	Lecture
Τ	Tutorial
Р	Practical
CWA	Class Work Assessment
MSE	Mid Semester Exam
ESE	End Semester Exam
BSC	Basic Science Course
ESC	Engineering Science Course
HSMC	Humanities and Social Sciences including Management course
PCC	Professional Core Course
PEC	Professional Elective Course
OEC	Open Elective Course
MC	Mandatory Course
PROJ	Project
GP	General Proficiency



Bloom's Taxonomy for Curriculum Design and Assessment

Preamble

The design of curriculum and assessment is based on Bloom's Taxonomy. A comprehensive guideline for using Bloom's Taxonomy is given below for reference.





B. Tech in Electronics and Communication Engineering Semester First/Second Subject Title Basic Electronics Engineering Code TEC 101/201 Course Component Credits Contact Hours 3 0 0 Engineering Science Course (ESC) 03 Contact Hours 3 0 0 Examination Duration (Hrs) Theory Weightage: Evaluation CWA MSE ESE Upon completion of this course, the students will be able to Course Outcomes Course Outcomes Upon completion of this course, the students will be able to CO CO 1 Remember operations on number systems and understand concepts of digital circuits. CO Apply the basics of PN junction diode in rectifier circuits and DC power supply. CO 4 Analyze Bipolar Junction Transistor (BTT) from its basic concepts and biasing circuits. Formation its performance of operational amplifier (OP-amp) from its performance parameters like gain. CMRR, offset values etc. Hours Unit No. Content Hours Hours Unit No. Content Hours Unit No. Content Hours Unit No. Content <th< th=""><th></th><th>Departm</th><th>ent of Electronics of</th><th>and Communication Eng</th><th>ineering</th><th>,</th><th></th></th<>		Departm	ent of Electronics of	and Communication Eng	ineering	,	
Semester First/Second Subject Title Basic Electronics Engineering Code TEC 101/201 Course Component Credits Contact Hours I T P Engineering Science Course (ESC) 03 Contact Hours 3 0 0 Examination Duration Theory Weightage: Evaluation CWA MSE ESE Upon completion of this course, the students will be able to 25 25 50 CO21 Remember operations on number systems and understand concepts of digital circuits. CO3 Apply the basics of PN junction diode. curve Outcomes C04 Analyze Bipolar Junction Transistor (BTT) from its basic concepts and biasing circuits. CO4 Analyze Bipolar Junction forther visues etc. CO6 Evaluate the performance of operational amplifier (OP-amp) from its performance parameters. Number systems & Boolean Algebra: Hours Unit No. Content Hours Hours 10 Unit No. Content Hours 10 Unit No. Content Hours 10 Unit No. Content Hours 10		B. Tech in Electronics and Communication Engineering					
Course ComponentCreditsContact HoursILTPEngineering Science Course (ESC)03Contact Hours300Examination Duration (Hrs)Theory 03Weightage: EvaluationCWAMSEESE(Hrs)03Evaluation252550Pre-requisite: Basic Semiconductor PhysicsCourse OutcomesUpon completion of this course, the students will be able toCO12Understand the basics of semiconductors and PN junction diode.CO2Understand the basics of PN junction diode in rectifier circuits and DC power supply.CO4Analyze Bipolar Junction Transistor (BJT) from its basic concepts and biasing circuits.CO4Analyze Bipolar Junction Transistor (BJT) from its basic concepts and biasing circuits.CO4Analyze Bipolar Junction Transistor (BJT) from its basic concepts and biasing circuits.CO4Analyze Bipolar Junction Transistor (BJT) from its basic concepts and biasing circuits.CotentHoursNumber Systems & Boolean Algebra:Number Systems & Boolean Algebra:Number Systems & Boolean Algebra:Number Systems ad their conversion, Addition & subtraction of biary, Octaland hexadecimal numbers, Multiplication & division of binary, Octaland hexadecimal numbers, Sulp	Semester	r First/Second Subject Title Basic Electronics Engineering Code		TEC 101/201			
Engineering Science Course (ESC) 03 Contact Hours 3 0 0 Examination Duration (Hrs) Theory Weightage: Evaluation CWA MSE ESE Statistic: Basic Semiconductor Physics 25 25 50 Course Outcomes Upon completion of this course, the students will be able to CO1 Remember operations on number systems and understand concepts of digital circuits. CO2 Understand the basics of semiconductors and PN junction diode. CO3 CO3 Apply the basics of PN junction diode in rectifier circuits and DC power supply. CO4 Analyze Bipolar Junction Transistor (BJT) from its basic concepts and biasing circuits. Evaluate the performance of operational amplifier (OP-amp) from its performance parameters like gain, CMRR, offset values etc. Evaluate the performance of operational amplifier (OP-amp) from its performance parameters like gain, CMRR, offset values etc. Evaluation of binary, Octal and hexadecimal numbers, Multiplication & division of binary, Octal and hexadecimal numbers, Multiplication & division of binary, Octal and hexadecimal numbers, Multiplication & division of binary, Octal and hexadecimal numbers, SOP & POS form to canonical form, Simplification of Boolean function: Algebraic method, Karnaugh map method (two, three & four variable K-map with don't care condition). 10 Unit 1: Basies o	Course	Component	Credits		L	Т	Р
Examination Duration (Hrs) Theory 0.3 Weightage: Evaluation CWA 25 MSE ESE 25 Pre-requisite: Basic Semiconductor Physics Course Outcomes Upon completion of this course, the students will be able to CO1 Remember operations on number systems and understand concepts of digital circuits. CO2 Understand the basics of PN junction diode in rectifier circuits and DC power supply. CO4 Analyze Bipolar Junction Transistor (BJT) from its basic concepts and biasing circuits. CO5 Evaluate the performance of operational amplifier (OP-amp) from its performance parameters like gain, CMRR, offset values etc. CO6 Design and develop various basic electronic circuits. Unit No. Content Wimber Systems & Bolean Algebra: Number Systems and their conversion, Addition & subtraction of binary numbers, fractional numbers, Logic gates, Boolean algebra, Implementation of basic gates using universal gates, Implementation of logic functions using basic four variable K-map with don't care condition). 10 Unit 1: Basics of Semiconductor Devices and is Applications: Energy band theory: Classification of solids based on energy band diagram, Semiconductors, Infri and diffusion current, P-N Junction; Formation of depletion region, V-I characteristics of P-N junction diodes, Diode breakdown mechanism. 8 Unit 3: AC to DC	Enginee Cou	ering Science rse (ESC)	03	Contact Hours	3	0	0
(Hrs) 03 Evaluation 25 25 50 Pre-requisite: Basic Semiconductor Physics Course Outcomes Upon completion of this course, the students will be able to COURS Outcomes CO1 Remember operations on number systems and understand concepts of digital circuits. CO3 Apply the basics of PN junction diode in rectifier circuits and DC power supply. CO4 Analyze Bipolar Junction diode in rectifier circuits and DC power supply. CO6 Design and develop various basic electronic circuits. Unit No. Content Hours Systems & Boolean Algebra: Number Systems & Boolean Algebra: Number Systems and their conversion, Addition & subtraction of binary numbers, fractional numbers, Multiplication & division of binary numbers, fractional numbers, Multiplication & division of binary numbers, Corversion from SOP & POS form of logic capression, Canonical form, Conversion from SOP & POS form of canonical form, Simplification of Boolean function: Algebraic method, Karnaugh map method (two, three & four variable K-map with don't care condition). Basics of Semiconductor Devices and its Applications: <th>Examina</th> <td>tion Duration</td> <td>Theory</td> <td>Weightage:</td> <th>CWA</th> <th>MSE</th> <td>ESE</td>	Examina	tion Duration	Theory	Weightage:	CWA	MSE	ESE
Pre-requisite: Basic Semiconductor Physics Course Outcomes Course Outcomes Upon completion of this course, the students will be able to CO 1 Remember operations on number systems and understand concepts of digital circuits. CO 2 Understand the basics of semiconductors and PN junction diode. CO 3 Apply the basics of PN junction diode in rectifier circuits and DC power supply. CO 4 Analyze Bipolar Junction Transistor (BJT) from its basic concepts and biasing circuits. CO 6 Design and develop various basic electronic circuits. Unit No. Content Hours Implementation of binary numbers, fractional numbers, Multiplication & division of binary numbers, fractional numbers, Multiplication & division of binary numbers, fractional numbers, Logic gates, Boolean algebra, Implementation of basic gates & universal gates, SOP & POS form of logic expression, Canonical form, Conversion from SOP & POS form to canonical form, Simplification of Boolean function: Algebraic method, Karnaugh map method (two, three & four variable K-map with don't care condition). Basics of Semiconductor Devices and its Applications: Introductor Devices and these performance parameter simplementation of depletin region, V-1 characteristics of P-N Junction, Formation of deple	(Hrs) 03 Evaluation 25 25				50		
Course Outcomes Upon completion of this course, the students will be able to CO 1 Remember operations on number systems and understand concepts of digital circuits. CO 3 Apply the basics of PN junction diode in rectifier circuits and DC power supply. CO 4 Analyze Bipolar Junction Transistor (BJT) from its basic concepts and biasing circuits. CO 6 Design and develop various basic electronic circuits. Unit No. Content Hours Number Systems & Boolean Algebra: Number Systems & Boolean Algebra: Hours Number Systems & Boolean Algebra: Hours Number Systems & Boolean Algebra: Hours Init No. Content Hours Number Systems & Boolean Algebra: Number systems and their conversion, Addition & subtraction of binary numbers, fractional numbers, Cogic gates, Boolean algebra, Implementation of basic gates & universal gates, Multiplication & Gonical form, Conversion from SOP & POS form of logic expression, Canonical form, Conversion from SOP & POS form to canonical form, Simplification of Boolean function: Algebraic method, Karnaugh map method (two, three & four variable K-			Pre-requisite: Basi	c Semiconductor Physics			
Upon completion of this course, the students will be able to CO 1 Remember operations on number systems and understand concepts of digital circuits. CO 2 Understand the basics of semiconductors and PN junction diode. CO 3 Apply the basics of PN junction diode in rectifier circuits and DC power supply. CO 4 Analyze Bipolar Junction Transistor (BJT) from its basic concepts and biasing circuits. CO 5 Evaluate the performance of operational amplifier (OP-amp) from its performance parameters like gain, CMRR, offset values etc. Hours Unit No. Content Hours Unit No. Content Hours Unit 1: gates using universal gates, SOP & POS form of logic expression, Canonical form, Conversion from SOP & POS form of logic expression, Canonical form, Conversion from SOP & POS form to canonical form, Simplification of Boolean function: Algebraic method, Karnaugh map method (two, three & four variable K-map with don't care condition). Basics of Semiconductor Devices and its Applications: 8 Unit 2: AC to DC Conversion and holes in intrinsic and extrinsic semiconductors, Hous, there analysis, Filter circuits: L, C, and Pi filters, Zener diode, Zener breakdown, Zener diode, as a voltage regulator, Analysis and design of regulator circuits using Zener diode, Avalanche diode. 8 Unit 1: gates using universal gates, SOP & POS form to canonical form, Conversion and boles in intrinsic semiconductors – P			Cours	e Outcomes			
C01 Remember operations on number systems and understand concepts of digital circuits. C02 Understand the basics of semiconductors and PN junction diode. C03 Apply the basics of PN junction diode in rectifier circuits and DC power supply. C04 Analyze Bipolar Junction Transistor (BJT) from its basic concepts and biasing circuits. C05 Evaluate the performance of operational amplifier (OP-amp) from its performance parameters like gain, CMRR, offset values etc. C06 Design and develop various basic electronic circuits. Unit No. Content Hours Number systems & Boolean Algebra: Numbers, Systems and their conversion, Addition & subtraction of binary optical and hexadecimal numbers, Multiplication & division of binary numbers, fractional numbers, Logic gates, Boolean algebra, Implementation of basic gates using universal gates, Implementation of logic expression, Canonical form, Conversion from SOP & POS form to canonical form, Simplification of Boolean function: Algebraic method, Karnaugh map method (two, three & four variable K-map with don't care condition). 8 Unit 2: Basics of Semiconductor Devices and its Applications: 8 Bereiro Nuctors, Drift and diffusion current, P-N Junction; Formation of depletion region, V-1 characteristics of P-N junction diodes, Diode breakdown mechanism. 8 Unit 3: AC to DC Conversion and Voltage Regulation: 8 Unit 4: AC to DC Conversion and Voltage Regulatio	Upon com	pletion of this c	ourse, the students	s will be able to			
C02 Understand the basics of semiconductors and PN junction diode. C03 Apply the basics of PN junction diode in rectifier circuits and DC power supply. C04 Analyze Bipolar Junction Transistor (BJT) from its basic concepts and biasing circuits. C05 Evaluate the performance of operational amplifier (OP-amp) from its performance parameters like gain, CMRR, offset values etc. C06 Design and develop various basic electronic circuits. Unit No. Content Hours Number Systems & Boolean Algebra: Number systems and their conversion, Addition & subtraction of binary, Octal and hexadecimal numbers, Logic gates, Boolean algebra, Implementation of basic gates using universal gates, SoP & POS form of logic functions using basic gates & universal gates, SOP & POS form to canonical form, Conversion from SOP & POS form to canonical form, Simplification of Boolean function: Algebraic method, Karnaugh map method (two, three & four variable K-map with don't care condition). Basics of Semiconductor Devices and its Applications: Energy band theory: Classification of solids based on energy band diagram, Semiconductors, Intrinsic semiconductors, Extrinsic semiconductors. P-type and N-type, Electrons and holes in intrinsic and extrinsic semiconductors, Mobility and conductivity, Mass action law, Charge densities in semiconductors, Drift and diffusion current, P-N Junction; Formation of depletion region, V- I characteristics of P-N junction diodes, Diode breakdown mechanism. 8 Unit 3: AC to DC Conversion and Voltage Regulation: 8 8 8 <th><i>CO I</i></th> <td>Remember ope</td> <td>rations on number s</td> <td>systems and understand co</td> <th>oncepts o</th> <th>of digital of</th> <td>circuits.</td>	<i>CO I</i>	Remember ope	rations on number s	systems and understand co	oncepts o	of digital of	circuits.
C03 Apply the basics of PR junction diode in rectifier circuits and DC power supply. C04 Analyze Bipolar Junction Transistor (BJT) from its basic concepts and biasing circuits. C05 Evaluate the performance of operational amplifier (OP-amp) from its performance parameters like gain, CMRR, offset values etc. C06 Design and develop various basic electronic circuits. Unit No. Content Hours Number Systems & Boolean Algebra: Number systems and their conversion, Addition & subtraction of binary, Octal and hexadecimal numbers, Multiplication & division of binary numbers, fractional numbers, Logic gates, Boolean algebra, Implementation of basic gates & universal gates, SoP & POS form of logic expression, Canonical form, Conversion from SOP & POS form of logic expression, Canonical form, Conversion from SOP & POS form to canonical form, Simplification of Boolean function: Algebraic method, Karnaugh map method (two, three & four variable K-map with don't care condition). Basics of Semiconductor Devices and its Applications: Energy band theory: Classification of solids based on energy band diagram, Semiconductors, Intrinsic semiconductors, Extrinsic semiconductors, Mobility and conductivity, Mass action law, Charge densities in semiconductors, Drift and diffusion current, P-N Junction, Formation of depletion region, V-I characteristics of P-N junction diodes, Diode breakdown mechanism. 8 Unit 3: AC to DC Conversion and Voltage Regulation: 8 Unit 4: Transistor and its Biasing Circuits: 8 Construction t	CO_2	Understand the	basics of semiconc	luctors and PN junction d	$\frac{10 \text{de.}}{1 \text{ DC}}$	1	
CO 4 Analyze Bipolar Junction (Transistor (B/T) from its basic concepts and blasting circuits. CO 5 Evaluate the performance of operational amplifier (OP-amp) from its performance parameters like gain, CMRR, offset values etc. Hours Unit No. Content Hours Unit No. Content Hours Vinit No. Content Hours Number Systems & Boolean Algebra: Number Systems and their conversion, Addition & subtraction of binary numbers, fractional numbers, Logic gates, Boolean algebra, Implementation of basic gates universal gates, SOP & POS form to canonical form, Conversion from SOP & POS form to canonical form, Simplification of Boolean function: Algebraic method, Karnaugh map method (two, three & four variable K-map with don't care condition). 10 Basics of Semiconductor Devices and its Applications: Energy band theory: Classification of solids based on energy band diagram, Semiconductors, Intrinsic semiconductors, Extrinsic semiconductors, P-type and N-type, Electrons and holes in intrinsic and extrinsic semiconductors, Mobility and conductivity, Mass action law, Charge densities in semiconductors, Drift and diffusion current, P-N Junction, Formation of depletion region, V-1 characteristics of P-N junction diodes, Diode breakdown mechanism. 8 Unit 3: AC to DC Conversion and Voltage Regulation: 8 Unit 4: Construction of Dipolar junction transistor (BJT), NPN and PNP type, Characteristics; Common base, Common emitter, Common collector configuration, Transistor biasing; The operating point, Stability f	CO3	Apply the basic	s of PN junction did	$\frac{1}{1000}$ $\frac{1}{1000}$ $\frac{1}{1000}$ $\frac{1}{1000}$ $\frac{1}{1000}$ $\frac{1}{1000}$ $\frac{1}{10000}$ $\frac{1}{10000000000000000000000000000000000$	DC pov	wer suppl	y.
CO 5 Evaluate the performance of operational aniphiler (OF-anip) from its performance of operational aniphiler (OF-anip) from its performance of parameters like gain, CMRR, offset values etc. CO 6 Design and develop various basic electronic circuits. Unit No. Content Number Systems & Boolean Algebra: Number Systems & Boolean Algebra: Number systems and their conversion, Addition & subtraction of binary numbers, fractional numbers, Logic gates, Boolean algebra, Implementation of basic gates using universal gates, Implementation of logic functions using basic 10 Conversion from SOP & POS form of logic expression, Canonical form, Conversion from SOP & POS form to canonical form, Simplification of Boolean function: Algebraic method, Karnaugh map method (two, three & four variable K-map with don't care condition). 8 Basics of Semiconductor Devices and its Applications: Energy band theory: Classification of solids based on energy band diagram, Semiconductors, Intrinsic semiconductors, Extrinsic semiconductors, Mobility and conductivity, Mass action law, Charge densities in semiconductors, Drift and diffusion current, P-N Junction; Formation of depletion region, V- I characteristics of P-N junction diodes, Diode breakdown mechanism. 8 Unit 3: AC to DC Conversion and Voltage Regulation: 8 Unit 4: Transistor and Bidge rectifier circuits: Rectifier performance parameter analysis, Filter circuits: L, C, and Pi filters, Zener diode, Zener breakdown, Zener diode, Avalanche diode. 8 Unit 4: Construction	CO 4	Evaluate the p	orformance of one	rational amplifiar (OP a	mp) from	a blasing	formance
CO 6 Design and develop various basic electronic circuits. Unit No. Content Hours Number Systems & Boolean Algebra: Number systems and their conversion, Addition & subtraction of binary, Octal and hexadecimal numbers, Multiplication & division of binary numbers, fractional numbers, Logic gates, Boolean algebra, Implementation of basic gates using universal gates, Implementation of logic functions using basic gates & universal gates, SOP & POS form of logic expression, Canonical form, Conversion from SOP & POS form to canonical form, Simplification of Boolean function: Algebraic method, Karnaugh map method (two, three & four variable K-map with don't care condition). 10 Basics of Semiconductor Devices and its Applications: Energy band theory: Classification of solids based on energy band diagram, Semiconductors, Intrinsic semiconductors, Extrinsic semiconductors, Mobility and conductivity, Mass action law, Charge densities in semiconductors, Drift and diffusion current, P-N Junction; Formation of depletion region, V-1 characteristics of P-N junction diodes, Diode breakdown mechanism. 8 Unit 3: AC to DC Conversion and Voltage Regulation: Introduction to DC power supply, Rectifiers circuit: Half wave, Center tapped full wave and Bridge rectifier circuits. Rectifier performance parameter analysis, Filter circuits: L, C, and Pi filters, Zener diode, Zener breakdown, Zener diode as a voltage regulator, Analysis and design of regulator circuits using Zener diode, Avalanche diode. 8 Unit 4: Construction of bipolar junction transistors (BJT), NPN and PNP type, Characteristics; Common base, Common emitter, Common collector configuration, Transistor biasing; The operating point, Stability	CO 5	parameters like	gain, CMRR, offset	values etc.	mp) noi	ii its per	Tormance
Unit No. Content Hours Vinit No. Content Hours Number Systems & Boolean Algebra: Number systems and their conversion, Addition & subtraction of binary, Octal and hexadecimal numbers, Multiplication & division of binary numbers, fractional numbers, Logic gates, Boolean algebra, Implementation of basic gates using universal gates, Implementation of logic functions using basic gates & universal gates, SOP & POS form to canonical form, Simplification of Boolean function: Algebraic method, Karnaugh map method (two, three & four variable K-map with don't care condition). 10 Basics of Semiconductor Devices and its Applications: Energy band theory: Classification of solids based on energy band diagram, Semiconductors; Intrinsic semiconductors, Extrinsic semiconductors, Mobility and conductivity, Mass action law, Charge densities in semiconductors, Drift and diffusion current, P-N Junction; Formation of depletion region, V-I characteristics of P-N junction diodes, Diode breakdown mechanism. 8 Unit 3: AC to DC Conversion and Voltage Regulation: Introduction to DC power supply, Rectifier circuit: Half wave, Center tapped full wave and Bridge rectifier circuits. Rectifier performance parameter analysis, Filter circuits: L, C, and Pi filters, Zener diode, Zener breakdown, Zener diode as a voltage regulator, Analysis and design of regulator circuits using Zener diode, Avalanche diode. 8 Unit 4: Transistor maission biasing; The operating point, Stability factor, Bias stabilization; Fixed bias, Collector to base bias and Self-bias circuit. 8	CO 6	Design and dev	elop various basic e	electronic circuits.			
Unit No. Content Hours Number Systems & Boolean Algebra: Number systems and their conversion, Addition & subtraction of binary, Octal and hexadecimal numbers, Multiplication & division of binary numbers, fractional numbers, Logic gates, Boolean algebra, Implementation of basic gates using universal gates, Implementation of logic functions using basic gates & universal gates, SOP & POS form to Canonical form, Conversion from SOP & POS form to canonical form, Simplification of Boolean function: Algebraic method, Karnaugh map method (two, three & four variable K-map with don't care condition). 10 Basics of Semiconductor Devices and its Applications: Energy band theory: Classification of solids based on energy band diagram, Semiconductors, Intrinsic semiconductors, Extrinsic semiconductors, Mobility and conductivity, Mass action law, Charge densities in semiconductors, Drift and diffusion current, P-N Junction, Formation of depletion region, V-1 characteristics of P-N junction diodes, Diode breakdown mechanism. 8 Unit 3: AC to DC Conversion and Voltage Regulation: Introduction to DC power supply, Rectifiers circuit: Half wave, Center tapped full wave and Bridge rectifier circuits. Rectifier performance parameter analysis, Filter circuits: L, C, and Pi filters, Zener diode, Zener breakdown, Zener diode as a voltage regulator, Analysis and design of regulator circuits using Zener diode, Avalanche diode. 8 Unit 4: Transistor maits Biasing Circuits: Construction of bipolar junction transistors (BJT), NPN and PNP type, Characteristics; Common base, Common emitter, Common collector configuration, Transistor biasing; The operating point, Stability factor, Bias stabilization; Fixed bias, Collector to base bias and Self-bias circuit.	U		•				
Unit 1:Number Systems & Boolean Algebra: Number systems and their conversion, Addition & subtraction of binary, Octal and hexadecimal numbers, Multiplication & division of binary numbers, fractional numbers, Logic gates, Boolean algebra, Implementation of basic gates using universal gates, SOP & POS form of logic functions using basic gates & universal gates, SOP & POS form to canonical form, Simplification of Boolean function: Algebraic method, Karnaugh map method (two, three & four variable K-map with don't care condition).10Unit 2:Basics of Semiconductor Devices and its Applications: Energy band theory: Classification of solids based on energy band diagram, Semiconductors, Intrinsic semiconductors, Extrinsic semiconductors, P-type and N-type, Electrons and holes in intrinsic and extrinsic semiconductors, Mobility and conductivity, Mass action law, Charge densities in semiconductors, Drift and diffusion current, P-N Junction; Formation of depletion region, V-I characteristics of P-N junction diodes, Diode breakdown mechanism.8Unit 3:AC to DC Conversion and Voltage Regulation: Introduction to DC power supply, Rectifiers circuit: Half wave, Center tapped full wave and Bridge rectifier circuits. Rectifier performance parameter analysis, Filter circuits: L, C, and Pi filters, Zener diode, Zener breakdown, Zener diode as a voltage regulator, Analysis and design of regulator circuits using Zener diode, Avalanche diode.8Unit 4:Transistor and its Biasing Circuits: Construction of bipolar junction transistors (BJT), NPN and PNP type, Characteristics; Common base, Common emitter, Common collector configuration, Transistor biasing; The operating point, Stability factor, Bias stabilization; Fixed bias, Collector to base bias and Self-bias circuit.8	Unit No.	Content					Hours
Unit 2:Basics of Semiconductor Devices and its Applications: Energy band theory: Classification of solids based on energy band diagram, Semiconductors; Intrinsic semiconductors, Extrinsic semiconductors–P-type and N-type, Electrons and holes in intrinsic and extrinsic semiconductors, Mobility and conductivity, Mass action law, Charge densities in semiconductors, Drift and diffusion current, P-N Junction; Formation of depletion region, V- I characteristics of P-N junction diodes, Diode breakdown mechanism.8Unit 3:AC to DC Conversion and Voltage Regulation: Introduction to DC power supply, Rectifiers circuit: Half wave, Center tapped full wave and Bridge rectifier circuits. Rectifier performance parameter analysis, Filter circuits: L, C, and Pi filters, Zener diode, Zener breakdown, Zener diode as a voltage regulator, Analysis and design of regulator circuits using Zener diode, Avalanche diode.8Unit 4:Transistor and its Biasing Circuits: Construction of bipolar junction transistors (BJT), NPN and PNP type, Characteristics; Common base, Common emitter, Common collector configuration, Transistor biasing; The operating point, Stability factor, Bias stabilizatior; Fixed bias, Collector to base bias and Self-bias circuit.8	Unit 1:	 Number Systems & Boolean Algebra: Number systems and their conversion, Addition & subtraction of binary, Octal and hexadecimal numbers, Multiplication & division of binary numbers, fractional numbers, Logic gates, Boolean algebra, Implementation of basic gates using universal gates, Implementation of logic functions using basic 12: gates universal gates, SOP & POS form of logic expression, Canonical form, Conversion from SOP & POS form to canonical form, Simplification of Boolean function: Algebraic method, Karnaugh map method (two, three & four variable K-map with don't care condition). 				10	
Unit 3:AC to DC Conversion and Voltage Regulation: Introduction to DC power supply, Rectifiers circuit: Half wave, Center tapped full wave and Bridge rectifier circuits. Rectifier performance parameter analysis, Filter circuits: L, C, and Pi filters, Zener diode, Zener breakdown, Zener diode as a voltage regulator, Analysis and design of regulator circuits using Zener diode, Avalanche diode.8Unit 4:Transistor and its Biasing Circuits: Construction of bipolar junction transistors (BJT), NPN and PNP type, Characteristics; Common base, Common emitter, Common collector configuration, Transistor biasing; The operating point, Stability factor, Bias stabilization; Fixed bias, Collector to base bias and Self-bias circuit.8	Unit 2:	Basics of Semiconductor Devices and its Applications: Energy band theory: Classification of solids based on energy band diagram, Semiconductors; Intrinsic semiconductors, Extrinsic semiconductors–P-type and N-type, Electrons and holes in intrinsic and extrinsic semiconductors, Mobility and conductivity, Mass action law, Charge densities in semiconductors, Drift and diffusion current, P-N Junction; Formation of depletion region, V- I characteristics of P-N junction diodes, Diode breakdown mochanism			8		
Unit 4:Transistor and its Biasing Circuits: Construction of bipolar junction transistors (BJT), NPN and PNP type, Characteristics; Common base, Common emitter, Common collector configuration, Transistor biasing; The operating point, Stability factor, Bias stabilization; Fixed bias, Collector to base bias and Self-bias circuit.8Unit 5:Introduction to Operational Amplificance6	Unit 3:	AC to DC Conv Introduction to I full wave and analysis, Filter Zener diode as using Zener diod	version and Voltag DC power supply, R Bridge rectifier ci circuits: L, C, and a voltage regulator, de, Avalanche diode	Regulation: Lectifiers circuit: Half wav ircuits. Rectifier perform Pi filters, Zener diode, Ze Analysis and design of r	ve, Cente nance pa ener brea regulator	r tapped arameter akdown, circuits	8
Unu 5. I introduction to Operational Ambiniers:	Unit 4: Unit 5:	Transistor and Construction of Characteristics; configuration, T stabilization; Fiz Introduction to	its Biasing Circuit f bipolar junction Common base, Fransistor biasing; T xed bias, Collector to Operational Amm	transistors (BJT), NPN Common emitter, Cor The operating point, Stab to base bias and Self-bias	and PN nmon c ility fact circuit.	IP type, collector for, Bias	8

Semester I & II



Total Hours	40
amp as integrator and differentiator.	
amp circuits, Summing amplifier, Difference amplifier, Voltage follower. Op-	
of an ideal Op-amp, Introduction of 741 IC. Inverting and non-Inverting Op-	
Introduction to integrated circuits; Advantages and limitations, Characteristics	

Total Hours

	Textbooks
1.	Jacob Millmann & Halkias, "Integrated Electronics", TMH, 2 nd Edition, 2009.
2.	M. Morris Mano, Michael D. Ciletti, "Digital Design", Pearson Education, 5th Edition, 2012.
	Reference Books
3.	Boylestad and L. Robert and Nashelsky Louis, "Electronics Devices and Circuits Theory",
	Pearson Education, 10 th Edition, 2009.
4.	S. Salivahanan and S. Arivazhagan, "Digital Circuits and Design", Oxford University Press,
	5 th edition, 2018.

Test / Quiz / Assignment / Mid Term Exam / End Term Exam. **Mode of Evaluation**



	Departm	ent of Electronics	and Communication Eng	ineering		
	B. Tech in Electronics and Communication Engineering					
Semester	First/Second	Subject Title	Basic Electronics Engin Lab	eering	Code	PEC 151/251
Course (Component	Credits		L	Т	Р
Engineer Cours	ing Science (ESC)	01	Contact Hours	0	0	2
Examinat	ion Duration	Practical	Weightage:	CWA	MSE	ESE
(1	Hrs)	02	Evaluation	25	25	50
		Pre-requisite: Basi	c Semiconductor Physics			
		Cours	e Outcomes			
Upon comp	oletion of this c	ourse, the students	s will be able to			
<i>CO 1</i>	Identify and ur nstruments.	derstand active &	passive components alor	ng with	various r	neasuring
<i>CO 2</i>	Verify truth tab	le of logic gates.				
<i>CO 3</i>	Analyse the characteristics of diodes and transistors.					
<i>CO</i> 4	Implement different electronics circuits using operational amplifier and logic gates.					
Exp. No.	<i>Exp.</i> <i>No. Name of the Experiment</i>					
<i>1</i> .	Familiarization of electronics measuring instrument and components.					
2.]	Measure the voltage and frequency using a CRO.					
3.	Study and verifi	cation of the truth t	able for logic gates.			
4. ′	Го design and v	erify the truth table	for logic gates using NOF	R gate.		
5.	Го design and v	erify the truth table	for logic gates using NAM	ND gate.		
<i>6</i> .	6. Study V-I characteristics of PN junction diode and determine the static and dynamic resistance from the characteristic curve.			dynamic		
7.	Study of a Half	wave rectifier circu	it with and without capaci	tor filter		
8.	Study of a Full v	wave rectifier circui	it with and without capaci	tor filter.		
<i>9</i> .	Study V-I chara	cteristics of Zener d	liode and determine its vo	ltage reg	ulation.	
10.	Study the input	and output characte	ristics of common base (C	CB) trans	istor.	
11.	Study the input	and output characte	ristics of common emitter	(CE) tra	nsistor.	
<i>12.</i>	Design and veri	fication of Inverting	g and non-inverting ampli	fier using	g Op-Am	p IC.
Innovative	Experiments					
<i>13</i> .	Design and veri	fication of summer	and subtractor circuit usin	ıg Op-Aı	np IC	
<i>14</i> .	Study and verifi	cation of the truth t	able for half adder using l	ogic gate	es.	
15.	As suggested by	the concerned facu	ulty/lab in charge.			

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam



	Dep	artment of Electroni	cs and Communication E	ngineerin	ıg	
	B. Tech in Electronics and Communication Engineering					
Semester	<i>nester</i> Third <i>Subject Title</i> Electronic Devices and Circuits <i>Code</i>		TEC 301			
Course C	omponent	Credits		L	Т	Р
Professio Course	onal Core (PCC)	03	Contact Hours	3	0	0
Exami	nation	Theory		CWA	MSE	ESE
Duratio	n (Hrs)	03	Weightage: Evaluation	25	25	50
Pre-requisite: Basic Electronics Engineering						
		Со	urse Outcomes			
Upon com	pletion of tl	his course, the stude	ents will be able to			
CO 1	Understant in different	d the working, bias t regions.	stabilization and character	istics of I	BJTs and N	AOSFET s
CO 2	Analyse H response.	BJT/MOSFET as an	nplifier in different conf	iguration	and its	frequency
<i>CO 3</i>	Understan	nd and analyse multi	-stage amplifiers and feed	oack topo	logies.	
<i>CO 4</i>	Investigat	e the basic concepts	of oscillators and their clas	sification	IS.	
CO 5	Analyse po	ower amplifiers and t	their classification.			
CO 6	Design BJ	T and MOSFET base	ed electronic circuits.			
Unit No.	Content					Hours
Unit 1:	Bipolar Ju Review of analysis (C cut off free Multistage and Cascoo	Inction Transistor: BJT, BJT as an am CB, CE, CC), Frequer juencies, RC couplin e amplifier: Cascad de configuration.	plifier and switch, Small ncy response of CE amplif g. e amplifier, Darlington pa	signal mo ïer, Calcu iir, Boots	odels and ilation of trapping,	9
Unit 2:	Field Effe Introduction JFET drain signal JFE amplifier, 1 characteris	ct Transistors: on to FET, Junction on characteristics, Trans ET parameters, DC MOSFET or IGFET, tics and Q-point anal	FET (JFET), Static charac nsfer characteristics, Q-po biasing of JFET, Comm DE MOSFET, E-only Mo lysis.	cteristics int analys non sour OSFET, N	of JFET, is, Small ce JFET MOSFET	10
Unit 3:	MOSFET MOSFET amplifier Common Calculation	as an Amplifier: biasing, MOSFET as circuits, Small sigr Source, Common D n of cut off frequenci	an amplifier and switch, Bi nal models and analysis rain). Frequency response es.	asing in M (Commo of CS a	MOSFET on Gate, umplifier,	9
Unit 4:	Feedback General fe feedback t Types of o and crystal	Circuits and Oscilla eedback structure, P opologies and their oscillators: RC phase oscillator.	ators: roperties of negative feed analysis. Principle of sinu shift, Wein bridge, Hartle	lback, Fo isoidal os ey, Colpit	our basic scillators, ts, Clapp	8
Unit 5:	Power Am Introduction and efficien push pull, C	aplifiers: on to power amplifier ncy of: Series fed cla Crossover distortion,	, Classification of power ar ass A, Transformer couple Class AB push pull, Class	nplifier, (d class A C power a	Dperation , Class B amplifier.	6
		Total	Hours			42

Semester III



Textbooks	
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1.	Millman Halkias,	" <i>Integrated electronics</i> ", TMH, 2 nd edition, 2001.	

2. Boylestad L Robert, "*Electronic devices and circuit theory*", Pearson, 10th edition, 2005.

Reference Books

3. Neaman A Donald, "*Electronics circuits*", TMH, 3rd edition, 2008.

4. S. Sedra and KC Smith, "*Microelectronic Circuits*", Oxford university press, 5th edition, 2009.

5. Jacob Millman and Arvin Grabel, "*Microelectronics*", TMH, 2nd edition, 2001.

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Den	artment of Electroni	cs and Communication E	ngineerin	19	
	2.4	Course: - E	Bachelor of Technology		6	
Semester	er Third Subject Title Digital Electronics Code		TEC 302			
Course Co	omponent	Credits		L	Т	Р
Professio Course	nal Core (PCC)	03	Contact Hours	3	0	0
Exami	nation	Theory	W Fundantian	CWA	MSE	ESE
Duratio	n (Hrs)	03	Weightage: Evaluation	25	25	50
		Pre-requisite: B	asic Electronics Engineeri	ng		
		Со	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
CO 1	Describe 1 design con	minimization technic nbinational circuits.	ques for the simplificatio	n of Bo	olean func	ctions and
<i>CO</i> 2	Understan	d the concepts of se	quential circuits and its rea	l time ap	plications.	
<i>CO 3</i>	Apply the	concepts in designin	g of asynchronous and syn	chronous	sequential	l circuits.
<i>CO</i> 4	Analyse ar	nd study various sem	iconducting memories.			
<i>CO</i> 5	Gain know	ledge of various log	ic families.			
CO 6	Implemen	t various digital syst	ems.			
Unit No.	Content					Hours
Unit 1:	Boolean A Basic Boo gates, K-M method for Combinati & subtract Multiplexe Programma and Seven	Igebra and Gate Le lean algebra concep lap method for minin minimization, NAN ional Logic Circuits onal circuits, Analysi for, Decimal adder, r, Demultiplexer, De able ROMs, Code C Segment Code).	evel Minimization: ts, Theorems, and proper mization up to 6-variables, D and NOR gate impleme s: is procedure, Design proce Binary multiplier, Magn ecoder, Encoder, Parity gen onvertors (BCD, excess-3	ties. Dig , Quine-M ntation. dure, Bin itude con nerator & code, G	ital logic AcClusky ary adder nparator, checker, ray code,	10
Unit 2:	Sequential Triggering Equation as JK Master Counter: Asynchron the counte asynchrono Registers: Types of n Parallel our register, Ap	l Logic Circuits: , Latches & Flip Flo nd excitation table), Slave Flip Flop. ous counter, Decoder r modulus, Decade ous and synchronous register, Serial in-Set t, Parallel in- Serial of pplication of shift reg	ops: RS, JK, D and T (Ch Flip Flop conversion, Race ing gates, Synchronous co counter, Presettable cour counters. erial out, Serial in-Paralle ut, Universal shift register, gisters.	aracterist around c ounters, (iter, Desi l out, Pa Bidirecti	ics table, condition, Changing gning of rallel in- onal shift	8
Unit 3:	Design of S Model seld equations a asynchrono circuit.	Synchronous and A ection, State transition and circuit diagram, bus sequential circu	synchronous Sequential on diagram, State synthe State reduction table, Desi it, Problems with asynch	Circuit: esis table gn and ar ronous s	, Design nalysis of equential	8
Unit 4:	Semicondu	uctor memories:				8

Semester III



	Programmable logic array, Programmable array logic, ROM, PROM, EPROM, EEPROM, Bipolar RAM, Static and dynamic RAM. Designing combinational circuits with multiplexer, ROM, PAL and PLA, D-A and A-D converter.	
Unit 5:	Logic Family: Introduction, Various characteristics, Register Transistor Logic (RTL), Diode-Transistor Logic (DTL), Transistor-Transistor Logic (TTL), Emitter Coupled Logic (ECL), NMOS and PMOS logic, CMOS logic family, Various properties of logic families, CMOS transmission gate circuits.	8
	Total Hours	42

	Textbooks
1.	Mano M. Morris and Ciletti M. D., "Digital Design", 4th Edition, Pearson Education, 2006.
2.	Charles H. Roth Jr, "Fundamentals of Logic Design", 5th Edition, Thomson, 2004.
	Reference Books
3.	Ronald J. Tocci, Neal S. Widmer, Gregory L. Moss, "Digital Systems Principles and
	Applications", 10th Edition, Pearson Education, 2007.
4.	Donald P Leach, Albert Paul Malvino & Goutam Saha, "Digital Principle and Application",
	7 th Edition, Tata McGraw Hill, 2010.

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Dep	artment of Electroni	cs and Communication E	ngineerii	ıg	
	B. Tech in Electronics and Communication Engineering					
Semester	Third	Subject Title	Networks Analysis a Synthesis	and	Code	TEC 303
Course Co	mponent	Credits		L	Т	Р
Professio Course	nal Core (PCC)	03	Contact Hours	3	0	0
Exami	nation	Theory	Weightage, Evaluation	CWA	MSE	ESE
Duratio	n (Hrs)	03	weignlage. Evaluation	25	25	50
		Pre-requisite: I	Basic Electrical Engineerin	g		
		Со	urse Outcomes			
Upon com	pletion of th	his course, the stude	ents will be able to			
CO 1	Remembe current, an	r the basic laws of th d potential divider ru	e network theory including les.	, Ohm's I	aw, Kircho	off's laws,
<i>CO 2</i>	Understan	d the network theore	ems in electrical circuits.			
<i>CO 3</i>	Apply grap	ph theory approach to	o solve electrical networks	•		
CO 4	Analyse the state analyse	e performance paran sis.	neters of RLC circuits in c	ontext of	transient a	ind steady
<i>CO</i> 5	Evaluate t	he performance para	meters of two port network	c and cou	pled circui	ts.
CO 6	<i>CO 6</i> Design the electrical networks in Foster and Cauer forms of realization using network functions.			g network		
Unit No.	Content				Hours	
Unit 1:	 Network Concepts and Theorems: Elements and sources, Node and mesh analysis, Kirchhoff's laws, Steady state sinusoidal analysis, Thevenin's, Norton's, Maximum power transfer, Tellegen's, reciprocity, and superposition theorems, Study of basic waveforms. 				10	
Unit 2:	<i>hit 2:</i> Graph Theory: Concept of graphs, Definitions, Trees, Co-tree, Chords and links, Matrices associated with graphs, Incidence matrix, Circuit matrix, Tie-set matrix, Cutset matrix and their KVL and KCL analysis.			6		
Unit 3:	Network Transients: Transient response, Time domain analysis of simple RC, RL and RLC circuits, Network analysis using Laplace transform, Driving point and transfer function, Resonance in electrical circuits.			8		
Unit 4:	Two Port Network and Coupling Circuit:Different two port parameters, Condition of reciprocity and symmetry for different two port parameters, Inter relationship between different two port parameters, Interconnection of two port networks. Coupled circuits: Self- inductance and mutual inductance, Coefficient of coupling, dot convention, Analysis of magnetic coupling circuits.10					
Unit 5:	Analysis a Driving po and proper Properties and RL Dr second form	nd Synthesis of Net bint function, transfer ties, Poles and zeroes of LC, RC and RL d iving point admittand ms. Total	work Functions: r function, Positive real fuses of network functions, Hundliving point functions, Sy ce functions using Foster a Hours	nction; I witz poly nthesis o nd Cauer	Definition ynomials, f LC, RC f first and	8

Semester III



1.	Kemmerly, Hayt and Durbin, "Engineering Circuit Analysis", TMH, 7th Edition, 2010.
2.	Van Valkenburg, M.E., " <i>Network Analysis & Synthesis</i> ", PHI/ Pearson education, 3 rd Edition, 2002.
	Reference Books

3.	Alexander, Charles K., Sadiku, Matthew N. O., "Fundamentals of Electric Circuits", TMH,
	5 th Edition, 2004.
1	Der Chaudhaum D "Networks and sustainer" New Ase International Dashiesticus 2nd Edition

4. Roy Choudhury D, "*Networks and systems*", New Age International Publications, 2nd Edition.

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Dep	artment of Electron	ics and Communication E	ngineerin	ıg	
	<u> </u>	Tech in Electronics	and Communication Eng	ineering	0	
Semester	Third	Subject Title	e Signals and Systems Code		TEC 304	
Course C	omponent	Credits		L	Т	Р
Professio	onal Core	03	Contact Hours	3	0	0
Eram	ination	Theory		CWA	MSE	ESE
Duratio	on (Hrs)	03	Weightage: Evaluation	25	25	50
	()	Pre-requisite:	Basic Electrical Engineerin	g		
		Co	urse Outcomes	8		
Upon com	pletion of tl	his course, the stude	ents will be able to			
CO 1	Differentia operations	ate between various of signals.	s types of signals and un	derstand	the impl	ication of
<i>CO</i> 2	Understan continuous	nd and classify systems time and discrete-time	ems based on the impulse me systems.	e respons	e behaviou	r of both
<i>CO 3</i>	Apply Fou	rier series for contin	uous-time signals.			
CO 4	Apply Fou	rier Transform for c	ontinuous-time signals.			
CO 5	Explain th	e Laplace transform	and its importance to analy	yse signal	ls and syste	ems.
CO 6	Design and	d develop LTI syster	ns and its response in time	and frequ	lency dom	ain.
Unit No.	Content					Hours
Unit 1:	<i>Unit 1:</i> Introduction to Continuous-time and Discrete-time Signals: Introduction to signal, Classification of signals: continuous /discrete-time, Analog/ digital signal, Periodic/ aperiodic, Even/odd, Energy/power, Deterministic/random, Commonly used continuous-time signals and discrete-time signals: Unit step, Unit ramp, Exponential, Rectangular pulse, Unit impulse, Operation on continuous –time and discrete time signals: Addition, Multiplication, Differentiation/difference, Integration/			8		
Unit 2:	Introduction to Continuous-time and Discrete-time Systems: Classification of systems: Static and dynamic, Linear, and non-linear, Time- variant and time invariant, Causal, and non-causal, Stable and unstable, Continuous time and discrete time LTI system, Impulse response and step response of LTI systems, Convolution integral/ convolution sum, Properties of LTI system.			9		
Unit 3:	Fourier Series Analysis of Continuous-time Signals: Introduction, Vector space representation by ortho-normal vectors and signal space representation by orthogonal signal set, Fourier series representation of periodic signals, Convergence of Fourier series, Trigonometric Fourier series and exponential Fourier series, Properties of the continuous time Fourier series. Power content of a periodic Signal.			8		
Unit 4:	Continuous Time Fourier Transform: Deriving Fourier transform from Fourier series, Convergence of the Fourier transforms, Fourier transform of standard signals, Properties of Fourier 8 transforms, Invers Fourier Transform, Convolution, Parseval's theorem: Energy spectral density, Power spectral density.			8		
Unit 5:	Laplace Transform: Introduction to Laplace transform, Relation between Laplace and Fourier transforms, Region of convergence for Laplace transform, Properties of			9		

Semester III



ROC, Laplace transform of some common signals, Properties of the Laplace transform, Convolution, Unilateral Laplace transform, Inverse Laplace transform and initial value and final value theorem, Solution of differential equation using Laplace transform. 42

Total Hours

	Textbooks
1.	Alan. V. Oppenheim, Alan. S. Willsk, S. Hamid Nawab, "Signals and systems", 2001, 2 nd
	edition- PHI learning Pvt. Ltd.
2.	Simon Haykin and Barry VanVeen, "Signals and systems", 2007, 2nd edition, Wiley, India.
3.	P. Rama Krishna Rao and Shankar Prakriya, "Signals and Systems", 2013, 2 nd edition, McGraw
	Hill.
	Reference Books
4.	B. P. Lathi, "Signal processing and linear systems", 2009, Oxford university press.
5.	R.F. Ziemer, W.H. Tranter and D.R. Fannin, "Signals and Systems - Continuous and Discrete",
	1998, 4 th edition, Prentice Hall.
6.	H. P. Hsu, "Signal and Systems", McGraw Hill Publications, 2008, 2 nd edition.

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Dep	artment of Electroni	cs and Communication E	ngineerin	ıg	
	B. Tech in Electronics and Communication Engineering					
Semester	Third	Subject Title	Advanced Engineer Mathematics	ring Code		TMA 310
Course Component		Credits		L	Т	Р
Basic Scier (BS	nce Course SC)	03	Contact Hours	3	0	0
Exami	nation	Theory	Weightage: Evaluation	CWA	MSE	ESE
Duratio	on (Hrs)	03		25	25	50
		Pre-requisite: Ba	sic Mathematics and Alge	bra		
		Со	urse Outcomes			
Upon com	pletion of tl	his course, the stude	ents will be able to			
CO 1	Understan	d analytic function a	and power series expansion	l.		
CO 2	Analyse di	fferent order of mon	nents.			
<i>CO 3</i>	Understan	d different numerica	l methods and their application	ations.		
<i>CO</i> 4	Analyse di	fferential and integra	al equations.			
CO 5	Understand conditional probability and Baye's theorem.					
CO 6	<i>CO 6</i> Apply these theorems in electronics and communication engineering problems.				IS.	
Unit No.	o. Content			Hours		
Unit 1:	Complex Variable: Analytic function, Complex integration, Cauchy integral formula, Cauchy integral formula for derivatives, Power series, Taylor series, and Laurent series, Zeros, Singularities and residues. Conformal mapping, Bilinear transformation.			8		
Unit 2:	<i>Moments:</i> <i>Kurtosis, Skewness, Curve fitting (all curves), Correlation and regression, Multiple regression. Definition and examples of vector space.</i>			8		
Unit 3:	Solution of Algebraic and Transcendental Equations: Bisection, Iteration method, Newton Raphson method, Interpolation: Finite differences, Newton's forward and backward formula, Central difference Bessel's formula, Interpolation with unequal intervals Lagrange's interpolation formula.			8		
Unit 4:	Numerical Integration:Trapezoidal rule, Simpson's 1/3 and 3/8 rule, Weddle's rule and Boole's ruleSolution of differential equation: Euler's method and Runge-Kutta method.					
Unit 5:	Random v Random v Probability covariance correlation	variables: variables, Baye's t distribution funct function: Principl functions, Central li	heorem, Function of R tions, Moments, Mean, les of autocorrelation f mit theorem, Properties of	andom v Correlat unction, Gaussian	variables, ion and cross – process.	8
		Total	Hours			42

	Textbooks
1.	B. S. Grewal, "Higher Engineering Mathematics", Khanna Publications, 43rd edition, 2013.
2.	B.V. Ramanna, "Higher Engineering Mathematics", Tata-McGraw Hill, 6th edition, 2006.
	Reference Books

Semester III



3.	Kreyszig, Erwin. "Advanced Engineering Mathematics", Wiley Publications, 10th edition,
	2010.
4.	A. Mattuck, "Introduction to Analysis", Prentice-Hall, 3rd edition, 1999.
5.	R. K. Jain, Iyengar, "Advanced Engineering Mathematics", Narosa Publication, 2 nd edition,
	2002.

Mode of Evaluation	Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Depe	artment of Electroni	cs and Communication E	ngineerin	ng	
	B. Tech in Electronics and Communication Engineering					
Semester	Third	Subject Title	Career Skills		Code	XCS 301
Course Co	Course Component Credits L T		Р			
Humanities and Social Sciences including Management course (HSMC)		02	Contact Hours	2	0	0
Exami	nation	Theory	Weichtage, Englugtion	CWA	MSE	ESE
Duratio	n (Hrs)	03	weignlage: Evaluation	25	25	50
		Pre-requisit	e: Communication Skills			
		Со	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
CO 1	Have a log differentia	gical approach to the stron	e problems and at the sar g and the week arguments	ne time t and valid	they will b lity of the s	be able to statement.
<i>CO</i> 2	Improve th	he reasoning ability of	of the students by using the	different	t methods.	
<i>CO 3</i>	Learn different approaches related to the coding or other complex types of problems which are related to the sequence detection etc.					
<i>CO</i> 4	Get a basic knowledge of the data interpretation.					
<i>CO</i> 5	Acquire knowledge of puzzles and different methods to solve the puzzles in an easier way is also included.					
CO 6	Develop th	e basic skills of aptit	ude and logical reasoning.			
Unit No.	Content					Hours
Unit 1:	Meeting E Introductio etiquette – apartments – Etiquette	tiquette: ns - The Handsha Hygiene, Grooming Behavior at work –	ke– Exchange of visitin g, and good sense Travel	g cards etiquette,	Personal Sharing	
	Manners an Group Dis Group dis sessions.	with women/men – nd small talk cussions: cussion techniques/	Adherence to office rules	ors and co – Discipl y langua	olleagues line table age/mock	6
Unit 2:	Manners an Group Dis Group dis sessions. Logical Re Series con diagram.	with women/men – nd small talk scussions: cussion techniques/ easoning: npletion, Coding de	Adherence to office rules Do's and Dont's/ bod coding, direction sense t	ors and co – Discipl y langua est, logic	olleagues line table age/mock cal Venn	6 6
Unit 2: Unit 3:	Manners an Group Dis Group dis sessions. Logical Re Series con diagram. Logical Re Mathemati reasoning.	with women/men – nd small talk scussions: cussion techniques/ easoning: npletion, Coding de easoning: cal operation, Numb	Adherence to office rules Do's and Dont's/ bod coding, direction sense t er ranking, Time sequence	ors and co – Discipi y langua est, logic test, Arit	olleagues line table age/mock cal Venn thmetical	6 6 6
Unit 2: Unit 3: Unit 4:	Manners an Group Dis Group dis sessions. Logical Re Series con diagram. Logical Re Mathemati reasoning. Job Applie Importance letters, Typ parts - Cov Chronolog	with women/men – nd small talk scussions: cussion techniques/ easoning: npletion, Coding de easoning: cal operation, Numb cation: e of business commun pes of letters. Writin er letter and the 'resu ical 'resume', functio	Adherence to office rules Do's and Dont's/ bod coding, direction sense t er ranking, Time sequence nication in today's world, E ag effective emails, Repor ume', Types of 'resumes' (onal 'resume'	ors and co – Discipi y langua est, logic test, Arit Designing t writing Curriculu	blleagues line table age/mock cal Venn thmetical business essential m Vitae)	6 6 6 6

Textbooks

Semester III



1.	R. K. Bansal and J.B. Harrison, "Spoken English for India", Orient Longman.
2.	Thomson and Martinet, "A practical English Grammar", Oxford University Press.
3.	Malti Aggarwal, "Professional Communication".
4.	M. A. Pink and A. E. Thomas, "English grammar, composition and correspondence", S.
	Chand and Sons.
5.	"A Dictionary of Modern Usage", Oxford University Press.
	Reference Books
6.	R.S Agarwal, "Quantitative aptitude".

7. R.S Agarwal, "Verbal and Non-Verbal Reasoning".

8. Shakuntala Devi "*puzzles*".

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



Department of Electronics and Communication Engineering							
B. Tech in Electronics and Communication Engineering							
Semester	Third	Subject Title	Electronics Circuit Lab		Code	PEC 301	
Course Component		Credits	Contact Hours	L	Т	Р	
Professional Core Course (PCC)		01		0	0	2	
Examination		Practical	Weightage: Evaluation	CWA	MSE	ESE	
Duration (Hrs)		02		25	25	50	
		Pre-requisit	e: Basic Electronics Lab				
		Со	urse Outcomes				
Upon com	pletion of th	nis course, the stude	ents will be able to				
CO 1	Remember rectifiers in	r the different elec 1 CRO.	tronic components and t	esting th	e characte	eristics of	
CO 2	Analyse th with simula	e characteristics of reation in OrCAD.	egulated power supply, am	plifiers a	nd oscillate	or circuits	
<i>CO 3</i>	Evaluate a	mplifier circuits to c	ompute gain and frequency	y respons	e.		
<i>CO</i> 4	Design and implement analog circuits on PCB followed by soldering and testing.						
Exp. No.	Name of the Experiment						
1.	Simulation of half wave and full wave center tapped rectifiers through OrCAD software.						
2.	Simulation of DC regulated power supply (+5V) through OrCAD software.						
3.	To implement the circuits of Half wave and Full wave center tapped rectifiers on the bread board and draw/measure the outputs with and without filter.						
4.	Simulation of CE Amplifier using PSPICE OrCAD.						
5.	Simulation of two stage RC Coupled Amplifier using PSPICE OrCAD.						
6.	To implement the circuit of single stage common emitter (CE) amplifier on the bread board and draw its output and frequency response curve.						
7.	Simulation of FET amplifier circuit using OrCAD and compute the gain and bandwidth.						
8.	To test the given Hartley oscillator and determine its frequency of oscillation.						
9.	To test the given Wein Bridge oscillator and determine its frequency of oscillation.						
10.	To test the given RC Phase shift oscillator and determine its frequency of oscillation.						
11.	To test the given COLPITTS oscillator and determine its frequency of oscillation.						
12.	To develop the negative of full wave center tapped rectifier/DC regulated power supply.						
<i>13</i> .	To make the PCB of full wave center tapped rectifier/DC regulated power supply.						
14.	To drill and solder the components on the PCB of full wave center Tapped rectifier/DC regulated power supply.						
15.	To test the PCB of full wave center tapped rectifier/DC regulated power supply.						
Innovative	Experiment	ts					
16.	To make the Layout of center tapped full wave rectifier through OrCAD software.						
17.	To make the Layout of DC regulated power supply through OrCAD software.						

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



Department of Electronics and Communication Engineering							
B. Tech in Electronics and Communication Engineering							
Semester	Third	Subject Title	Digital Electronics Lab		Code	PEC 302	
Course Component		Credits	Contact Hours	L	Т	Р	
Professional Core Course (PCC)		01		0	0	2	
Examination		Practical	Weighten on Frightention	CWA	MSE	ESE	
Duratio	n (Hrs)	02	weightage: Evaluation	25	25	50	
		Pre-requisit	e: Basic Electronics Lab				
		Со	urse Outcomes				
Upon com	pletion of tl	nis course, the stude	ents will be able to				
CO 1	Understan	d various logic gate	s and digital circuits.				
<i>CO</i> 2	Identify various digital ICs and understanding its operation.						
<i>CO 3</i>	Design elementary digital circuits under real and simulated environment.						
<i>CO</i> 4	Simulate various logic circuits using simulation tool.						
Exp. No.	Name of the Experiment						
1.	To verify the truth table of basic logic gates (AND, OR, NOT, NAND, NOR, XOR). To realize basic two input Boolean AND, OR logic functions using discrete components.						
2.	To verify the Consensus Theorem (Boolean algebra functions) using universal digital IC Gates.						
3.	To design and test a half/full adder circuit using digital IC gates.						
4.	To design and test a half/full subtractor circuit using IC gates.						
5.	To design, implement and test the function $F(A,B,C,D)=m(1,3,5,7,9,15)+d(4,6,12,13)$ using a NOR-OR implementation.						
б.	To design and test RS, JK, D and T flip flops using logic gates.						
7.	To design and test shift registers using flip-flops.						
8.	To design and test an asynchronous up/down counter.						
9.	To design, implement and test half/full adder/subtractor functions using a multiplexer.						
10.	To design and simulate the implementation of BCD TO EXCESS 3-CODE CONVERTER using OrCAD/PSPICE.						
11.	To design and simulate the implementation of ring counter using OrCAD/PSPICE.						
Innovative							
12.	To design, implement and simulate half & full adders using OrCAD/PSPICE.						
13.	To design,	implement and simu	late half & full subtractors	using Or	CAD/PSP	ICE.	

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam



Department of Electronics and Communication Engineering							
B. Tech in Electronics and Communication Engineering							
Semester	Third	Subject Title	Notworks Lab		Code	PEC	
	Inird		Networks Lab	-		303	
Course Component		Credits	Contact Hours	L	Т	Р	
Professional Core		01 Contact Hours		0	0	2	
Course (PCC)			0	v			
Examination		Practical	Weightage: Evaluation	CWA	MSE	ESE	
Duratio	on (Hrs)	02	Heighlage. Eratuation	25	25	50	
		Pre-requist	ite: Basic Electrical Lab				
		Со	urse Outcomes				
Upon com	pletion of t	his course, the stude	ents will be able to				
CO 1	Understar	d the basic circuit co	oncepts and network theore	ems.			
<i>CO 2</i>	Analyse th	e transient character	istics and frequency respor	ise of RL	C circuits.		
<i>CO 3</i>	Evaluate different parameters of two port network in electrical networks.						
<i>CO</i> 4	Design and test series/parallel RLC Circuits (Time/Phasor Domain).						
Exp. No.	Name of the Experiment						
1.	Verification of principle of superposition with dc and ac sources.						
2.	Verification of Thevenin theorem in dc and ac circuits.						
3.	Verification of Norton theorem in dc and ac circuits.						
4.	Verification of Maximum power transfer theorem in dc and ac circuits.						
5.	Verification of Tellegen's theorem for two networks of the same topology.						
6.	Analysis of the transient response of RL circuits with step voltage input.						
7.	Analysis of the transient response of RC circuits with step voltage input.						
8.	Analysis of the transient response of RLC circuits with sinusoidal ac input.						
9.	Analysis of the frequency response of RLC circuit with sinusoidal ac input.						
10	Determination of the z parameters of a two-port network and computation of Y						
10.	parameters.						
11	Determination of h parameters of a two-port network and computation of ABCD						
11.	parameters.						
12.	Verification of the two-port parameter in inter-connected two port networks.						
Innovative	e Experimen	ts					
13.	Determination of image impedance and characteristic impedance of T and \prod networks.						
14	Determination of driving point and transfer functions of a two-port ladder network and						
14.	verify with theoretical values.						
15.	Determina	tion of frequency res	ponse of a Twin – T notch	filter.			

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam



Department of Electronics and Communication Engineering						
B. Tech in Electronics and Communication Engineering						
Semester	Fourth	Subject Title	Communication Systems I Code		Code	TEC 401
Course Co	mponent	Credits		L	Т	Р
Professional Core Course (PCC)		03	Contact Hours	3	0	0
Examination		Theory	Weightage, Engligation	CWA	MSE	ESE
Duration	n (Hrs)	03	weigniage: Evaluation	25	25	50
	Pre-requisite: Signals and Systems					
		Со	urse Outcomes			
Upon comp	letion of t	his course, the stude	ents will be able to			
CO 1	Demonstr signals.	ate and understand	l analog communication s	system a	nd represe	ntation of
CO 2	Demonstr demodulat	ate and understan	d different methods of esign, operation and application	amplitue ations.	de modula	ation and
<i>CO 3</i>	Demonstr schemes, t	ate and understand heir design, operation	different methods of angle n and applications.	modulatio	on and dem	odulation
CO 4	Demonstrate and understand different methods of pulse modulation, their design, operation and applications					
CO 5	Evaluate the performance of analog communication system in the presence of noise.					
CO 6	Demonstrate and understand analog communication system and representation of signals.					
	<u> </u>					
Unit No.	Content					Hours
Unit 1:	Amplitude Modulation Systems: Modulation, Need of modulation, Model of communication system, Amplitude Modulation: Equation for AM wave, Modulation index, Power and current relationships, Transmission and power efficiency, Generation and demodulation of DSB-FC, DSB-SC, SSB-SC and VSB signals, Spectral characteristics of amplitude modulated signals, Comparison of amplitude modulation systems: AM receiver and its characteristic					12
Unit 2:	Angle Modulation Systems: Phase and frequency modulation: Narrow band and wideband FM & PM, Spectral characteristics of angle modulated signals, Generation and demodulation of FM Signal, PLL, Communication receiver.					12
Unit 3:	Noise: Introduction – internal and external noise, Noise equivalent bandwidth, S/N ratio, Noise figure, Equivalent noise temperature, Cascade connection of two port network.					6
Unit 4:	Pulse Ana Sampling Pulse posit	log Modulation Sys process, Pulse ampli- ion modulation.	stem: itude modulation, Pulse duration modulation,			
Unit 5:	SNR Performance of Continuous Wave Modulation Systems: Introduction: Review of probability and random process. Gaussian and white noise characteristics, Analog communication model, SNR calculation in DSB-SC, SSB-SC, DSB-FC & FM systems, FM threshold effect; Pre- emphasis and De-emphasis in FM, Comparison of performances.					8
1		Iotal	nours			43


	Textbooks					
1.	B. P. Lathi, "Modern Digital and Analog Communication", Oxford Publication, 3rd edition,					
	2005.					
2.	Simon Haykin, "Communication Systems", John Willey, 4th edition, 2001.					
3.	Taub and Schilling, "Principles of Communication System", Tata McGraw-Hill, 4th edition,					
	1995.					
4.	HWEI HSU, "Analog and Digital Communications", Schaum Outline Series, 2 nd edition, 2003.					
	Reference Books					
5.	Roddy and Coolen, "Electronic Communication", Prentice Hall of India, 4th edition, 1998.					
6.	Singh and Sapre, "Communication system", TMH, 2/e, 2007.					
7.	A. Papoulis, "Probability, Random variables and Stochastic processes", MGH, 4th edition,					
	2002.					

Mode of Evaluation	Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



Department of Electronics and Communication Engineering						
B. Tech in Electronics and Communication Engineering						
Semester	SemesterFourthSubject TitleAnalog Integrated CircuitsCode		TEC 402			
Course Co	omponent	Credits		L	Т	Р
Professio Course	nal Core (PCC)	03	Contact Hours	3	0	0
Exami	nation	Theory	Weichtagen Englugtion	CWA	MSE	ESE
Duratio	n (Hrs)	03	weignlage: Evaluation	25	25	50
		Pre-requisite: Ele	ectronics Devices and Circ	uits		
		Со	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
<i>CO</i> 1	Identify va	arious configurations	of differential amplifier.			
<i>CO</i> 2	Understan	d the concepts of ide	eal and practical operationa	al amplifi	ers (Op-Ai	mp).
CO 3	Apply the circuits.	concepts of Op-Am	p in designing of the line	ear and n	on-linear	integrated
<i>CO 4</i>	Analyse th	e performance paran	neters of active filters using	g Op-Am	p.	
<i>CO</i> 5	Evaluate t	he performance para	meters of oscillators and m	ultivibra	tors using	Op-Amp.
CO 6	Design vol	tage regulator circuit	ts using Op-Amp.			
Unit No.	Content					Hours
Unit 1:	Brief review of differential amplifier (DC and AC analysis), OP-AMP Fundamentals:I:DC and AC analysis of various configurations of differential amplifier, Input stage, Intermediate stage circuits, Constant current bias circuits, Current					10
Unit 2:Operational Amplifier Applications: Inverting/Non-inverting amplifier: Calculation of input and output impedance along with gain with feedback for finite open loop gain, Summer, Difference amplifier, Integrators, Differentiators, VCVS, CCVS and VCCS, 					8	
Unit 3:	<i>Non-linear Circuits:</i> Logarithmic amplifiers, Log/Antilog modules, Precision rectifier, OP-AMP as comparator. Oscillators (Hartley, Colpitts, RC phase shift), Multivibrators: Astable, Monostable and Bistable, Triangular wave generator, Multivibrator, 555 timer and applications, PLL & capture range.					10
Unit 4:	 Active Filters: Butterworth filter: Low pass filter, High pass filter, Band pass filter, Band-reject Filter, Sallen-Key unity gain filter, Sallen-Key equal component filter 8 and its performance parameters: Gain, Cut-off frequency, Frequency response, State variable filter. 					8
Unit 5: Voltage Regulators: Series Op-amp regulators, IC voltage regulators, 723 general purpose for regulators, Switching regulators, Fixed voltage (78/79, XX) regulators.					6 42	

Textbooks

1. Sedra and Smith, "Microelectronic Circuits", Oxford University press, 5th Edition, 2019.



2.	J. Michael Jacob, " <i>Applications and design with Analog Integrated Circuits</i> ", PHI, 2 nd Edition, 2010.
	Reference Books
3.	B. Razavi, "RF Microelectronics", Prentice Hall, 2 nd Edition, 2011.
4.	B.P. Singh and Rekha Singh, "Electronic Devices and Integrated Circuits", Pearson Education,
	1 st Edition, 2012.
5.	Ramakant A. Gayakwad, "Op-Amps and Linear Integrated Circuits", PHI, 3 rd Edition, 2009.

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



Department of Electronics and Communication Engineering								
B. Tech in Electronics and Communication Engineering								
Semester Fourth		Subject Title	Microprocessor and its Applications Ca		Code	TEC 403		
Course C	omponent	Credits		L	Т	Р		
Professio Course	onal Core (PCC)	03	Contact Hours	3	0	0		
Exami	nation	Theory		CWA	MSE	ESE		
Duratio	n (Hrs)	03	Weightage: Evaluation	25	25	50		
		Pre-requis	ite: Digital Electronics					
		Со	urse Outcomes					
Upon com	pletion of th	nis course, the stude	ents will be able to					
CO 1	Remember	r the concept of mici	rocomputer system.					
<i>CO</i> 2	Understan	d microprocessor 80	085 and 8086 hardware.					
CO 3	Apply the different ta	concepts of assemb sks.	bly language programming	g of 808:	5 and 8086	5 to fulfil		
CO 4	Examine t time timer	he application of 80 and counter.	85 and 8086 microprocess	or with i	nterrupt sy	stem, real		
CO 5	CO 5 Test different interfacing ICs and memory for defined tasks with 8085 and 808 microprocessor				and 8086			
CO 6	16 Integrate the knowledge of 8085 and 8086 in various embedded systems							
	8				5.011151			
Unit No.	Content					Hours		
Unit 1:	Introduction to Microprocessors: Evolution of microprocessors, Microprocessor internal architecture, 8 hardware model of 8085. Pin diagram and function of each pin					8		
Unit 2:	2: Programming with 8085: Instruction set, Programming model of 8085, Addressing modes, Assembly language programming, Peripheral I/O, Memory mapped I/O, 8085			8				
Unit 3:	<i>it 3:</i> 16 Bit Processor: 16-bit microprocessors (8086): Architecture, Pin diagram, Physical address, Segmentation, Memory organization, Addressing modes, Instruction set, Assembly language programming of 8086, Comparison of 8086 & 8088 microprocessor.					10		
Unit 4:	4: Interfacing (Data Transfer) with Microprocessor: Data transfer schemes: Introduction, Handshaking signals, Types of transmission, 8255 (PPI), Serial data transfer (USART 8251), Memory interfacing, 8257 (DMA), Programmable interrupt controller (8259).			8				
Unit 5:Interfacing of Microprocessor with Timing Devices: Programmable interval timer/ counter (8253/8254): Introduction, Modes, Interfacing of 8253, Applications. Introduction to DAC & ADC, ADC & DAC Interfacing (0808, 0809).7			7					
			Total Hours 41					

	Textbooks
1.	Ramesh Gaonkar, "Microprocessor Architecture, Programming, and Applications with the
	8085", Penram International Publication (India) Pvt. Ltd., 6th Edition, 2013.



2.	A. K. Ray & K. M. Bhurchandi, " <i>Advanced Microprocessors and peripherals</i> ", Tata McGraw Hill, 3 rd Edition, 2012.				
	Reference Books				
3.	Douglas V. Hall, "Microprocessors and Interfacing", Tata McGraw Hill, 3rd Edition, 2012.				
4.	Barry B. Brey, "The Intel Microprocessors Architecture Programming and interfacing",				
	D oth use and a				

Pearson, 8th edition, 2012.

Mode of EvaluationTest / Quiz / Assignment / Mid Term Exam / End Term Exam.



Department of Electronics and Communication Engineering						
B. Tech in Electronics and Communication Engineering						
SemesterFourthSubject TitleElectromagnetic Field TheoryCode		TEC 404				
Course C	omponent	Credits		L	Т	Р
Professio Course	onal Core (PCC)	03	Contact Hours	3	0	0
Exami	nation	Theory	Waishtass. Fugle stice	CWA	MSE	ESE
Duratio	on (Hrs)	03	weigniage: Evaluation	25	25	50
	Pre-requ	uisite: Fundamentals	of Physics and Engineerin	g Mather	natics	
		Со	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
CO 1	Understan	d the concept of vec	tor algebra, gradient, diver	gence an	d curl.	
CO 2	Differentia the problem	ate among different to ns of electromagnetic	types of coordinate system c field theory.	s and ap	ply them for	or solving
<i>CO 3</i>	Analyse th	e electric field and n	agnetic field for various s	tructures.		
<i>CO 4</i>	Evaluate E	E-M wave parameter	in different medium.			
CO 5	Model Tra	nsmission line and it	s various parameter.			
CO 6	Analyse th	e behaviour of E and	H field in parallel-plate g	eometry.		
	<u> </u>					
Unit No.	Content					Hours
Unit 1:	Introduction to Electromagnetic: Vector algebra, Co-ordinate systems, Scalar and vector fields, Line integral, Surface integral, Volume integral, Gradient of a scalar field, Divergence of a vector field. Curl of a vector field. Divergence theorem and Stoke's theorem					8
Unit 2:	<i>Static Fields:</i> Coulomb's law, Electric field intensity, Electric flux density, Gauss' law & its application, Electrostatic potential, Poisson's & laplace equation, Energy density in electrostatics field, Dielectric constant, Continuity equation, Boundary condition in electrostatics, Biot-Savart law, Ampere's law & its application, Magnetic flux density, Force due to magnetic field, Magnetic energy, Boundary condition in magnetostatics				12	
Unit 3:	Maxwell's Equation and Electromagnetic Wave Propagation:Uniform plane waves, Poynting theorem, Wave polarization, Reflection & 8refraction of a plane wave at normal incidence & oblique incidence.				8	
Unit 4:	Unit 4:Introduction to Transmission Lines: Transmission line parameters, Transmission line equations, Input impedance, Reflection coefficient & Standing wave ratio, Power, Quarter wave transformer and impedance matching through single stub using smith chart.				8	
Unit 5:Parallel Plate Waveguide: Analysis of Transverse Electric (TE) mode, Transverse Magnetic (TM) Mode and Transverse Electromagnetic (TEM) waves.6				6		
Total Hours 42						44

	Textbooks						
1.	Mathew N.O. Sadiku, " <i>Elements of Electromagnetics</i> ", Oxford University Press, 3 rd Edition, 2011.						



2.	Hyatt, William, "Engineering Electromagnetics", McGraw Hill 7th Edition, 2011.					
	Reference Books					
3.	Griffiths D.J., "Introduction to Electrodynamics", Prentice Hall of India LTD, 3rd Edition,					
	2010.					
4.	Krauss, J.D., "Electromagnetics with Applications", TMH, 5th edition, 2012.					
5.	Jordan & Balmain, "Electromagnetic Wave & Radiating Systems", Prentice Hall of India LTD,					
	2 nd edition, 2010.					

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.	
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Department of Electronics and Communication Engineering							
	B. Tech in Electronics and Communication Engineering						
Semester	SemesterFourthSubject TitleCareer SkillsCode		Code	XCS 401			
Course Co	omponent	Credits		L	Т	Р	
Humanities and Social Sciences including Management course (HSMC)		02	Contact Hours	2	0	0	
Exami	nation	Theory	Weightage, Evaluation	CWA	MSE	ESE	
Duratio	n (Hrs)	03	weigniage: Evaluation	25	25	50	
		Pre-requisit	e: Communication Skills				
		Со	ourse Outcomes				
Upon com	pletion of th	nis course, the stude	ents will be able to				
CO 1	Have a log differentia	gical approach to th te between the stron	e problems and at the sar and the week arguments	ne time t and valid	they will b lity of the s	be able to statement.	
<i>CO</i> 2	Improve th	he reasoning ability of	of the students by using the	e different	t methods.		
CO 3	Learn different approaches related to the coding or other complex types of problems which are related to the sequence detection etc.					problems	
<i>CO</i> 4	Get a basic knowledge of the data interpretation.						
CO 5	Acquire kr way is also	nowledge of puzzles included.	and different methods to	solve the	puzzles in	an easier	
CO 6	Develop th	e basic skills of aptiv	tude and logical reasoning.				
Unit No.	Content					Hours	
Unit 1:	<i>t 1:</i> Functional Grammar: Parts of speech, Articles, Parallel construction, Subject verb agreement.				6		
Unit 2:	Logical Reasoning: Blood relation, Puzzle test, syllogism, Classification, Seating/placing 6 arrangements,			6			
Unit 3:	Logical Reasoning: Ranking and comparison, Sequential order and things, Selection based on conditions, Data interpretation				6		
Unit 4:	Building V Analogy, F	ocabulary: Para jumbles, Antony	ms and synonyms.			6	
Total Hours 24							

	Textbooks
1.	R. K. Bansal and J.B. Harrison, "Spoken English for India", Orient Longman.
2.	Thomson and Martinet, "A practical English Grammar", Oxford University Press.
3.	Malti Aggarwal, "Professional Communication".
4.	M. A. Pink and A. E. Thomas, "English grammar, composition and correspondence", S.
	Chand and Sons.
5.	"A Dictionary of Modern Usage", Oxford University Press.
	Reference Books
6.	R.S Agarwal, "Quantitative aptitude".
7.	R.S Agarwal, "Verbal and Non-Verbal Reasoning".



8. Shakuntala Devi "*puzzles*".

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Depa	artment of Electroni	cs and Communication E	ngineerir	ıg	
	<u> </u>	Tech in Electronics	and Communication Eng	ineering	0	
Semester	Fourth	Subject Title	Communication System	s I Lab	Code	PEC 401
Course C	omponent	Credits		L	Т	Р
Professio Course	onal Core (PCC)	01	Contact Hours	0	0	2
Exami	ination	Practical	Weichtage, Englugtion	CWA	MSE	ESE
Duratio	on (Hrs)	02	weigniage: Evaluation	25	25	50
		Pre-requisite: B	asics of CRO and MATLA	В		
		Со	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
<i>CO</i> 1	Understan	d and analyse the w	aveforms of DSB-FC, DSI	<u>3-SC, SS</u>	B-SC.	
<u>CO 2</u>	Analyse th	e waveforms of diffe	erent angle modulation tech	nniques (FM & PM)).
CO 3	Compare a	and evaluate the per	tormances of different ana	log modu	lation tech	niques.
CO 4	Investigate	e pulse analog modu	lation system and analyse	their syst	em perform	nance.
Eur Ma	Name of the	Free article and				
Exp. No.	Concretion	of omplitude modul	atad (DSP EC) waveform	and datar	minos its m	adulation
1.	indices.		aled (DSB-FC) waveloring		mines its ii	loculation
2.	Generation of Double sideband suppressed carrier (DSB-SC) waveform using balanced modulator					
3.	Generation of single sideband suppressed carrier (SSB-SC) signal.					
4.	Generation of frequency modulated (FM) signal using voltage-controlled oscillator.					
5.	Demodulat	ion of FM signal usi	ng phase locked loop (PLL	<i>.</i>).		
6.	Generation	and detection of PA	М.			
7.	Generation	and detection of PW	/M & PPM.			
8.	Simulation	of Double sideband	suppressed carrier (DSB-S	C) signa	l using MA	ATLAB.
9.	Simulation	of amplitude modul	ated (DSB-FC) signal usin	g MATL	AB.	
10.	Simulation	of Single sideband s	suppressed carrier (SSB-SC	C) signal	using MAT	ΓLAB.
11.	Simulation	of frequency modul	ated (FM) signal using MA	TLAB.		
12.	Simulation	of phase modulated	(PM) signal using MATL	AB.		
13.	Simulation	of Frequency division	on Multiplexing (FDM) us	ing MAT	LAB.	
Innovative	Experiment	ts				
14.	To analyse	the radiation pattern	of Yagi-Uda antenna.	6.1		
15.	Getting familiar with the features and basic operations of the spectrum analyzer and investigating signals in frequency domain.		lyzer and			
16.	To plot the MATLAB.	frequency domain	representation of DSB-FC,	DSB-SC	C and SSB	-SC using
17.	To plot the	frequency domain r	epresentation of FM, and F	M using	MATLAB	
18.	To demon MATLAB.	strate the effect of	f AWGN in DSB-FC, I	OSB-SC	and SSB-	SC using
19.	MATLAB. Simulation of frequency modulation and demodulation in noisy condition using MATLAB.			n in noi		

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam



	Dep	artment of Electroni	ics and Communication E	ngineerir	ıg	
	В.	Tech in Electronics	and Communication Eng	ineering		
Semester	Fourth	Subject Title	Analog Integrated Circu	its Lab	Code	PEC 402
Course Co	mponent	Credits		L	Т	Р
Professional Core Course (PCC)		01	Contact Hours	0	0	2
Exami	nation	Practical	Weichtness Fugle stiers	CWA	MSE	ESE
Duratio	n (Hrs)	02	weightage: Evaluation	25	25	50
		Pre-requisite	: Electronics Circuits Lab			
		Со	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
<i>CO</i> 1	Understan	d the concepts of op	en loop/closed loop Op-Ai	np config	gurations.	
<i>CO 2</i>	Analyse th	e performance paran	neters of Active Filters usin	ng Op-Ai	np.	
<i>CO 3</i>	Evaluate using OP-A	the performance cha	aracteristics of comparato	r and m	ulti-vibrato	or circuits
<i>CO</i> 4	Design various linear and non-linear circuits using Op-Amp.					
-				•		
Exp. No.	Name of the Experiment					
1.	Design and Test open loop inverting and non-inverting op-amp.					
2.	Design and Test closed loop inverting and non-inverting op-amp.					
3.	Design and Test op-amp based adder and subtractor circuits.					
4.	Design and Test op-amp based integrator circuits.					
5.	Design and	l Test op-amp based	differentiator circuits.			
6.	Design and	l Test op-amp based	active RC low pass filters.			
7.	Design and	l Test op-amp based	active RC high pass filters			
8.	Design and Test op-amp based active Band pass filter.					
9.	Design and Test op-amp based comparator circuits.					
10.	Realize op-amp based triangular wave generator.					
11.	Analyze CMRR and slew rate of Op-Amp.					
12.	12. Design and test astable and monostable multivibrator circuits using 555 timer.					
Innovative	Experimen	ts				
13.	Design and	l test unity gain salle	n key low pass filter.			
14.	Design bar	nd reject filter.				
15.	Design and test Op-amp based PLL.					
<i>16</i> .	Self-motiv	ated experiments or	suggested by the lab inchar	·ge.		

 Mode of Evaluation
 Test / Quiz / Assignment / Mid Term Exam / End Term Exam



	Dep	artment of Electroni	cs and Communication E	ngineerii	ıg			
	<u> </u>	Tech in Electronics	and Communication Eng	ineering	0			
Semester	<i>er</i> Fourth <i>Subject Title</i> Microprocessor Lab $Code$ PE_{40}			PEC 403				
Course Co	mponent	Credits		L	Т	Р		
Professio	nal Core	01	Contact Hours	0	0	2		
Course	(PCC)			CTTL 4				
Exami	nation	Practical	Weightage: Evaluation	CWA	MSE	ESE		
Duratio	n (Hrs)	02		25	25	50		
		Pre-requisite	2: Digital Electronics Lab					
Unon com	alation of t	CO	urse Outcomes					
CO 1	Demombo	ns course, the stude	ents will be able to					
01	Kemembe	r 8085 and 8080 inst	ruction set.		iononnooo	an haad		
CO 2	microcom	uter kit	iory language programs	s on n	licroproces	sor-based		
	Apply the	programming concer	ots to test and debug assem	bly lang	lage progra	ams in the		
<i>CO 3</i>	laboratory.	programming conce		iory rung	auge progre			
<i>CO</i> 4	Assemble	various devices and	memories with microproce	ssor for a	ny defined	l task.		
Exp. No.	Name of th	he Experiment						
1.	Write prog	ram in 8085 to swap	two 8-bit numbers.					
2	Write a program in 8085 to move a block of data bytes from one location to another							
2.	location.							
3.	Write programs in 8085 to perform addition & subtraction of 8-bit number with carry /							
4	borrow.		1'		-			
4.	write a program in 8085 for addition of 16 bits numbers with carry.							
5.	(a) write a (b) Write a	n ALP in 8085 to fin	id two's complement of 8/	16 bit dat	1. a.			
6.	Write an ALP in 8085 to add two 8-bit BCD data.							
7	(a) Write a	n ALP in 8085 to fin	d larger number between t	wo numb	ers.			
7.	(b) Write a	n ALP in 8085 to fin	nd smaller number between	two nun	nbers.			
8.	Write an ALP in 8085 to find largest /smallest in a series of n number.							
9.	Write an A	LP in 8085 to find m	nultiplication of 8-bit numb	ber.				
10.	(a) Write a	program in 8086 to	add two 16-bit numbers gi	ven by th	e user.			
	(b) Write a program in 8086 to subtract two 16-bit numbers given by the user.							
11.	(a) Write a program in 8086 to multiply two 16-bit data.							
	(b) Write a	program in 8086 to	find the largest no. from a	n uata.	n numbor	a stored in		
12	(a) write a	program in 8080 to	find the largest no. from a	i allay Ol	II IIUIIIDEIS	s storeu m		
12.	(b) Write a program in 8086 to perform sorting of given set of numbers.							
13.	Write a program in 8086 to add and subtract two 8-bit BCD numbers.							
14	(a) Write a	program in 8086 to	convert a BCD number to	its ASCI	code equi	valent.		
(b) Write a p) Write a program in 8086 to convert a BCD number to its grey code equivalent.						
Innovative	Experimen	ts						
15.	Write an A	LP for traffic light c	ontroller using 8085.					
<i>16</i> .	Write an A	LP for interfacing of	FPPI 8255 with microproce	essor 808	5.			
17.	A data stri	ng of no. of bytes is	converted to its equivalen	t 2's con	plement u	sing 8086		
	string instr	uction.						



Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam



	Depo	artment of Electroni	cs and Communication E	ngineerii	ıg	
	<u> </u>	Tech in Electronics	and Communication Eng	gineering	0	
Semester	Fifth	Subject Title	Digital Signal Proces	sing	Code	TEC 501
Course Co	omponent	Credits		L	Т	Р
Professio	onal Core	03	Contact Hours	3	0	0
Course	(PCC)	05		5	0	0
Exami	nation	Theory	Wajahtaga: Evaluation	CWA	MSE	ESE
Duratio	n (Hrs)	03	Weighlage. Evaluation	25	25	50
		Pre-requisi	te: Signals and Systems			
		Со	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
CO 1	Understan	d discrete time signa	als & systems and various	transform	ns.	
<i>CO 2</i>	Analyse ar	nd evaluate the DFT	and FFT algorithm.			
<i>CO 3</i>	Evaluate t	he implementation of	f digital filter structures.			
<i>CO</i> 4	Apply the	design methods of II	R digital filter.			
<i>CO</i> 5	Analyse ar	nd apply design tech	niques of FIR digital filters	8.		
CO 6	Integrate	the knowledge in	designing of various dig	gital sign	al process	sing-based
	systems.					
	~					
Unit No.	Content					Hours
Unit 1:	Transforms: Elements of Digital Signal Processor, Discrete time sinusoids, Discrete time signals and systems, Correlation (Cross and auto correlation). Z transform 8 and its properties, ROC properties, Inverse Z transform. Introduction to Discrete time Fourier series (DTFS) and Discrete time Fourier transform (DTFT) and their properties.					8
Unit 2:	DFT and FFT Algorithms: Discrete Fourier Transform (DFT), DFT as linear transformation, DFT properties, Circular convolution, Fast Fourier Transform (FFT): Decimation –in- Time Fast Fourier Transform (DITFFT), Decimation –in- Frequency Fast Fourier Transform (DIFFFT), Applications of FFT, Goertzel algorithm,				9	
Unit 3:	Structures of Digital Filters: Structure for realization of digital filters: Direct form I, Direct form II, Cascade and parallel Form, Transversal structure linear phase FIR filter structure, Lattice structure, Signal flow graph and transposed structure.					
Unit 4:	Design of Infinite Impulse Response (IIR) Digital Filters: Design of IIR digital filters using impulse invariance technique, Bilinear transformation technique, Approximation of derivatives technique, Design of low pass Butterworth filter and Chebyshev filter.					
Unit 5:	Design of Finite Impulse Response (FIR) Digital Filters: Symmetric and anti-symmetric FIR filters, Linear phase FIR filters, Design using frequency sampling technique , Design of FIR filter using window techniques- Hamming, Hanning and Blackman, Rectangle, Bartlett and Kaiser windows, Concept of optimum equi-ripple approximations, Effect of finite word length, Fixed point and binary floating point number representations, Comparison, Overflow error, Truncation error.42					



	Textbooks					
1.	J. G. Proakis, D.G. Manolakis and D. Sharma, " <i>Digital Signal Processing Principles</i> , <i>Algorithms and Applications</i> " Pearson Education 4 th edition 2012					
2.	Oppenhiem V.A.V and Schaffer R.W, " <i>Discrete – time Signal Processing</i> ", Prentice Hall, New Jersey, US., 3 rd edition, 2013.					
	Reference Books					
3.	S.K.Mitra, "Digital Signal Processing", TMH, New Delhi, India, 4th edition, 2013.					
4.	Emmanuel C. Ifeachor, " <i>Digital Signal Processing A Practical Approach</i> ", Prentice Hall, New Jersey, US, 2 nd edition reprint, 2011.					

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Depo	artment of Electroni	cs and Communication E	ngineerir	ıg	
	<u> </u>	Tech in Electronics	and Communication Eng	ineering	0	
Semester	Fifth	Subject Title	Communication Syste	ms II	Code	TEC 502
Course C	omponent	Credits		L	Т	Р
Professio Course	onal Core (PCC)	03	Contact Hours	3	0	0
Examination		Theory	Weightage, Englishing	CWA	MSE	ESE
Duratio	on (Hrs)	03	weigniage: Evaluation	25	25	50
	Pre-	requisite: Signals an	d Systems, Communicatio	n systems	s I	
		Со	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
CO 1	Demonstra schemes.	ate the concepts of	sampling, Quantization a	nd variou	is wavefor	m coding
CO 2	Analyse th	e effect of ISI and th	eir mitigation.			
<i>CO 3</i>	Design and	l develop different d	igital modulation systems.			
CO 4	Describe t effect of A	he mathematical mo WGN channel and d	del of a digital modulatio etermine its bit error rate p	n technic erforman	que, charac	cterize the
CO 5	Apply the	concepts of informat	ion theory for digital comr	nunicatio	n systems.	
CO 6	Apply the concepts of digital communications for reliable communication with high data rate.					
Unit No.	Content					Hours
Unit 1:	Sampling and Baseband Transmission:Model of digital communication system, Sampling of low pass and band pass signals, Distortion due to sampling, Uniform and non-uniform quantization, Quantization error, Companding (A law and μ law), Pulse code modulation, Differential PCM and delta modulation, Adaptive delta modulation, Linear10					
Unit 2:	Digital Transmission through Band Limited AWGN Channels: Representation of line codes – Properties and applications of line codes, Power spectral density of NRZ & RZ unipolar format, NRZ & RZ polar format, NRZ &RZ bipolar format, and Manchester format, Intersymbol 8 interference, Nyquist criterion for Distortion-less baseband binary Transmission, Raised cosine filter, Introduction to equalization techniques and Zero forcing equalizer.					8
Unit 3:	Digital Modulation Techniques: Represent of bandpass signals and systems, Gram Schmidt procedures, Representation of digitally modulated signals; Amplitude shift keying, Phase shift keying, Differential PSK, Quadrature PSK, Frequency shift keying, Minimum shift keying, Quadrature Amplitude Modulation (QAM).					
Unit 4:	<i>nit 4:</i> Optimum Receivers for AWGN Channel: Model for received signal passed through an AWGN channel, Matched filter receiver and correlation receiver, Detector, Probability of error calculation for BASK, BPSK, QPSK, BFSK, and QAM.				7	
Unit 5:	Information Theory and Error Control Coding:Information measure; Entropy and information rate, Discrete memory less source, Mutual information, Binary symmetric channel, Discrete channel capacity, Continuous information source, Continuous channel capacity, Source coding theorem, Shannon-Fano coding, Huffman coding, Channel				10	



Total Hours	45
Convolution coding.	
capacity theorem, Linear block codes, Coding Gain, Hamming codes,	

Textbooks Simon Haykin, "Digital Communications", 2001, 4th edition, John Wiley, India. 2. Herbert Taub and Donald L Schilling, "Principles of Communication Systems", 2012, 4th

	edition, Tata McGraw Hill, New Delhi.
	Reference Books
3.	John.G. Proakis, "Digital Communication, 2014, 5th edition, Pearson Education, Noida, India.
4.	Bernard Sklar, "Digital Communications: Fundamentals and Applications", 2016, 2 nd edition,
	Prentice Hall, New Jersey, US.
5.	B. P. Lathi and Z. Ding, "Modern Digital and Analog Communication Systems", 2009, 4th
	edition, Oxford University Press.

Mode of Evaluation	Test / Quiz / Assignment / Mid Term Exam / End Term Exam.

1.



	Depa	artment of Electron	ics and Communication E	ngineerir	ıg	
	B. Tech in Electronics and Communication Engineering					
Semester	Fifth	Subject Title	Microcontroller and Em Systems	bedded	Code	TEC 503
Course C	omponent	Credits		L	Т	Р
Professio Course	onal Core (PCC)	03	Contact Hours	3	0	0
Exam	nation	Theory	Weightage Englustion	CWA	MSE	ESE
Duration (Hrs) 03 Vergenage: Evaluation 2			25	25	50	
		Pre-requisite: Mic	croprocessor and its application	tions		
		Co	ourse Outcomes			
Upon com	pletion of th	his course, the stud	ents will be able to			
<u>CO I</u>	Remember	r the concept of mic	rocontroller.	- 1 1 1	1	
<i>CO</i> 2	Understan	id the concepts of er	nbedded systems using 805	and Ar	duino IDE	
<i>CO 3</i>	Apply the motors.	concepts of interfaci	ng of 8051 and Arduino to	periphera	l device, se	ensors and
CO 4	Examine to counter.	the applications of	8051 microcontroller and	l Arduino	o as I/O, 1	timer and
CO 5	Evaluate programmi	different tasks using for Arduino.	ng assembly language pro	ogrammir	ng for 805	51 and C
CO 6	Develop fo	oundation for the des	signing of Advanced embed	lded syste	ems.	
Unit No.	Content					Hours
Unit 1:	Microcontroller: Difference between microprocessors and microcontrollers, Types of Micro- controllers, ARM processor, Memory structure of 8051, Processor architecture – Harvard v/s Von Neumann, CISC v/s RISC, 8051 architecture, control storage, Variable area, Stack, Hardware register space, SFR, 8051 pin diagram					
Unit 2:	8051 Instruction Set: Addressing modes, External addressing, Instruction execution, Instruction set – data movement, Arithmetic, Bit operators, Branch, Software development tools like assemblers, Simulators, O/P file formats. Assembling and running an 8051 program, 8051 data types, 8051 flag bits and the PSW register, 8051 register banks and stack				9	
Unit 3:	Programming of 8051 and Interrupts: Programming of 8051, I/O bit manipulation. Timer, Counter, Programming of timer, 8051 interrupts, Interrupts priority in the 8051, and interrupts programming.					
Unit 4:	Introduction to Arduino IDE PlatformIntroduction to ATMEGA328 microcontroller and to Arduino IDE,Instruction set, Hardware, characteristics, Interfacing with differentperipheral devices, Debugging hardware errors, Using PWM I/O pins,Interfacing Arduino hardware with internet of things					
Unit 5:	Interfacing: Interfacing with 8051: LCD, Keyboard, ADC, DAC interfacing, Sensor interfacing and signal conditioning, Stepper motor and DC motor, Basics of serial communications, 8051 connection to RS-232, 8051 serial port programming assembly.				8	
		Tota	Hours			42



	Textbooks
1.	Muhammad Ali Mazidi, Janice G. Mazidi, Rolin D. McKinlay, " <i>The 8051 Microcontrollers & Embedded Systems</i> ", Pearson Education, 2 nd Edition, 2007.
2.	V Udayashankara, M S Mallikarjunaswamy, "8051 Micro-controller, Hardware, Software and Application", Tata McGraw-Hill education, 2009.
3.	Simon Monk, " <i>Programming Arduino: Getting Started with Sketches</i> ", McGraw-Hill education, 2 nd Edition, 2016.
	Reference Books
4.	Kenneth Ayala, "The 8051 Microcontroller", West Publishing Company, 3rd edition, 2007.
5.	Julien Bayle, "C-Programming for Arduino", Packt Publishing, 2013.

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Department of Electronics and Communication Engineering					
	B.	Tech in Electronics	and Communication Eng	ineering	0	
Semester	Fifth	Subject Title	Antenna and Wave Prop	agation	Code	TEC 504
Course C	ourse Component Credits L		Т	Р		
Professional Core Course (PCC)		03	Contact Hours	3	0	0
Examination		Theory	Weichtage, Engligation	CWA	MSE	ESE
Duratio	on (Hrs)	03	weigniage: Evaluation	25	25	50
Pre-requi	site: Commu	unication Systems I,	Communication Systems I Theory	I, and Ele	ectromagne	etic Field
		Со	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
CO 1	Understan	d the concept of rad	iation.			
<i>CO</i> 2	Compute f	fundamental paramet	ters of antenna and differer	nt antenna	a character	istics.
<i>CO 3</i>	Analyse ur	niform and non-unifo	orm antenna array.			
<u>CO 4</u>	Evaluate f	undamental paramet	ers for designing of micros	trip patcl	n antenna.	
CO 5	<i>CO</i> 5 Develop the concepts of wave propagation through free space.					
<i>CO</i> 6	CO 6 Design antenna for different application.					
T T */ N T						
Unit No.	Content	F J 4 - J				Hours
Unit 1:	<i>I:</i> Potential theory, Helmholtz integrals, Radiation from a current element, Basic antenna parameters, Radiation field of an arbitrary current distribution, small loop antennas.				8	
Online 100 pullicitiesReceiving Antenna: Reciprocity relations, receiving cross section, and its relation to gain, Reception of completely polarized waves, Linear antennas, Current distribution, Radiation field of a thin dipole, Folded dipole, Feeding methods, Radiation from helical antenna.			10			
Unit 3:	<i>Jnit 3:</i> Antenna Arrays: Array factorization. Array parameters. Broad side and end fire arrays. Yagi- Uda arrays Log-Periodic arrays, Broadband antennas, Helical antenna, Spiral antenna.			8		
Unit 4:	Aperture Antennas:Fields as sources of radiation, Horn antennas, Babinet's principle, Parabolicreflector antenna, Feeding systems, Microstrip antennas, Metamaterialantenna.					
Unit 5:	antenna. Wave Propagation: Propagation in free space, Propagation around the earth, Surface wave propagation, Structure of the ionosphere, Propagation of plane waves in ionized medium, Determination of critical frequency, MUF, Fading, Troposphere propagation, Super refraction.					
		Total	Hours			42

 Textbooks

 1. J. D. Kraus, R. Marhefka, A. Khan, "Antennas and Wave Propagation", McGraw Hill Education, Publication, 4th edition, 2017.



2.	C. A. Balanis "Antenna analysis & Design", John Wiley, 3rd edition, 2016.
3.	R. E. Collin, "Antennas and Radio Wave Propagation", McGraw-Hill, 1st edition, 2013.
	Reference Books
4.	A. R. Harish and M. Sachidananda "Antennas and Wave Propagation", Oxford Publication,
	1 st edition, 2017.
5.	Joe Myers, "Structure and Applications of Microstrip Antennas", Clanrye International
	Publication, 1st edition, 2015.

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Den	artment of Electron	ics and Communication E	noineerin	10	
	<u> </u>	Tech in Electronics	and Communication Eng	vineering	8	
Semester	Fifth	Subject Title	Career Skills		Code	XCS 501
Course C	omponent	Credits		L	Т	Р
Humanities and Social Sciences including Management course (HSMC)		02	Contact Hours	2	0	0
Exami	ination	Theory	Weightage: Evaluation	CWA	MSE	ESE
Duratio	on (Hrs)	03	weigniage: Evaluation	25	25	50
		Pre-requisit	e: Communication Skills			
		Со	ourse Outcomes			
Upon com	pletion of th	his course, the stude	ents will be able to			
CO 1	<i>CO 1</i> Have a logical approach to the problems and at the same time they will be able to differentiate between the strong and the week arguments and validity of the statement.					
CO 2	Improve the reasoning ability of the students by using the different methods.					
CO 3	Learn different approaches related to the coding or other complex types of problems which are related to the sequence detection etc.					
<i>CO</i> 4	Get a basic	knowledge of the d	lata interpretation.			
CO 5	Acquire kr way is also	nowledge of puzzles included.	and different methods to	solve the	puzzles in	an easier
CO 6	Develop the basic skills of aptitude and logical reasoning.					
Unit No.	Content					Hours
Unit 1:	<i>Thit 1:</i> Effective Reading Skills: Reading comprehension, Purpose of reading, Skimming and scanning. Tips for improving comprehension skills. (For effective reading skills practice papers on Reading Comprehension will be provided to students).				4	
Unit 2:	Aptitude section: Clocks, Calendar, Profit/loss, Percentage, Average.4				4	
Unit 3:	Aptitude S Ages, Train	Section: ns & Boats, Simplifi	cation, Ratio & proportion	, Partners	hip.	12
Unit 4:	Critical Re Analyze lo	easoning: gical arguments.				4
Total Hours 24						24

	Textbooks
1.	R.K.Bansal and J.B. Harrison, "Spoken English for India", Orient Longman.
2.	Thomson and Martinet, "A practical English Grammar", Oxford University Press.
3.	Malti Aggarwal, "Professional Communication".
4.	M. A. Pink and A. E. Thomas, "English grammar, composition and correspondence", S.Chand
	and Sons.
5.	"A Dictionary of Modern Usage", Oxford University Press.
	Reference Books
6.	R.S Agarwal, "Quantitative aptitude".
7.	R.S Agarwal, "Verbal and Non Verbal Reasoning".
5. 6. 7.	and Sons. "A Dictionary of Modern Usage", Oxford University Press. Reference Books R.S Agarwal, "Quantitative aptitude". R.S Agarwal, "Verbal and Non Verbal Reasoning".



8. Shakuntala Devi "*puzzles*".

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Department of Electronics and Communication Engineering					
	B.	Tech in Electronics	and Communication Eng	gineering	0	
Semester	Fifth	Subject Title	Digital Signal Processir	ng Lab	Code	PEC 501
Course Component		Credits		L	Т	P
Professio Course	onal Core (PCC)	01	Contact Hours	0	0	2
Exami	ination	Practical		CWA	MSE	ESE
Duratio	on (Hrs)	02	weightage: Evaluation	25	25	50
		Pre-requisite:	Fundamentals of MATLAI	В		
		Со	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
CO 1	Understan functions.	id, implement, and a	analyse various basic signa	al convolu	ution and c	orrelation
<i>CO</i> 2	Analyse an	nd evaluate DFT and	I IDFT functions through N	MATLAB	software.	
<i>CO 3</i>	Analyse an	nd evaluate FFT algo	orithm through MATLAB	software.		
<i>CO</i> 4	Analyse an	nd evaluate FIR and	IIR digital filter through N	IATLAB	software.	
Exp. No.	o. Name of the Experiment					
1.	Generation of various signals functions (Unit impulse, Unit step, Unit ramp signals, Sinc & Signum) through MATLAB.					
2.	 Sampling theorem verification by generating and plot of the continuous time sinusoid signal into discrete time signal and reconstruction of the continuous time signal from its sampled signals 					
3.	Write a MA	ATLAB program to p	plot the power spectral den	sity (PSD) of given	signal.
4.	Write a MA	ATLAB program to p	plot the energy spectral der	nsity (ESI	D) of giver	ı signal.
5.	Write a MATLAB program to generate and plot the real, imaginary, magnitude and phase part of given imaginary exponential function.					
6.	To convolve sequence (i) linear (ii) circular, and their characteristics using MATLAB. (By given problems, verify it by mathematically as well as experimental ways).					
7.	To correlate of sequences using MATLAB. (By given problems, verify it by mathematically as well as experimental ways and plot them)					
8.	DFT and II	DFT computation for	a sequence N points using	g MATLA	AB.	
<i>9</i> .	Developme mathematic	ent of FFT algori cally as well as expen	thm using MATLAB, rimentally.	validate	the result	through
10.	Generation	of Gaussian distribu	ited numbers using MATL	AB.		
11.	To simulate	e 2 nd order IIR Filter	using MATLAB.			
12.	To simulate	e and design FIR filt	er using MATLAB.			
Innovative	Experiment	ts				
13.	Circular Co	onvolution of two Se	quences by using FFT met	hod.		
14.	Write a M algorithm.	ATLAB Program t	o implement Radix2 Dec	imation i	n Time (I	OIT) FFT

 Mode of Evaluation
 Test / Quiz / Assignment / Mid Term Exam / End Term Exam



	Department of Electronics and Communication Engineering					
	В.	Tech in Electronics	and Communication Eng	ineering		
Semester	Fifth	Subject Title	Communication Systems	s II Lab	Code	PEC 502
Course C	omponent	Credits		L	Т	Р
Professional Core Course (PCC)		01	Contact Hours	0	0	2
Examination		Practical		CWA	MSE	ESE
Duratio	n (Hrs)	02	Weightage: Evaluation	25	25	50
	Pre-	requisite: Basics of	CRO and fundamentals of	MATLA	В	
		Со	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
CO 1	Develop an	nd understand the si	ignal sampling, quantizatio	n, and its	reconstrue	ction.
<i>CO</i> 2	Develop an	n ability to understa	nd and design various way	veform co	ding techn	niques.
<i>CO 3</i>	Develop an	n ability to evaluate	and design various digital	modulati	on techniq	ues.
<i>CO 4</i>	Develop an ability to evaluate and design Time Division Multiplexing technique.					
Exp. No.	Name of the Experiment					
1.	Sampling of the signal using different sampling techniques and reconstruction of the sampled signals.					
2.	Generation	and detection of pul	se code modulation techni	que.		
3.	Generation and detection of Delta demodulator technique.					
4.	To demons	strate Time division 1	nultiplexing & de-multiple	exing pro	cess.	
5.	Mapping o	f binary data into bas	seband pulses using differe	nt data fo	rmatting te	echniques.
6.	Mapping of binary data into passband signal using binary amplitude shift keying (BASK).					
7.	Mapping of binary data into passband signal using binary frequency shift keying (BFSK).					
8.	Mapping of binary data into passband signal using binary phase shift keying (BPSK).					
9.	Simulation	of binary amplitude	shift keying (BASK) modu	lated Sig	nal using N	IATLAB.
10.	Simulation	of binary frequency	shift keying (BFSK) modu	lated sign	nal using N	IATLAB.
11.	Simulation	of binary phase shif	t keying (BPSK) modulate	d signal ı	using MAT	LAB.
12.	Simulation	of differential phase	shift keying (DPSK) using	g MATL	AB.	
Innovative	Experimen	ts				
13.	To plot and using MAT	d analyze the wavef	orm for Quadrature Phase stream.	Shift Ke	ying (QPS	SK) signal
<i>14</i> .	Simulation	of QAM modulation	n and demodulation using l	MATLAI	3.	
15.	Simulation	of MSK modulation	and demodulation using N	ATLAE	3.	

Mode of Evaluation	Test / Quiz / Assignment / Mid Term Exam / End Term Exam
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	Department of Electronics and Communication Engineering							
	В.	Tech in Electronics	and Communication Eng	gineering				
Semester	ster Fifth Subject Title Microcontroller & Embedded Lab		Code	PEC 503				
Course Component		Credits		L	Т	Р		
Professional Core Course (PCC)		01	Contact Hours	0	0	2		
Examination		Practical		CWA	MSE	ESE		
Duratio	n (Hrs)	02	Weightage: Evaluation	25	25	50		
		Pre-requist	ite: Microprocessor Lab					
		Со	urse Outcomes					
Upon com	pletion of th	nis course, the stude	ents will be able to					
CO 1	Remember	r 8051 microcontrol	ler instruction set.					
CO 2	Understan microcomp	nd different assem outer kit.	ibly language programs	s on m	nicrocontro	ller-based		
CO 3	Apply the laboratory.	programming conce	pts to test and debug assem	ıbly langı	lage progra	ams in the		
<i>CO</i> 4	Assemble	various devices and	memory with microcontrol	ler for an	y defined t	ask.		
Exp. No.	Name of the Experiment							
1	a) Write a program in 8051 to add two 8-bit numbers.							
	b) Write a program in 8051 to subtract two 8-bit numbers.							
2.	a) Write a program in 8051 to add two 16-bit numbers.b) Write a program in 8051 to subtract two 16-bit numbers.							
	a) Write a program in 8051 to find the largest no. from an array of n numbers stored in							
3.	an array.							
	b) Write a program in 8051 to perform smallest no. from an array of n numbers stored							
4.	Write a pro	ogram in 8051 to add	two 8-bit BCD numbers.					
5.	a) Write a j	program in 8051 to r	nultiply two 8-bit data.					
6	Write a pro	program in 8051 to con	wert a BCD number to its	A SCIL co	de equival	ant		
0. 7	Write a pro	ogram in 8051 which	move a block of data		ue equivan			
8.	Write a pro	ogram in 8051 which	sort a block of data					
<u>9</u> .	Write a pro	ogram in 8051 which	convert a binary number t	o its grev	code equi	valent		
10.	Write a pro	gram in 8051 which	determines average of n n	umbers.				
11.	Write a pro	ogram in 8051 to con	vert a BCD number to its b	binary co	de equivale	ent		
10	Write a pro	ogram in Arduino to	use PWM pin to increase	and decr	ease the in	tensity of		
12.	brightness in an LED.							
13.	Write a pro	ogram in Arduino to	interface LED and create a	burglar a	alarm.			
14.	Write a pro	ogram in Arduino to	interface with a dc motor.					
Innovative	Experimen	ts						
15.	8255 Interf	face to 8051.						
<i>16</i> .	Traffic Lig	ht Controller interfac	ce to 8051.					
17.	Interfacing	Arduino IDE to crea	ate an IOT data log.					

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam



	Dep	artment of Electroni	cs and Communication E	ngineerir	ıg	
	<u> </u>	Tech in Electronics	and Communication Eng	ineering	8	
Semester	Sixth	Subject Title	Wireless Communica	tion	Code	TEC 601
Course C	omponent	Credits		L	Т	Р
Professio Course	onal Core (PCC)	03	Contact Hours	3	0	0
Exami	nation	Theory	Weichtness Fugle stiers	CWA	MSE	ESE
Duratio	n (Hrs)	03	weignlage: Evaluation	25	25	50
		Pre-requisite:	Communication Systems I	Ι		
		Со	urse Outcomes			
Upon com	pletion of tl	his course, the stude	ents will be able to			
CO 1	Demonstr evolution of	ate an understanding of different wireless c	g on functioning of wireless communication systems an	s commu d standar	nication sy ds.	ystem and
CO 2	Demonstr of differen	ate an understanding t generations and star	on cellular concepts, cellu ndards for mobile cellular	lar archite communi	ecture, and cation.	evolution
<i>CO 3</i>	Analyse an	nd design of mobile 1	radio propagation models.			
CO 4	Analyse di impairmen	ifferent channel para t removal techniques	meters, causes of impairme	ents in sig	nal propag	gation and
CO 5	<i>CO 5</i> Analyse different diversity combining techniques.					
CO 6	Apply the	concepts of spread sp	bectrum for designing wire	less Com	nunication	Systems.
Unit No.	Content					Hours
Unit 1:	 Wireless Communication System, Standards & Cellular Concept: An overview of wireless communication, Basic elements in wireless communication systems, Wireless communication system, and standards. Evolution of mobile cellular communication (1G, 2G. 2.5G, 3G and beyond), Typical cellular standards (AMPS, GSM, GPRS, WCDMA, LTE, LTE-A). Cellular concept – Frequency reuse – Channel assignment strategies – Handoff strategies – Interference & system capacity, Trunking & grade of service. Improving coverage and capacity in cellular system 			10		
Unit 2:Evolution of Mobile Radio Propagation Fundamentals: Large Scale Path Loss:Unit 2:Introduction to radio wave propagation, Free space propagation model, Basic propagation mechanisms, Ground reflection (Two-Ray) Model, Indoor propagation models, path loss model.			7			
Unit 3:	Small Scale Fading & Multipath: Small-scale multipath propagation, Impulse response model of multipath channel, Parameters influencing small scale fading, Types of small-scale fading, Diversity mechanisms.					9
Unit 4:	4: Diversity Combining Techniques: Rayleigh & Rician fading models, Selection Combining (SC), Equal Gain Combining (EGC), and Maximal Ratio Combining (MRC), Derivation of SC, EGC, and MRC improvement, RAKE receiver.				7	
Unit 5:	Spread sp Multiple ad spectrum hopping.	ectrum: ccess techniques, Pse (DS-SS), Frequency	eudo-noise sequence, Direc hopped spread spectrum	ct sequent m (FHSS	ce spread S). Time	7
		Total	Hours			40



	Textbooks		
1.	Sanjay Kumar, "Wireless Communication: The Fundamental and Advanced Concepts", 2015		
	(Indian reprint), 1 st edition, River Publishers Series.		
2.	Rappaport, T.S., "Wireless communications", 2012 (Reprint), 2nd edition, Pearson Education,		
	Noida, India.		
3.	David Tse, Pramod Viswanath, "Fundamentals of Wireless Communication", Cambridge		
	University Press, 2005.		
	Reference Books		
4.	T L Singal, "Wireless Communications", 2014 (Reprint), 1st edition, Tata McGraw Hill		
	Education, New Delhi, India.		
5.	Simon Haykin and Michael Moher, "Modern Wireless Communications", 2005, 2 nd edition,		
	Parson Education, Delhi.		
6.	Andrea Goldsmith, "Wireless Communications", 2005, Cambridge University Press.		

Mode of EvaluationTest / Quiz / Assignment / Mid Term Exam / End Term Exam.



Department of Electronics and Communication Engineering						
	В.	Tech in Electronics	and Communication Eng	ineering		
Semester	Sixth	Subject Title	Microwave Engineer	ring	Code	TEC 602
Course C	omponent	Credits		L	Т	Р
Professional Core Course (PCC)		03	Contact Hours	3	0	0
Exami	nation	Theory	Weichtage, Englugtion	CWA	MSE	ESE
Duratio	n (Hrs)	03	weigniage: Evaluation	25	25	50
Pre-requi	site: Comm	unication Systems I,	Communication Systems I Theory.	I, and Ele	ectromagne	etic Field
		Со	urse Outcomes			
Upon com	pletion of tl	nis course, the stude	ents will be able to			
CO 1	Remember characteris	r the basic concep tics and cavity reson	ts of waveguides and us ators.	nderstand	ling of w	aveguides
CO 2	Apply the parameters	basics of the wavegui	de to different microwave	compone	nts based o	n network
<i>CO 3</i>	O 3 Analyse various microwave sources and their characteristics.					
CO 4	Understan microwave	d various paramete components.	rs measurement for evaluation	ating the	performar	nce of the
CO 5	CO 5 Implement Microstrip filters used in RF transmitter and receiver.					
CO 6	Design RF	components, transm	itter, receiver, and RF corr	municati	on links.	
		•				
Unit No.	Unit No. Content Hours					Hours
Unit 1:	Waveguides and Transmission Line:Rectangular and circular waveguide, Excitation of waveguides, Rectangular1cavity resonators, Introduction to microstrip line.					10
Unit 2:Passive Microwave Devices: Network parameter of microwave circuit, Scattering matrix, Microwave T junctions, E plane TEE, H plane TEE, Magic TEE, Hybrid TEE, Hybrid ring, 8 Terminations, Attenuators & phase changers, Isolator & circulators, Directional couplers and power divider.			8			
Unit 3:	Microwave Sources: Klystron, Reflex Klystron, Magnetron (Conventional, linear), TWT, Gunn diode, IMPATT, TRAPATT, Tunnel diode –Operation & characteristics, Basics of GaAs FET.					
Unit 4:	Microwave Measurements: Measurement of frequency, Wavelength, Power, VSWR, Impedance determination, S-Parameter measurements, Spectrum analyzer, Network analyzer.					
Unit 5:	analyzer.Microwave Systems:Types of filter designing, Low-pass prototype filter design, Filter transformations, Filter implementation, Richard transformation, Kuroda identities, Stepped-Impedance low pass filters. Introduction to RFID, MMIC, RFMEMS, and Effect of microwave on human body.				8	
Total Hours 4					40	

	Textbooks
1.	Liao, Samuel, "Microwave Devices & Circuits", PHI, 3rd edition, 2003.

Semester VI

Page | 65



2.	Pozar, D M, " <i>Microwave Engineering</i> ", John Wiley & sons, 4th edition, 2013.						
	Reference Books						
3.	Collins, R E, " <i>Foundations for Microwave Engineering</i> ", John Wiley & sons, 2 nd edition, 2007.						
4.	I J Bhal & P. Bharti, " <i>Microwave Solid state Circuit Design</i> ", John Wiley & sons, 2 nd Edition, 2003.						

Mode of Evaluation	Test / Quiz / Assignment / Mid Term Exam / End Term Exam.
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	Department of Electronics and Communication Engineering						
B. Tech in Electronics and Communication Engineering							
Semester	SemesterSixthSubject TitleVLSI Technology and DesignCode		Code	TEC 603			
Course Component		Credits		L	Т	Р	
Professio Course	onal Core (PCC)	03	Contact Hours	3	0	0	
Exam	ination	Theory	Weightage, Evaluation	CWA	MSE	ESE	
Duratio	on (Hrs)	03	weigniage. Evaluation	25	25	50	
		Pre-requisite: El	ectronic Devices and Circu	uits			
		Со	urse Outcomes				
Upon com	pletion of th	nis course, the stude	ents will be able to				
CO 1	Develop ba	asic understanding of	f VLSI fabrication Technol	logy.			
<i>CO</i> 2	Illustrate	different kind of diff	usion and deposition techn	iques in V	VLSI.		
CO 3	Discuss V	LSI design concepts	s, MOS structure, and MO	OSFET e	equation in	terms of	
000	current and	l voltage.					
<i>CO</i> 4	Examine t	he properties and cha	aracteristics of MOS struct	ures.			
<i>CO</i> 5	Understan	d various layout and	l stick design of CMOS cir	cuits.			
CO 6	Propose th	e characteristic diffe	rences in MOS structures	and devic	e-based pr	ojects.	
Unit No.	Content						
Unit 1:	VLSI Technology: Clean room technology, Crystal growth and wafer preparation, Electronic grade silicon, CZ crystal growth technique, Silicon shaping. Epitaxy: Vaporphase epitaxy, Doping and auto-doping, Buried layers. Oxidation:						
Unit 2:	Diffusion: Models of diffusion in solids, Fick's law. Ion implantation: Range theory, Ion stopping, Implantation equipment, Annealing. Lithography: Types, Photoresist. Etching: Wet etching, Ion milling, Liftoff. Metallization: Applications, Choices, Deposition.					8	
Unit 3:	Era of VLSI Design: Introduction to VLSI design, Front end and Back end design, Computer aided design technology. MOS Transistor: MOS structure, MOS system under external Bias, Threshold voltage, Structure and operation of MOS transistor, MOSFET device design equation, MOSFET scaling, MOSFET capacitances.					8	
Unit 4:	MOS Inverters: Static characteristics, Resistive – load inverter, Inverters with n-type MOSFET load, CMOS inverter, Switching characteristics of MOS inverters, Delay-time definitions, Switching power dissipation of CMOS inverters.					10	
Unit 5:	Layout Design: Design rules, Stick diagram, Parasitic effects, Layout design prospects, CMOS basic circuits layout design: NAND, NOR, AND, OR, AOI circuits.					8	

Textbooks



1.	S. Kang and Y. Leblebici, "CMOS Digital Integrated Circuits, Analysis and Design", 3rd			
	Edition, Tata McGraw-Hill, 2003.			
2.	S. M. Sze, "VLSI Technology" 2 nd edition, McGraw Hill, 1988.			
3.	James D. Plummer, Michael Deal, Peter D. Griffin, "Silicon VLSI Technology: Fundamentals,			
	<i>Practice, and Modeling</i> ", 1 st edition, Pearson, 2003.			
4.	Sorab K.Ghandi, "VLSI Fabrication Principles Silicon And Gallium Arsenide", 2 nd edition,			
	A Wiley Inderscience Publications, 1994.			
Reference Books				
5.	D. A. Pucknell and K. Eshraghian, "Basic VLSI Design", 3rd Edition, Prentice-Hall of India,			
	1994.			
6.	Stephen A. Campbell, "The Science and Engineering of Microelectronic Fabrication", 2 nd			
	Edition, Oxford University Press, 2008.			

 Mode of Evaluation
 Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



Department of Electronics and Communication Engineering							
B. Tech in Electronics and Communication Engineering							
Semester	Sixth	Subject Title	Career Skills Co		Code	XCS 601	
Course C	omponent	Credits		L	Т	Р	
Humanities and Social Sciences including Management course (HSMC)		02	Contact Hours	2	0	0	
Exam	ination	Theory	Weightage Fyaluation	CWA	MSE	ESE	
Duratio	on (Hrs)	03	weigniage. Evaluation	25	25	50	
		Pre-requisit	e: Communication Skills				
		Со	urse Outcomes				
Upon com	pletion of th	nis course, the stude	ents will be able to				
CO 1	Have a log differentia	gical approach to th te between the stron	e problems and at the sar g and the week arguments	ne time t and valid	they will b lity of the s	be able to statement.	
CO 2	Improve th	Improve the reasoning ability of the students by using the different methods.					
<i>CO</i> 3	Learn different approaches related to the coding or other complex types of pr which are related to the sequence detection etc.					problems	
<i>CO</i> 4	Get a basic	Get a basic knowledge of the data interpretation.					
CO 5	Acquire knowledge of puzzles and different methods to solve the puzzles in way is also included.				an easier		
CO 6	Develop th	e basic skills of apti	tude and logical reasoning.				
	-						
Unit No.	Content					Hours	
Unit 1:Building Advanced Vocabulary: Sentence completion: Single and double vocabulary Job Application: Personal interviews and C.V Writing essential parts - Cover letter and the 'resume'. Types of 'resumes' (Curriculum Vitae) Chronological 'resume', functional 'resume'.					5		
Unit 2:	Aptitude Section: Number system, P& C, Probability, Log,				8		
Unit 3:	<i>nit 3:</i> Aptitude Section: Time & work, S.I & C.I, Time & distance, Mixture, Chain rule, Pipes & cisterns				6		
Unit A.	Advanced Grammar:			5			
0 <i>nu</i> 4.	Spotting er	rors, Subject verb ag	greement-based errors.			5	
Total Hours						24	

	Textbooks				
1.	R.K. Bansal and J.B. Harrison, "Spoken English for India", Orient Longman.				
2.	Thomson and Martinet, "A practical English Grammar", Oxford University Press.				
3.	Malti Aggarwal, "Professional Communication".				
4.	M. A. Pink and A. E. Thomas, "English grammar, composition and correspondence", S.				
	Chand and Sons.				
5.	"A Dictionary of Modern Usage", Oxford University Press.				



Reference Books

6. R.S Agarwal, "*Quantitative aptitude*".

7. R.S Agarwal, "Verbal and Non-Verbal Reasoning".

8. Shakuntala Devi "*puzzles*".

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



Department of Electronics and Communication Engineering						
B. Tech in Electronics and Communication Engineering						
Semester Sixth		Subject Title	CAD of Electronics using CADENCE Tool Lab		Code	PEC 601
Course Component		Credits		L	Т	Р
Professio Course	onal Core (PCC)	01	Contact Hours	0	0	2
Exami	nation	Practical	Weichtagen Englugtion	CWA	MSE	ESE
Duratio	on (Hrs)	02	weignlage: Evaluation	25	25	50
		Pre-requisite: Digital Electronics lab				
		Со	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
CO 1	Understan like MOSF	d the concepts assoc ETs, CMOS, logic g	iated with different analog a states etc.	and digita	al electroni	cs devices
CO 2	Apply the inverter, ad	basics of these devi- lder, subtractor etc.	ces to analyse various elec	etronic ci	rcuits like	amplifier,
<i>CO 3</i>	Analyse (both DC and transient) different circuits using simulation tools.					
<i>CO 4</i>	Design various analog and digital electronics circuit.					
Exp. No.	Name of th	ne Experiment				
PART - A	(using Cade	ence Tool)				
1.	Design and simulation of various gates.					
2.	Design and	l simulation of XOR	gate using NAND gate on	ly.		
3.	Design and	l simulation of comp	arator.			
4.	Design and	l simulation of full a	dder and full subtractor.			
5.	Design and	l simulation of multi	plexer and demultiplexer.			
6.	Design and	l analysis (DC and T	ransient) of CMOS inverte	r using 0	.18 µm tec	hnology.
7.	Design, sin	nulation and analysis	of common source amplif	ier using	$0.18\mu\mathrm{m}\mathrm{te}$	chnology.
8.	Design, sin	nulation and analysis	s of common drain amplifie	er using ($1.18 \mu m$ tec	chnology.
9.	Design and comparison of DC and transient output characteristics of CMOS inverter at different aspect ratio.					
10.	Layout design of CMOS inverter using 0.18 µm technology					
PART – B (using Xilinx Tool)						
11.	Design, simulation and synthesis of various logic gates using Verilog HDL.					
12.	Design, simulation and synthesis of full adder and full subtractor using Verilog HDL.					
<i>13.</i> Design, simulation and synthesis of multiplexer and de-multiplexer.						
Innovative Experiment:						
<i>14</i> .	Design, simulation and synthesis of Flip-Flops.					
15.	Design and simulation of MOS differential amplifier using Cadence tool.					
<i>16</i> .	Design and simulation of current mirror circuit using Cadence tool.					

 Mode of Evaluation
 Test / Quiz / Assignment / Mid Term Exam / End Term Exam



Department of Electronics and Communication Engineering						
B. Tech in Electronics and Communication Engineering						
Semester	Sixth	h Subject Title Microwave and Antenna Lab		na Lab	Code	PEC 602
Course Component		Credits	Contact Hours	L	Т	Р
Professional Core Course (PCC)		01		0	0	2
Exam	ination	Practical	Weightage: Evaluation	CWA	MSE	ESE
Duratio	on (Hrs)	02		25	25	50
	Pre-requisit	uisite: Electromagnetic Field Theory, Antenna and Wave Propagation				
		Со	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
CO 1	Understan	d microwave bench	and related component.			
CO 2	Apply the parameters	fundamentals to m for various microwa	easure the parameters of ave devices.	microwa	ives and a	nalyse S-
<i>CO 3</i>	Evaluate and measure the necessary antenna performance parameters.					
<i>CO</i> 4	Develop basic skills to learn some CAD tool and apply in the design of various antennas.					
Exp. No.	Name of the Experiment					
1.	To measure the guide wavelength and frequency of the signal in a rectangular waveguide, working on TE_{10} mode.					
2.	To draw the mode characteristic of reflex klystron.					
3.	To measure the characteristics of given E plane, H plane and Magic TEE.					
4.	To measure	e the characteristics	of given circulator and dire	ectional co	oupler.	
5.	Analyze the change is frequency and output power with the change in bias voltage of Gunn diode.					
6.	To verify the	he characteristic of le	ow pass filter using power	sensor.		
7.	To draw the polar pattern and measure the gain of waveguide Horn antenna.					
8.	To study the characteristics of a patch antenna.					
9.	To design and simulate a rectangular shape microstrip patch antenna with the given input parameters.					
10.	To design and simulate a triangular shape microstrip patch antenna with the given input parameters.					
11.	To design and simulate a circular shape microstrip patch antenna with the given input parameters.					
12.	To implement optimization for the design of a patch antenna.					
Innovative	Experiment	ts				
13.	<i>13.</i> Measure the characteristic of power divider and power combiner (S-Band and C-Band).					C-Band).
<i>14</i> .	To design a	and simulate a low p	ass filter with the given inp	out param	eters.	

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam


Department of Electronics and Communication Engineering						
	B. Tech in Electronics and Communication Engineering					
Semester	Seventh	Subject Title	Principles of Manage	Principles of Management Code		TEC 701
Course C	omponent	Credits		L	Т	Р
Humanities and Social Sciences including Management course		03	Contact Hours	3	0	0
Exam	nation	Theory		CWA	MSE	ESE
Duratio	n (Hrs)	03	Weightage: Evaluation	25	25	50
		Pre-requisite: K	nowledge of Ethical Scien	ce		
		Co	urse Outcomes			
Upon com	pletion of th	is course, the stude	nts will be able to			
CO 1	Understand	definition and key	words related to principle of	of manage	ement.	
CO 2	Analyse the	e elements and steps	of planning.			
CO 3	Investigate	the structure, design	n, and principle of organisi	ng.		
<i>CO</i> 4	Interpret p	rinciples and elemer	nts of directing.			
<i>CO</i> 5	Understand	the process and fur	nctions of controlling			
CO 6	Apply pract	ical concepts of scie	entific management in their	r respectiv	ve work do	omain.
		^		^		
Unit No.	Content Hours					
Unit 1:	Overview of Management: Definition - Management - Role of managers - Evolution of management thought - Organization and the environmental factors – Trends and challenges of Management in global scenario.					10
Unit 2:	Function of Planning:Nature and purpose of planning - Planning process - Types of plans - Objectives Managing by objective (MBO) strategies - Types of strategies - Policies - Decision making - Types of decision - Decision making process - Rational decision-making process - Decision making under different conditions.8				8	
Unit 3:	Function of Organizing: Nature and purpose of organizing - Organization structure - Formal and informal groups organization - Line and Staff authority - Departmentation - Span of control - Centralization and decentralization - Delegation of authority 88- Staffing - Human resource development, Selection and recruitment - Orientation - Career development - Career stages - TrainingPerformance appraisal.8					
Unit 4:	Function of Directing: Creativity and Innovation - Motivation and satisfaction - Motivation theories - Leadership styles - Leadership theories - Communication - Barriers to effective communication - Organization culture - Elements and types of culture - Managing cultural diversity.8					
Unit 5:	Function of Controlling: Process of controlling - Types of control - Budgetary and non-budgetary control techniques - Managing productivity - Cost control - Purchase control - Maintenance control - Quality control - Planning operations.8					

Semester VII



Total Hours

42

	Textbooks				
1.	L. M. Prasad, "Priciples and Practice of Management", S. Chand & Sons, 3 rd edition, 2008.				
2.	P. C. Tripathi and P. N. Reddy, "Principles of Management", Tata Mcgraw Hill, 4th edition,				
	2008.				
	Reference Books				
3.	Heinz Weihrich, Mark V. Cannice and Harold Koontz, "Management: A Global Perspective",				
	Tata Mcgraw Hill, 12/e, 2009.				

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Depa	rtment of Electronic	cs and Communication Er	ngineerin	g	
	B. Tech in Electronics and Communication Engineering					
Semester	Seventh	Subject Title	Subject TitleDisaster ManagementCode		TEC 731	
Course C	omponent	Credits		L	Т	Р
Engineeri Course	ng Science (ESC)	02	Contact Hours	2	0	0
Exam	ination	Theory		CWA	MSE	ESE
Duratio	on (Hrs)	03	Weightage: Evaluation	25	25	50
	Pre	-requisite: Basic kn	owledge of History and Ge	ography		
		Cor	urse Outcomes			
Upon com	pletion of th	is course, the stude	nts will be able to			
CO 1	Describe th	e concepts of disaste	ers and its types.			
<i>CO</i> 2	Explain the	relationship betwee	n disasters and developme	nt.		
CO 3	Apply the a	pproaches of Disast	er Risk Reduction (DRR)	and the r	elationshij	between
005	vulnerability	y, disasters, disaster	prevention and risk reduct	ion.		
CO 4	Discuss disa disaster ever	asters around the worns.	rld and the unequal social of	conseque	nces stemr	ning from
<i>CO</i> 5	Build skills	to respond to disaste	ers.			
CO 6	Understand case studies	1 the strengths and w	veaknesses of disaster man	agement	approache	es through
Unit No.	Content					Hours
Unit 1:	Introduction, Definitions and Classification: Concepts and Definitions: Disaster, Hazard, Vulnerability, Resilience, Risks Natural disasters: Cloud bursts, Earthquakes, Tsunami, snow, Avalanches, landslides, Forest fires, Diversion of river routes (ex. Kosi river), Floods, Drought, Cyclones, Volcanic hazards/ disasters (Mud volcanoes): Causes and distribution, Hazardous effects and environmental impacts of natural disasters, Mitigation measures, Natural disaster prone areas in India, Major natural disasters in India with special reference to Uttarakhand. Man-Induced Disasters: Water logging, Subsidence, Ground water depletion, Soil Erosion, Release of toxic gases and hazardous chemicals into environment. Nuclear explosions				10	
Unit 2:	Inter-Relationship between Disasters and Development:Factors affecting vulnerabilities, Differential impacts, Impacts of development projects such as dams, Embankments, Changes in land use etc., Climate change adaption, Relevance of indigenous knowledge, Appropriate technology and local resources, Sustainable development and its role in disaster mitigation, Roles and responsibilities of — community, Panchayat raj institutions/urban local bodies, State, Centre and other stake holders in disaster mitigation.6				6	
Unit 3:	Disaster Management (Pre-disaster stage, Emergency stage and Post disaster stage): Pre-disaster stage (preparedness): Preparing hazard zonation maps, Predictability/forecasting and warning, Preparing disaster preparedness plans, Land use zoning, Preparedness through information, Education and communication (IEC), Disaster resistant house construction, Population reduction in vulnerable areas, Awareness.			8		

Semester VII



Unit 1: Case studies: Natural and Man-Made Disasters in India: A. Natural Disasters in India with Special Reference to Uttarakhand: (4 lectures) 1. Earthquakes: Uttarkashi (1991), Kutch (2001), Sikkim (2011) 2. Cloud Bursts: Uttarkashi (2012) 3. Landslides along Himalayan and other regions: Malpa (Pithoragarh) (1998), Varunavrat hill landslide at Uttarkashi (2003) 4. Floods: Orissa floods (2011) 5. Tsunami: Indian Ocean earthquake and Tsunami (2004) 6. Cyclones: Thane (2011) 7. Droughts: Karnataka (2011) 8. Snow avalanche B. Man-Induced Disasters in India: 1. Forest fires: Forest fires in Uttarakhand, 2004, 2012 and deforestation 2. Industrial disasters: Bhopal gas tragedy, 1984 3. Mining: Chasnala (Bihar) mining disaster, 1975 4. Oil spills: Mumbai oil spill, 2010. 5. Nuclear disaster accidents: Narora atomic power station, Blandshahar (1993); Kalpakkam atomic power station (2002); Kota atomic power station, Rajasthan (1995) C. Disasters Relevant to the Area Specific to the Discipline of the Students. Mock shows: Mock shows will be organized and conducted by expert agencies for understanding the vulnerability of areas in and around campus along with redevite the remetinementin	Unit 4:	 Emergency stage: Rescue training for search & operation at national & regional level, Immediate relief, Assessment surveys Post Disaster stage-Rehabilitation and reconstruction of disaster affected areas; Urban disaster mitigation: Political and administrative aspects, Social aspects, Economic aspects, Environmental aspects. Disaster Management Laws and Policies in India: Environmental legislations related to disaster management in India: Disaster management Act, 2005; Environmental policies & programmes in India-Institutions & national centres for natural disaster mitigation: National Disaster Management Authority (NDMA): Structure and functional responsibilities, National Institute of Disaster Management (NIDM): Role and responsibilities 	6
adopting the preventive measures.	Unit 5:	 Case studies: Natural and Man-Made Disasters in India: A. Natural Disasters in India with Special Reference to Uttarakhand: (4 lectures) 1. Earthquakes: Uttarkashi (1991), Kutch (2001), Sikkim (2011) 2. Cloud Bursts: Uttarkashi (2012) 3. Landslides along Himalayan and other regions: Malpa (Pithoragarh) (1998), Varunavrat hill landslide at Uttarkashi (2003) 4. Floods: Orissa floods (2011) 5. Tsunami: Indian Ocean earthquake and Tsunami (2004) 6. Cyclones: Thane (2011) 7. Droughts: Karnataka (2011) 8. Snow avalanche B. Man-Induced Disasters in India: 1. Forest fires: Forest fires in Uttarakhand, 2004, 2012 and deforestation 2. Industrial disasters: Bhopal gas tragedy, 1984 3. Mining: Chasnala (Bihar) mining disaster, 1975 4. Oil spills: Mumbai oil spill, 2010. 5. Nuclear disaster accidents: Narora atomic power station, Blandshahar (1993); Kalpakkam atomic power station (2002); Kota atomic power station, Rajasthan (1995) C. Disasters Relevant to the Area Specific to the Discipline of the Students. Mock shows: Mock shows will be organized and conducted by expert agencies for understanding the vulnerability of areas in and around campus along with adopting the preventive measures. 	10

	Textbooks and Reference Books				
1.	K.J. Anandha Kumar, Ajinder Walia, Shekher Chaturvedi, "India Disaster Report", 2011,				
	National Institute of Disaster Management, June 2012.				
2.	R.B.Singh (Ed), "Environmental Geography", Heritage Publishers New Delhi, 1990.				
3.	Savinder Singh, "Environmental Geography", Prayag Pustak Bhawan, 1997.				
4.	Kates, B.I & White, G.F, "The Environment as Hazards", oxford, New York, 1978.				
5.	R.B. Singh (Ed), "Disaster Management", Rawat Publication, New Delhi, 2000.				
6.	R.B. Singh, "Space Technology for Disaster Mitigation in India (1NCED)", University of				
	Tokyo, 1994.				

Semester VII



7.	Dr. Satender, "Disaster Management in Hills", Concept Publishing Co., New Delhi, 2000.
8.	H.K. Gupta (Ed), "Disaster Management", Universities Press, India, 2003.
9.	A.S. Arya Action Plan for Earthquake, Disaster, Mitigation in V.K. Sharma (Ed), "Disaster
	Management" IIPA Publication New Delhi, 1994.
10.	R.K. Bhandani, "An overview on Natural & Manmade Disaster & their Reduction", CSIR,
	New Delhi.
11.	M.C. Gupta, "Manuals on Natural Disaster management in India, National Centre for
	Disaster Management", IIPA, New Delhi, 2001.

 Mode of Evaluation
 Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



Department of Electronics and Communication Engineering						
	B. Tech in Electronics and Communication Engineering					
Semester	Fifth	Subject Title	Control Systems Code		TEC 552	
Course C	omponent	Credits		L	Т	Р
Program Course (Elective PEC) (I)	03	Contact Hours	3	0	0
Exami	nation	Theory	Weightage, Englugtion	CWA	MSE	ESE
Duratio	n (Hrs)	03	weigniage: Evaluation	25	25	50
	Pre-requisi	te: Basic Electrical E	Engineering, Network Anal	ysis and S	Synthesis	
		Со	urse Outcomes			
Upon com	pletion of t	his course, the stude	ents will be able to			
CO 1	Remembe mathemati	r basic concepts of cal modeling of phys	f network systems, Lapla ical system.	ace trans	form to u	inderstand
CO 2	Understar	nd the concepts of tim	ne domain analysis of first	and seco	nd order sy	ystems.
CO 3	Apply operation analytical a	en and close loop pe and graphical freque	ble zero concepts for stab	ility of a	a system b	y various
<i>CO</i> 4	Analyse th	e system performance	ce different compensation t	echnique	s.	
<i>CO</i> 5	Evaluate of	controllability and ob	servability by state space a	approach	concepts.	
CO 6	Formulate	e a system model for	a given set of desired spec	ification.		
Unit No.	Content					
Unit 1:	Introduction: Introduction to open loop and closed loop control systems, Feedback characteristics of control systems, Mathematical representation of physical systems, Control hardware and their models: dc and ac servomotors, Electrical and mechanical analogy, Block diagram algebra and signal flow graphs, Mason's gain formula.				8	
Unit 2:	Time Domain Analysis:Standard test signals, Time response of first and second systems,Performance indices. Error analysis: Static and dynamic Error coefficients,Effect of adding poles and zeroes to the system, Response of P, PI, and PIDcontrollers.				8	
Unit 3:	Concept of Stability: Concept of stability, Asymptotic and conditional stability, Routh Hurwitz criterion, Root locus technique (Concept and construction). Frequency Response Analysis: Correlation between time and frequency response, Polar and inverse polar plots, Nyquist stability criterion, Bode plots, M and N circle.				10	
Unit 4:	Design through Compensation Techniques: Realization of lag, lead and lag-lead compensators, Design of closed loop control system using root locus and Bode plot compensation.			8		
Unit 5:	State Variable Analysis: Introduction, State space representation, State modes of linear systems, State equations, Transfer matrices, Diagonalization solution of state equations, Controllability, and observability. Introduction to non-linear systems.				8	
Total Hours 42					42	

Textbooks



Nagrath I. J. & Gopal M., "Control System Engineering", New Age International Publishers,				
5 th Edition, 2007.				
Manke. B. S., "Linear control systems", Khanna Publishers, 11th Edition, 2012.				
Reference Books				
Kuo B. C., "Automatic Control Systems", PHI, 7th Edition, 2010.				
Ogata K., "Modern Control Engineering", PHI, 5th Edition, 2010.				
Nise S. Norman., "Control Systems Engineering" Wiley India Pvt. Ltd., 5th Edition, 2009.				

 Mode of Evaluation
 Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



Department of Electronics and Communication Engineering						
	B. Tech in Electronics and Communication Engineering					
Semester	Fifth	Subject Title	Electromagnetic Interference and Compatibility Code		Code	TEC 553
Course C	omponent	Credits		L	Т	Р
Program Course (Elective (PEC) (I)	03	Contact Hours	3	0	0
Exami	ination	Theory	Weightage, Englugtion	CWA	MSE	ESE
Duratio	on (Hrs)	03	weigniage: Evaluation	25	25	50
		Pre-requisite: E	lectromagnetic Field Theo	ry		
		Со	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
CO 1	Understan	d the concepts of ele	ectromagnetic interference.			
<i>CO</i> 2	Analyse th	e measurement techi	niques of electromagnetic i	nterferen	ce.	
<i>CO 3</i>	Differentia	ate among various E	MC standards.			
<i>CO 4</i>	Examine E	EMI control and filte	ring.			
CO 5	Investigat	e EMC design and in	terconnection.			
CO 6	Design and	l develop different E	MC techniques.			
	-					
Unit No.	Content					
Unit 1:	Basic Concept: Definition of EMI and EMC, Classification of EMI/EMC - CE, RE, CS, RS, Units of parameters, Sources of EMI, EMI coupling modes - CM and DM, ESD phenomena and effects, Transient phenomena and suppression.					8
Unit 2:	 EMI Measurement: Basic principles of RE, CE, RS and CS measurements, EMI measuring instruments- Antennas, LISN, Feed through capacitor, Current probe, EMC Analyzer and detection Technique open area site, Shielded anechoic chamber, TEM cell. 				8	
Unit 3:	EMC Standard and Regularization: National and intentional standardizing organizations, FCC, CISPR, ANSI, DOD, IEC, CENEEC, FCC CE And RE standards, CISPR, CE and RE 8 standards, IEC/EN, CS standards, Frequency assignment - Spectrum conversation.				8	
Unit 4:	EMI Control and Method Fixes:Shielding, Grounding, Bonding, Filtering, EMI gasket, Isolation transformer,8Opto-isolator.					
Unit 5:	EMC Design and Interconnection Technique: Cable routing and connection, Component selection and mounting, PCB Design- Trace routing, Impedance control, Decoupling, Zoning and grounding				8	
Total Hours 40						

	Textbooks				
1.	H. W. Ott, " <i>Electromagnetic Compatibility Engineering</i> ", Wiley, 1 st edition, 2009.				
2.	C. R. Paul, " <i>Introduction to Electromagnetic compatibility</i> " Wiley, 2 nd edition, 2010.				
	Reference Books				



 D. G. Baker, "Electromagnetic Compatibility: Analysis and Case Studies in Transportation", Wiley, 1st edition, 2017.
 D. A. Waster, "Electromagnetic Compatibility: Principles and Applications", Magnel Dellar,

4. D. A. Weston, "*Electromagnetic Compatibility: Principles and Applications*", Marcel Dekker Inc, 1st edition, 1991.

Mode of EvaluationTest / Quiz / Assignment / Mid Term Exam / End Term Exam.



Department of Electronics and Communication Engineering						
	B. Tech in Electronics and Communication Engineering					
Semester	FifthSubject TitleHigh Speed Communication CircuitsCode		Code	TEC 554		
Course Co	omponent	Credits		L	Т	Р
Program Course (Elective PEC) (I)	03	Contact Hours	3	0	0
Exami	nation	Theory		CWA	MSE	ESE
Duratio	n (Hrs)	03	weightage: Evaluation	25	25	50
Pre-requi	site: Electro	onics Devices and Cir	rcuits, Analog Integrated C Systems I	Circuits, a	nd Commu	inication
		Со	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
CO 1	Identify th	e concepts of RF des	sign and different commun	ication tr	ansceiver 1	nodules.
<i>CO</i> 2	Understan	d LNA and mixer in	nplementation.			
<i>CO 3</i>	Discuss po	wer amplifiers and e	fficiency of power amplifi	ers.		
<i>CO</i> 4	Implemen	t circuits for phase lo	ocked loop.			
<i>CO</i> 5	Analyse th	e application of freq	uency synthesizers.			
<i>CO</i> 6	Design var	ious high-speed com	munication systems for wi	ireless ap	plications.	
	~					
Unit No.	Content	• • • • •				Hours
Unit 1:	Internal and external noise, Noise in resistors, Noise sources in a CMOS amplifier, Broadband amplifier design Considerations for noise, Narrowband amplifier Noise requirements, Cascaded amplifiers noise performance.					8
Unit 2:	 LNA Design: LNA topologies, LNA noise factor and noise figure, Narrowband LNA Design for wireless systems, Direct input termination of CS Amplifier, Noise Factor analysis of CS amplifier, Noise factor Analysis of CG amplifier, Inductor degenerated CS amplifier, Derive noise factor for inductor degenerated amplifier. 				10	
Unit 3:	Power Amplifiers: Resistor loaded class A amplifier, Class A RF power amplifier, Class B power amplifier, Push-Pull amplifier, Class C amplifier, Class D power amplifier, Class D Push-Pull power amplifier, Class B vs. D Push-Pull amplifier waveforms.				10	
Unit 4:	VCO and Mixers: Voltage Controlled Oscillators (VCO's), Model for voltage to frequency mapping of VCO, Model for voltage to phase mapping of VCO, frequency domain model of VCO, Recently popular approach – The MOS varactor, Method to increase Q of MOS varactor, Boosted VCO, Very high frequency VCO, Mixer design for wireless systems, Ideal mixer behaviour, Issue of image aliasing.				8	
Unit 5:	Image aliasing.Overview of Phase-Locked Loops and Integer-N Frequency Synthesizers:Phase-locked loop, Method of phase detection, Impact of changes in phase error, Integer-N frequency synthesizer, Integer-N frequency synthesizers in wireless systems, Key limitation of integer-N synthesizers, Fractional-N frequency synthesis, Classical fractional-N synthesizer architecture, Accumulator operation, Phase interpolation technique.			10		



Total Hours

46

	Textbooks			
1.	J. Smith, "Modern Communication Circuits", McGraw – Hill, 2 nd Edition, 1997			
2.	Lee, Thomas H. "The Design of CMOS Radio-Frequency Integrated Circuits", Cambridge,			
	UK: Cambridge University Press, 1997.			
	Reference Books			
3.	T. H. Lee, "The Design of CMOS Radio – Frequency Integrated Circuits" 2 nd Edition,			
	Cambridge 2004.			
4.	J. S. Beasley & G. M. Miller, "Modern Electronic Communication" 9th Edition, Pearson. 2004			
5.	T.L. Floyd, " <i>Electronic Devices</i> ", 7th Edition, Pearson, 2007.			
6.	Razavi, Behzad, "RF Microelectronics", Upper Saddle River, NJ: Prentice Hall, 1997.			

Mode of EvaluationTest / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Department of Electronics and Communication Engineering					
	B Tech in Electronics and Communication Engineering					
			Probability and Stoch	astic		TEC
Semester Fifth		Subject Title	Processes	ustie	Code	555
Course Co	omponent	Credits		L	Т	Р
Program	Elective	03	Contact Hours	3	0	0
Course (PEC) (I)		05		5	0	0
Exami	nation	Theory	Weightage · Evaluation	CWA	MSE	ESE
Duratio	Duration (Hrs) 03 Hospital get 2 valuation 25 25		50			
		Pre-requisite:	Engineering Mathematics			
		Со	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
CO 1	Demonstra	ate an understanding	g of the basic concepts of	f random	variable &	& random
001	processes.					
<i>CO</i> 2	Describe r	andom vectors and the	heir characterization.			
<i>CO 3</i>	Analyse th	e operation of two ra	andom variables.			
CO 4	Analyse the characterized	he stochastic proce ation.	sses with the help of p	robability	y models	and their
CO 5	Evaluate t	he spectral character	istics of random process.			
CO 6	Determine	the PDF and CDF f	or different models.			
Unit No.	Content					
	Introduction to Theory of Probability:					
Unit 1:	Axioms of probability, Review of set theory, Joint & conditional probability,					
	Independer	nt events, Combined	experiments.		•	
	Random V	ariables and Rand	om Vectors:			
	Distributio	ns and densities. Sor	ne useful probability distri	butions (Uniform,	
T 1 0	Gaussian,	Exponential, Gamm	na, Rayleigh, Rician, Bi	nomial,	Poisson),	10
Unit 2:	Conditional distribution & density function, Functions of one RV, Statistical					
	Chebyehof	f inclusions on of	te random variable - Expected	ctations, r	vioments,	
	functions					
	Functions of Two Random Variables:					
	Operation	on two random varia	ables, Correlation, Covaria	nce, Vec	tor space	
II:4 2.	of random variables, Multiple random variables, Operation on multiple					
<i>Unu 5:</i>	random va	ariables, Central lin	nit theorem, Infinite sequ	ences of	random	10
	variables.	Convergence conce	pts. Laws of large numl	pers, Tch	nebycheff	
	inequality	and estimation of un	known parameters.			
	Stochastic	Processes:				
17	Stationarity	y& independence, S	Stationarity in the strict	and wide	e senses,	10
Unit 4:	Ergodicity,	, Widesense stationa	ry processes. Correlation	function	s & their	10
	properties, Gaussian random process, Covariance functions and their properties. Measurement of correlation functions					
	Snectral c	haracteristic of ran	dom process.			
.	Power sne	ectral density & the	eir properties. Relation	between	PSD &	
Unit 5:	autocorrela	tion function, W	iener-Khintchine relation	s, Cros	s power	6
	spectrum d	ensity and its proper	ties.			
		Total	Hours			42



	Textbooks
1.	Peyton Z. Peebles, Probability, random variable, and random signal principle, 4 th Edition,
	McGraw-Hill, 2001.
2.	Athanasios Papoulis, S. Unnikrishna Pillai, "Probability, Random Variables and Stochastic
	Processes", 4th Edition, McGraw-Hill, 2002.
	Reference Books
3.	R.B. Ash &C. Doleans Dade, "Probability and Measure Theory" (2/e), Elsevier, 2005.
4.	E. Wong & B. Hajek, "Stochastic Processes in Engineering systems", Springer, 1985.
5.	R.B. Ash and W.A. Gardner, "Topics in stochastic processes", Academic Press, 1975.

Mode of EvaluationTest / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Depe	artment of Electroni	ics and Communication E	ngineerin	ıg	
	B. Tech in Electronics and Communication Engineering					
Semester	eter Sixth Subject Title Data Communication Networks Code		TEC 651			
Course C	omponent	Credits		L	Т	Р
Program Elective Course (PEC) (II)		03	Contact Hours	3	0	0
Exami	nation	Theory	Weightage, Englugtion	CWA	MSE	ESE
Duratio	n (Hrs)	03	weigniage: Evaluation	25	25	50
Pre-requisite: Communication Systems II						
		Co	urse Outcomes			
Upon com	pletion of th	his course, the stude	ents will be able to		1 0 GT	1 1 1 1 1 1 1 1
CO 1	Remember network m	r data communication odels and different p	on and networks with an or rotocols associated.	overview	of OSI an	d TCP/IP
<i>CO</i> 2	Understan	d data transmission	over physical layer.			
<i>CO 3</i>	Explain va	arious data link layer	design issues and services	•		
CO 4	Classify di access.	ifferent Multiple Ac	cess protocols and IEEE s	tandards	applied fo	r medium
CO 5	Analyse N	etwork Layer design	issues and evaluate transp	ort layer	services.	
CO 6	Learn and	integrate the function	ons of presentation, session	n and app	lication lay	yer.
Unit No.	Content					Hours
Unit 1:	Goals and Applications of Networks, LAN, MAN, WAN, Wireless network, Protocols and standards. Reference model: OSI, TCP/IP. Basics of physical layer, Digital transmission, Circuit and packet switching.					6
Unit 2:	Data Link Layer: Data link layer design issues, Services provided to network layers, Framing, Error control, Flow control, Error detection and correction, Elementary data link protocols, an unrestricted simplex protocol, A simplex stop-and-wait 8 protocol, Simplex protocol for a noisy channel, Sliding window protocols, A protocol using go-back-N, A protocol using selective repeat, Example data link protocol-HDLC and PPP.					
Unit 3:	Medium Access Sub layer: Channel allocations, Static and dynamic allocation in LAN, Multiple access protocols, ALOHA, Carrier sense multiple access protocols, Collision free 8 protocols, Limited contention protocols, Ethernet, IEEE standard and protocols.					
Unit 4:	Network and Transport Layer: Network layer design issues, Concept of virtual circuit and datagram subnet, Routing algorithms, Internetworking, IP protocol and addressing. Transport services, Design issues, Elements of transport protocols, Simple transport protocols, Connection management, UDP, TCP, Congestion1212					
Unit 5:	control and quality of service.Presentation and Application Layer & Security: Presentation Layer: Design issues, Data compression techniques, Cryptography. Application layer: Domain name system (DNS), File transfer (FTP), Access and management, Electronic mail (SMTP), Virtual terminals. Network Security: Security services, Message confidentiality, Integrity and authentication.8				8	



Total Hours

	Textbooks				
1.	Andrew S. Tanenbaum and David J. Wetherall, "Computer Networks", Prentice Hall, 5th				
	edition, 2011.				
2.	Behrouz A. Forouzan, "Data Communications and Networking", McGraw-Hill, 4th edition,				
	2007.				
	Reference Books				
	Reference Books				
3.	<i>Reference Books</i> James F. Kurose, Keith W. Ross, " <i>Computer Networking: A Top-Down Approach</i> ", Pearson,				
3.	Reference Books James F. Kurose, Keith W. Ross, "Computer Networking: A Top-Down Approach", Pearson, 6 th edition, 2013.				
3. 4.	Reference Books James F. Kurose, Keith W. Ross, "Computer Networking: A Top-Down Approach", Pearson, 6 th edition, 2013. William Stallings, "Data and Computer Communication", Pearson Education, 8 th edition,				

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



Department of Electronics and Communication Engineering						
	B. Tech in Electronics and Communication Engineering					
Semester	er Sixth Subject Title Digital VLSI Circuit Design Code		TEC 652			
Course Co	ourse Components Credits		L	Т	Р	
Program Course (Elective PEC) (II)	03	Contact Hours	3	0	0
Exami	ination	Theory	Waiahtaan Engluation	CWA	MSE	ESE
Duratio	on (Hrs)	03	weignlage: Evaluation	25	25	50
	Pre-req	uisite: Basic Electro	nics Engineering and Digi	tal Electro	onics	
		Co	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
CO 1	Describe the	he basic MOS structu	are and layout design.			
CO 2	Understan	d the static and dyna	mic characteristics of MO	S inverte	rs.	
<i>CO 3</i>	Apply the	MOS concepts to des	sign combinational and sec	quential N	IOS logic	circuits.
<i>CO 4</i>	Analyse di	fferent digital MOS	logic circuits.			
<i>CO</i> 5	Estimate p	ower consumption o	f CMOS logic circuits.			
CO 6	Integrate of MOS ba	various concepts of c sed digital circuits.	ligital VLSI circuit design	and appl	y them in	designing
Unit No.	Content					Hours
Unit 1:	 Review of MOS Technology: MOS structure, MOS under external bias, MOSFET, Scaling of MOS circuits, Small geometry effects, MOSFET capacitances. MOS circuit design processes: MOS layers, Design rule: Stick diagram and layout. 					10
Unit 2:	Unit 2:MOS Inverters: Static characteristics: Introduction, Resistive-load inverter, Inverters with N- Type MOSFET load, CMOS inverter. Switching characteristics and interconnect effects: Introduction, Delay –time, Inverter design with delay constraints, Estimation of interconnect parasitic, Calculation of interconnect delay, Switching power dissipation of CMOS inverters.10					10
	MOS Logic Circuits:Combinational MOS logic circuits: MOS logic circuit with depletion NMOSloads, CMOS logic circuits, Complex logic circuits, CMOS transmission10gates. Sequential MOS logic circuits: Behaviour of bistable elements, SRlatch, Clocked latch and Flip-flop, CMOS D latch and Flip-flop.					
Unit 3:	loads, CM gates. Sequ latch, Cloc	onal MOS logic circu OS logic circuits, C uential MOS logic c ked latch and Flip-flo	its: MOS logic circuit with complex logic circuits, CN ircuits: Behaviour of bista op, CMOS D latch and Flip	n depletio MOS tran able elem p-flop.	n NMOS smission ents, SR	10
Unit 3: Unit 4:	loads, CM gates. Sequ latch, Cloc Dynamic I Basic prin Synchrono performance	onal MOS logic circu OS logic circuits, C uential MOS logic c ked latch and Flip-fle Logic Circuits: nciples of pass tr us dynamic circuit ce dynamic CMOS circuit	its: MOS logic circuit with omplex logic circuits, CM ircuits: Behaviour of bista op, CMOS D latch and Flip ransistor circuits, Voltag techniques, Dynamic CM ircuits.	n depletio MOS tran able elem p-flop. ge boots IOS circu	n NMOS smission ents, SR trapping, iit, High	10 6
Unit 3: Unit 4: Unit 5:	loads, CM gates. Sequ latch, Cloc Dynamic I Basic prin Synchrono performanc Low Powe Overview of Estimation capacitance	onal MOS logic circu OS logic circuits, C uential MOS logic c ked latch and Flip-fle Logic Circuits: nciples of pass tr us dynamic circuit ce dynamic CMOS circuit r CMOS Logic Circuit of power consumption and optimization of e, Adiabatic logic circ	aits: MOS logic circuit with complex logic circuits, CN ircuits: Behaviour of bista op, CMOS D latch and Flip cansistor circuits, Voltag techniques, Dynamic CN ircuits. cuits: n, Low power design throug f switching activity, Reducuits.	n depletio MOS tran able elem p-flop. ge boots IOS circu gh voltag action of	n NMOS smission ents, SR trapping, ait, High e scaling, switched	10 6 6

 S. Kang and Y. Leblebici, "CMOS Digital Integrated Circuits, Analysis and Design" McGraw-Hill, 3rd Edition, 2003. 	, Tata



2.	J. M. Rabaey, A. Chandrakasan and B. Nikolic, " <i>Digital Integrated Circuits: A Design Perspective</i> ", Prentice-Hall of India, 2 nd Edition, 2006.
	Reference Books
3.	D. A. Pucknell and K. Eshraghian, " <i>Basic VLSI Design</i> ", Prentice-Hall of India, 3 rd Edition, 1994.
4.	K. Eshraghian, D. A. Pucknell and S. Eshraghian, " <i>Essentials of VLSI Circuit and System</i> ", Prentice-Hall of India, 2 nd edition, 2005.
5.	N. H. E. Weste et. al., "CMOS VLSI Design", Pearson, 3rd edition, 2005.
6.	R. Jacob Baker, " <i>CMOS: circuit design, layout, and simulation</i> ", John Wiley & Sons, 3 rd edition, 2010.

Mode of EvaluationTest / Quiz / Assignment / Mid Term Exam / End Term Exam.



Department of Electronics and Communication Engineering						
B. Tech in Electronics and Communication Engineering						
Semester	ester Sixth Subject Title Semiconductor Materials and Devices Code		Code	TEC 653		
Course Component		Credits		L	Т	Р
Program Course (n Elective (PEC) (II)	03	Contact Hours	3	0	0
Exam	ination	Theory		CWA	MSE	ESE
Durati	on (Hrs)	03	weightage: Evaluation	25	25	50
	Pre-requisite	: Basic Electronics I	Engineering, Electronic De	evices and	l Circuits	
		Сог	urse Outcomes			
Upon com	pletion of th	is course, the stude	nts will be able to			
CO 1	Create basi	c understanding of s	emiconductor device phys	ics.		
<i>CO</i> 2	Evaluate th	e two terminal MOS	structure in terms of its el	ectrical p	arameters	
<i>CO 3</i>	Analyse the	three terminal MOS	S structure in terms of elec	trical pote	ential and	charge.
<i>CO 4</i>	Apply surfa	ce potential and cha	rges in different regions of	MOSFE	T operatio	on.
<i>CO</i> 5	Understand the short channel and narrow channel effects.					
CO 6	6 Implement the concepts of semiconductor device physics in developing real life applications.					real life
Unit No.	Content					Hours
Unit 1:	Basics of Semiconductors:Semiconductor materials, Energy levels, Intrinsic and extrinsicsemiconductor, Equilibrium in absence/presence of electric field.					
Unit 2:	 PN Junction Diode: Junction diode: p-n junction, Tunnel diode, Quasi-Fermi levels, Depletion width capacitance and its application in doping profile determination, I-V characteristics of narrow and wide base diodes and their equivalent circuits, Breakdown mechanisms, Small signal ac impedance. 					8
Unit 3:	Two Terminal MOS Structure: Flat band voltage, Potential balance and charge balance, Effect of gate body voltage on surface condition, Accumulation, Depletion, Inversion, General analysis, Small signal capacitance.				10	
Unit 4:	Three Terminal MOS Structure:Contacting the inversion layer, Body effect, Different regions of operation,Pinch-off voltage.					
Unit 5:	Four Terminal MOS Structure: Transistors regions of operation, Complete all-region model, Simplified all- region model, Models based on quasi fermi potential, Regions of inversion in terms of terminal voltage, Temperature effects, Breakdown, Enhancement mode, Depletion mode transistors.			6		

	Textbooks
5.	Tsividis, Yannis, and Colin McAndrew, "Operation and Modelling of the MOS Transistor",
	Oxford: Oxford university press, Vol. 2, 2003.
6.	S. Kang and Y. Leblebici, "CMOS Digital Integrated Circuits, Analysis and Design", 3rd
	Edition, Tata McGraw-Hill, 2003.



	Reference Books
7.	Robert L. Boylestad and Louis Nashelsky, "Electronic Devices and Circuit Theory", 9th
	Edition, Prentice Hall of India (PHI), 2006.
8.	Ben g. Streetman and Sanjay Kumar Banerjee, "Solid State Electronic Devices", 6th Edition,
	Prentice Hall of India (PHI), 2013.
9.	Takayasu Sakurai, Akira Matsuwawa and Takakuni Douseki, "Fully-Depleted SOI CMOS
	Circuits and Technology for Ultralow power applications", Springer, 2006.

Mode of EvaluationTest / Quiz / Assignment / Mid Term Exam / End Term Exam.



Department of Electronics and Communication Engineering						
B. Tech in Electronics and Communication Engineering						
Semester	r Sixth Subject Title Digital Video Processing Code		TEC 654			
Course C	Course Component Credits L T		Т	Р		
Program Elective Course (PEC) (II)		03	Contact Hours	3	0	0
Exam	ination	Theory	Weightage, Evaluation	CWA	MSE	ESE
Duratio	on (Hrs)	03	weigniage: Evaluation	25	25	50
		Pre-requisite:	Digital Signal Processing			
		Сог	ırse Outcomes			
Upon com	pletion of th	is course, the stude	nts will be able to			
CO 1	Recall the c	oncept of colour vid	eo system.			
CO 2	Understand	I motion estimation	technique and various bloc	k matchi	ng algorith	ım.
<i>CO 3</i>	Analyse var	rious video coding so	chemes.			
<i>CO</i> 4	Apply conte	ent dependent video	coding.			
<i>CO</i> 5	Assess the o	bject-based video co	oding.			
CO 6	CO 6 Understand video compression standards.					
Unit No.	Content					Hours
Unit 1:	<i>Unit 1:</i> Introduction to Video Processing: Principles of color video system, Video display, Composite versus component video, Progressive and interlaced scan, Sampling of video signals, DVI technology.					8
Unit 2:Motion Estimation Techniques: General methodologies, Pixel based motion estimation, Block matching algorithm, Deformable block matching algorithm, Mesh based motion estimation, Global motion estimation, Region based motion estimation, Multi-resolution motion estimation, and feature based motion estimation.				8		
Unit 3:	Basic of Video Coding: Categorization of video coding schemes, Information theory for source coding, Binary encoding, Scalar quantization, Vector quantization, Wave form-based coding, Block-based transform coding, Predictive coding, Temporal prediction and transform coding.				8	
Unit 4:	Content dependent Video Coding: Two-dimensional shape coding, Texture coding for arbitrarily shaped region, 8 Joint shape and texture coding, Region based video coding.					
Unit 5:	Unit 5: Object based Video Coding: Knowledge based video coding, Semantic video coding, Layered coding system Video Compression Standard: Standards, H 261 family of standards			8		
		Total	Hours			40

	Textbooks
1.	Y. Wang, J. Ostermann, and Y.Q.Zhang, "Video Processing and Communications", Prentice Hall, 1 st Edition, 2001.
2.	Ed. Al Bovik, "Handbook of Image and Video Processing", Academic Press, 2 nd Edition, 2000.
	Reference Books



3. A. M. Tekalp, "Digital video Processing", Prentice Hall, 2nd Edition, 2001.

Mode of EvaluationTest / Quiz / Assignment / Mid Term Exam / End Term Exam.



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Department of Electronics and Communication Engineering						
	<i>B</i> . 1	Tech in Electronics	and Communication Eng	ineering		
Semester	GemesterSeventhSubject TitleOptical Fiber CommunicationsCode		Code	TEC 751		
Course C	Component	Credits		L	Т	Р
Program Course (n Elective PEC) (III)	03	Contact Hours	3	0	0
Exam	ination	Theory		CWA	MSE	ESE
Durati	on (Hrs)	03	Weightage: Evaluation	25	25	50
Pre-requis	<i>ite:</i> Commun	ication Systems I, C	communication Systems II,	and Mic	rowave Er	igineering
		Cot	urse Outcomes			
Upon com	pletion of th	is course, the stude	nts will be able to			
CO 1	Remember waveguides	the concepts of li and propagation me	ight and understanding c	of differe	nt types	of optical
<i>CO</i> 2	Understand	d attenuation, losses,	, and polarization for differ	ent types	of optical	fiber.
<i>CO 3</i>	Apply the c	concepts of optics to	analyze different optical tr	ansmitter	sources.	
<i>CO 4</i>	Analyse the	e genesis of optical d	etectors with noise conside	erations.		
CO 5	Evaluate th and optical	e optical fiber syster networking.	ns in terms of modulation,	demodu	lation, mu	ltiplexing,
CO 6	Apply the c	oncepts of optical co	ommunication to design op	tical netv	vorks.	
Unit No.	Content					Hours
Unit 1:	 Introduction: The general system, Advantages of optical fiber communication. Optical Fiber Waveguides: Ray theory transmission; Total internal reflection, Acceptance angle, Numerical aperture, Skew rays. Mode theory for optical propagation; Modes in planar guide, Phase and group velocity. Cylindrical fiber; Modes, Step indexed fiber, Graded index fiber. Single mode fibers; Cutoff wavelength, Mode-field diameter and spot size, Effective refractive index, Group delay and mode delay factor 					
Unit 2:	Attenuation in Optical Fibers: 8 Material absorption losses; Intrinsic and extrinsic absorption. Linear and non- linear scattering losses. Fibers bend loss. Dispersion; Intramodal and intermodal dispersion, Modal noise. Polarization; Modal birefringence, Polarization maintaining fibers.					
Unit 3:	Optical Sources: 10Basic Concept; Absorption and emission of radiation, Population inversion, Optical feedback and laser oscillation, Threshold condition for laser oscillation. Optical emission from semiconductor; The PN junction, Spontaneous emission, Carrier recombination, Stimulated emission and lasing, Heterojunctions, Semiconductor materials. The Semiconductor injection laser, Injection laser characteristics. LED power and efficiency, The double heterojunction LED, LED structures and characteristics.10			10		
Unit 4:	Optical Det Optical dete Long wavel N Photodic internal gai	tectors: ection principles, Ab ength cutoff, Semico ode and P-I-N Pho n; Avalanche photoo	sorption, Quantum efficien onductor photodiode withor otodiode, Semiconductor diode, Benefits and drawb	ncy, Resp ut interna photodic acks of a	onsivity, l gain; P- ode with valanche	6



	performance considerations. Optical Fiber Systems: Modulation format; Amplitude shift keying, Frequency shift keying, Phase	8
	shift keying, Polarization shift keying. Demodulation schemes; Heterodyne	
	synchronous detection, Heterodyne nonsynchronous Detection, Homodyne	
Unit 5:	Optical Time Division Multiplexing (OTDM), Wavelength Division	
	Multiplexing (WDM).	
	Introduction to Optical Network:	
	Optical network concepts, Network topologies; Bus, Ring, Star and mesh,	
	Local Area Network (LAN), Synchronous Optical Network (SONET),	
	Synchronous Digital Hierarchy (SDH).	
	Total Hours	42

	Textbooks		
1.	John M S Senior, "Optical Fiber Communication", PHI, 3rd Ed, 2009.		
	Reference Books		
2.	Joseph C Palais, "Fiber Optic Communications", 5th Ed., 2005.		
3.	G E Keiser, "Optical Fiber Communication", McGraw-Hill, 5th Ed, 2013.		
4.	Govind P Agrawal, "Fiber-Optic Communication Systems", Wiley, 3rd Ed, 2015.		

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Depa	rtment of Electronic	cs and Communication E	ngineerin	g	
B. Tech in Electronics and Communication Engineering						
Semester	ster Seventh Subject Title ASIC Design and FPGA Code		TEC 752			
Course C	Course Components Credits L T		Т	Р		
Program Course (n Elective PEC) (III)	03	Contact Hours	3	0	0
Examination Theory Weightness Evolution CWA MSE		MSE	ESE			
Durati	on (Hrs)	03	weigniage: Evaluation	25	25	50
		Pre-requisite: V	LSI Technology and Desig	gn		
		Cor	urse Outcomes			
Upon com	pletion of th	is course, the stude	nts will be able to			
CO 1	Describe th	e concepts of ASICs	s, CMOS logic and ASIC l	ibrary des	sign.	
CO 2	Understand implementa	d different optimization.	tion techniques and their	relative in	nteraction	of FPGA
CO 3	Apply the c circuits.	oncepts of ASIC and	d FPGA interconnection in	designin	g various	electronic
CO 4	Analyse CN	AOS based Application	ion Specific Integrated Cir	cuit (ASI	C) system	s design.
CO 5	Evaluate A	SIC family using Xi	linx tool to optimize the de	evice perf	formance.	0
CO 6	Design SOC	C based integrated ci	rcuits for various FPGA a	oplication	s.	
	0	U				
Unit No.	Content					Hours
Unit 1:	Introduction: Introduction to ASICs, CMOS logic and ASIC library design, Types of ASICs, Design flow, CMOS transistors CMOS design rules, Combinational logic cell, Sequential logic cell, Data path logic cell, Transistors as resistors, Transistor parasitic capacitance, Logical effort, Library cell design, Library architecture, Review of VHDL/Verilog: Entities and architectures.				10	
Unit 2:	ASIC and FPGA Families: Programmable asics, Programmable ASIC logic cells and programmable ASIC I/O cells anti fuse, Static RAM, EPROM and EEPROM technology, 8 PREP benchmarks, ACTEL ACT, Xilinx LCA Altera FLEX, Altera MAX DC & AC inputs and outputs, Clock & power inputs, Xilinx I/O blocks.					
Unit 3:	ASIC and FPGA Interconnect: ASIC design software and low-level design entry, ACTEL ACT, Xilinx LCA, Xilinx EPLD, Altera MAX 5000 and 7000, Altera MAX 9000, Altera FLEX, Design systems, Logic synthesis, Half gate ASIC, Schematic entry, Low level design language, PLA tools, EDIF, CFI design representation.			10		
Unit 4:	FPGA Implementation: FPGA partitioning, partitioning methods, Floor planning, Placement, Physical design flow, Global routing, Detailed routing, Special routing, Circuit extraction, DRC.					
Unit 5:	FPGA Applications:Design using Xilinx family, FPGA and advance Silicon on Chip (SOC) classFPGA, SOC design flow, Platform-based and IP based SOC designs, Basicconcepts of bus-based communication architectures.			6		
		Total	Hours			42

Textbooks



1.	M.J.S .Smith, "Application - Specific Integrated Circuits", Addison – Wesley Longman Inc.,		
	1 st Edition, 2002.		
2.	Skahill, Kevin, "VHDL for Programmable Logic", Pearson Education", 1st Edition, 2006.		
	Reference Books		
3.	John F. Wakherly, "Digital Design: Principles and Practices", Prentice Hall, 4th Edition,		
	2008.		

Mode of Evaluation	Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Depa	rtment of Electronic	cs and Communication Er	ngineerin	g	
	<u> </u>	Tech in Electronics	and Communication Eng	ineering	0	
Semester	rSeventhSubject TitleRadar and Navigation AidsCode		TEC 753			
Course C	omponent	Credits		L	Т	Р
Program Course (J	Elective PEC) (III)	03	Contact Hours	3	0	0
Exam	ination	Theory	Weichtagen Englugtion	CWA	MSE	ESE
Duratio	on (Hrs)	03	weigniage: Evaluation	25	25	50
		Pre-requisite:	Microwave Engineering			
		Cor	irse Outcomes			
Upon com	pletion of th	is course, the stude	nts will be able to			
<i>CO</i> 1	Understand	the concept Radar	and its application.			
<i>CO</i> 2	Analyse M	I and Pulsed Doppl	er radar.			
<i>CO 3</i>	Investigate	detection of signal a	ind noise in it.			
<i>CO</i> 4	Understand	the concepts of nav	vigation.			
<i>CO</i> 5	Formulate	Doppler navigation	system and its accuracy.			
<i>CO</i> 6	Design vari	ous radar and naviga	tion-based systems.			
T T 1 (D T	<u> </u>					TT
Unit No.	<i>Content</i>	(D L D !				Hours
Unit 1:	Introduction to Radar Basics: The simple form of the radar Equation, Radar block diagram, Radar frequencies, Applications of radar, Detection of signals in noise, Receiver noise and the signal-to-noise ratio, Probability density functions, 8 Probabilities of detection and false alarm, Integration of radar pulses, Radar cross section of targets, Radar cross section fluctuations, Transmitter power, Pulse repetition frequency, Antenna parameters, System losses.					
Unit 2:	MTI and Pulse Doppler Radar: Introduction to doppler and mti radar, Delay line cancelers, Staggered pulse repetition frequencies, Moving target detector, Limitations to MTI 9 performance, Pulse doppler radar, Doppler filters, Tracking with radar, Monopulse tracking, Conical scan, Sequential lobing, Tracking in range.					
Unit 3:	Radar Transmission and Detection of Signals in Noise:Radar transmitters, Linear beam power tubes, Solid state RF power sources, Magnetron, Crossed field amplifiers. The radar receiver, Receiver noise figure, Super heterodyne receiver, Duplexers and receiver protectors, Matched filter receiver, Detection criteria, Detectors, Automatic detector, Constant false alarm rate receivers, Propagation of waves, atmospheric refraction, Standard propagation, Nonstandard propagation, Radar clutter, land and sea clutter, Detection of target in precipitation, The Radar antenna, Reflector antennas, Electronically steered phased array antennas, Phase shifters, Frequency-scan Arrays.8					
Unit 4:	Introduction Radio direct aural null of Adcock direct direction fir course radio receive ring	In to Navigation: tion finding, The Lo direction finder, Th action finder, Automa ider, Range and acc o range, VHF Omr equipment, Range a	oop antenna, Loop Input/o e goniometer, Errors in atic direction finders, The O uracy of direction finders, ni Directional Range Find and accuracy of VOR.	output circ direction Commutat , The LF/ der (VOF	cuits, An finding, ted aerial MF four R), VOR	8



	Distance Measuring Equipment (DME) and Tactical Air Navigation	
Unit 5:	(TACAN): Operation of DME and TACAN, Instrument landing system, Ground controlled approach system, Microwave Landing System(MLS), Doppler navigation, Beam configurations, Track stabilization, Doppler spectrum, Components of the doppler navigation system, Accuracy of doppler navigation systems, Inertial navigation, Principles of operation, Navigation over the earth, Components of an inertial navigation system, Earth coordinate mechanization, Strapped-down systems, Accuracy of inertial navigation systems, Global Positioning System (GPS).	9
	Total Hours	42

	Textbooks		
1.	M. I. Skolnik, "Introduction to Radar Systems", Tata McGraw-Hill, 3rd edition, 2017.		
2.	N. S. Nagaraja, " <i>Elements of Electronics Navigation</i> ", Tata McGraw-Hill, 2 nd Edition, 2017.		
Reference Books			
3.	P. Z. Peebles, " <i>Radar Principles</i> ", Wile, 1st edition, 2007.		
4.	J.C Toomay, "Principles of Radar", PHI 2 nd edition, 2004.		

Mode of Evaluation	Test / Quiz / Assignment / Mid Term Exam / End Term Exam.
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	Depa	rtment of Electroni	cs and Communication Er	ngineerin	g	
	B . 2	Tech in Electronics	and Communication Eng	ineering		
Semester	Seventh	Subject Title	Organic Electronics Devi Circuits	ices and	Code	TEC 754
Course C	omponents	Credits		L	Т	Р
Program Course (n Elective PEC) (III)	03	Contact Hours	3	0	0
Exam	ination	Theory		CWA	MSE	ESE
Durati	on (Hrs)	03	weightage: Evaluation	25	25	50
1	Pre-requisite:	Basic Electronics E	Engineering, Electronics De	evices and	l Circuits.	
		Con	urse Outcomes			
Upon com	pletion of th	is course, the stude	nts will be able to			
CO 1	Remember devices.	the basics and lin	nitations of conventional	silicon-ba	ased semi	conductor
<i>CO</i> 2	Understand	the basic concepts	and classification of organ	ic materia	als.	
CO 3	Apply the believes of the determined of the second	basic concepts of characteristics.	arge transport in organic m	naterials f	or differen	nt organic
<i>CO 4</i>	Analyse the	different properties	of OLED.			
<i>CO</i> 5	Evaluate th	e performance of or	ganic solar cells.			
<i>CO</i> 6	Design and	develop innovative	organic electronic devices.			
Unit No.	Content					Hours
Unit 1:	Organic Materials and Device Physics: Introduction; Organic materials: Conducting polymers and small molecules, Organic semiconductors: p-type and n-type semiconductors, Source, Drain and Gate electrodes, Gate dielectrics, Substrate. Energy band diagram and concept of charge transport in organic semiconductors; Comparison between organic and inorganic semiconductors including the merits, Demerits and limitations.					
Unit 2:	Organic Thin Film Transistors (OTFTs):Introduction; Operating principle; Output and transfer characteristics; Classification of various organic thin film transistors (OTFT) structures; Performance parameters; Impact of structural parameters on behaviour of OTFT; Concept of contact resistance; Single Gate (SG) and Dual Gate (DG) TFT performance comparison; Merits, Demerits, Limitations and future scope. Applications: - Organic complementary inverter circuits; Organic memory - Organic static random-access memory (OSRAM).10					
Unit 3:	Organic Light Emitting Diodes (OLEDs) Introduction; Organic materials for OLEDs; Classification of OLEDs, Operating principle; Output and transfer characteristics; Analysis of OLED 8 performance: Optical, Electrical and thermal properties, Merits and demerits; Stability issues; OLEDs as display applications.				8	
Unit 4:	Organic Solar Cell: Introduction; Operating principle; Characteristics; Materials for organic solar cells; Classification of organic solar cell- Single layer, Bi-layer and bulk hetero junction organic solar cell; Merits and demerits; Applications and future scope.				7	
Unit 5:	Organic Se Introduction sensors (Pie	nsors: a; Working principle zoresistive, Piezoel	e and organic sensing mate ectric, and Capacitive sen	erials for sor), Ten	pressure	8



sensors, Humidity sensors and pH sensor; comparison between organic and conventional sensors including merits, demerits and limitations; Applications of organic sensors; Basics of ionic polymer–metal composites (IPMC) and its applications.

Total Hours

	Textbooks		
1.	Hagen Klauk, "Organic Electronics: Materials, Manufacturing and Applications", Wiley-		
	VCH Verlag Gmbh & Co. KGaA, Germany, 1st edition, 2006.		
2.	Klaus Mullen, Ullrich Scherf, "Organic Light Emitting Devices: Synthesis, Properties and		
	Applications", Wiley-VCH Verlag Gmbh & Co. KGaA, Germany, 1st edition, 2005.		
3.	Johannes Karl Fink, "Polymeric Sensors and Actuators", John Wiley & Sons, 1st edition, 2012.		
	Reference Books		
4.	Hagen Klauk, "Organic Electronics II: More Materials and Applications", Wiley-VCH		
	VerlagGmbh& Co. KGaA, Weinheim, Germany, 1st edition, 2012		
5.	Flora Li, Arokia Nathan, Yiliang Wu, Beng S. Ong, "Organic Thin Film Transistor		
	Integration: A Hybrid Approach", Wiley-VCH, Germany; 1st edition, 2011.		
6.	Wolfgang Brutting, "Physics of Organic Semiconductors", Wiley-VCH Verlag Gmbh & Co.		
	KGaA, Germany, 2 nd edition, 2005.		
7.	Daniel A. Bernards, Róisín M. Owens, George G. Malliaras, "Organic Semiconductors in		
	Sensor Applications", Springer Science & Business Media, 1st edition, 2008.		

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.

42



Department of Flectronics and Communication Engineering						
B Tech in Electronics and Communication Engineering						
D. Teen in Electronics and Communication Engineering						TEC
Semester	Seventh	Subject Title	Wireless Sensor Netw	vork	Code	755
Course C	Component	Credits		L	Т	P
Program Course (1	n Elective PEC) (IV)	03	Contact Hours	3	0	0
Exam	ination	Theory	Weightages Englishing	CWA	MSE	ESE
Duratie	on (Hrs)	03	weignlage: Evaluation	25	25	50
		Pre-requisite:	Wireless Communication			
		Con	urse Outcomes			
Upon com	pletion of th	is course, the stude	nts will be able to			
CO 1	Understand networks (V	d the basic concep VSN).	ots, constraints, and appl	lications	of wirele	ss sensor
<i>CO</i> 2	Understand	d the enabling techno	ologies for WSN.			
CO 3	Understand WSN.	d and analyse the d	lifferent MAC (Medium A	Access C	ontrol) pro	otocols of
<i>CO 4</i>	Understand	d routing protocols of	of WSN.			
<i>CO</i> 5	Understand	d and analyse the de	sign principles of wireless	sensor ne	etwork.	
CO 6	Develop var	rious real-life applic	ations using wireless sense	or networ	k.	
Unit No.	Content					Hours
	Introductio	on of Wireless Sense	or Networks (WSNs):			7
Unit 1:	Introduction to sensor networks, Unique constraints and challenges,					
	Advantage of sensor networks, Applications of sensor networks					
Unit 2:	<i>Unit 2:</i> WSNs enabling technologies, challenges: Classification of WSNs Mobile Ad-hoc Networks (MANETs) and wireless sensor networks, Enabling technologies for wireless sensor networks. Issue				wireless s. Issues	8
	and challenges in wireless sensor networks					
	Physical and Data Link Layer:					9
	Design constraints and requirements - Physical layer and transceiver design,					
Unit 3:	Link layer fundamentals and requirements – Link management - MAC protocols — S-MAC Low duty cycle and wakeup concepts – Contention					
	based – Schedule based, IEEE 802.15.4 Standard – PHY/MAC slotted -					
	unslotted CSMA/CA- GTS mechanism					
	Routing and Transport Controls Protocol:					8
	Routing challenges and design issues in WSNs, Wireless network routing					
Unit 4:	protocols, Energy efficient unicast routing, Energy efficient broadcast					
	/multicast routing, Geographical routing, Traditional transport control					
	protocols, Design issues of transport control protocols, CODA, ESRT, RMST_PSEO_GRAUDA and Ad hoc Transport Protocols (ATP)					
	KMS1, PSFQ, GRAUDA and Ad noc Transport Protocols (ATP)				10	
	Design principles for WSNs Gateway concepts & need for gateway WSN					
Unit 5:	to internet communication, and internet to WSN communication. Single-					
	node architecture, Hardware components & design constraints, Operating					
	systems and	l execution environn	nents, Introduction to Tiny	OS and n	esC.	
Total Hours 42						42



	Textbooks				
1.	Feng Zhao & Leonidas J. Guibas, "Wireless Sensor Networks- An Information Processing				
	Approach", Elsevier, India, 1 st edition, 2014.				
2.	Mohammad Ilyas, Imad Mahgoub, "Handbook of Sensor Networks: Compact Wireless and				
	Wired Sensing Systems", CRC Press, 1 st edition, 2004.				
3.	Holger Karl and Andreas Wiilig, "Protocols and Architectures for Wireless Sensor				
	<i>Networks</i> ", John Wiley and Sons Limited, New Delhi, India, 1 st edition, 2017.				
	Reference Books				
4.	Kazem Sohraby, Daniel Minoli, & Taieb Znati, "Wireless Sensor Networks-Technology,				
	Protocols, and Applications", John Wiley and Sons Limited, New Delhi, India, 1st edition,				
	2016.				
5.	Jun Zheng and Abbas Jamalipour, "Wireless Sensor Networks- A Networking Perspective",				
	John Wiley and Sons Limited, New Delhi, India, 1 st edition, 2014.				
	John whey and Sons Elinited, New Denn, India, 1 Conton, 2014.				

Mode of EvaluationTest / Quiz / Assignment / Mid Term Exam / End Term Exam.



Department of Electronics and Communication Engineering						
B. Tech in Electronics and Communication Engineering						
Semester	ester Seventh Subject Title Fundamentals of Nanotechnology Code		Code	TEC 756		
Course C	omponent	Credits		L	Т	Р
Program Course (I	Elective PEC) (IV)	03	Contact Hours	3	0	0
Exam	ination	Theory	Weichtage, Engligation	CWA	MSE	ESE
Duratio	on (Hrs)	03	weignlage: Evaluation	25	25	50
	Pre-re	equisite: Basic Physic	ics and Basic Electronics E	Engineerii	ng	
		Cor	urse Outcomes			
Upon com	pletion of th	is course, the stude	nts will be able to			
CO 1	Remember electron dev	the concepts of envices and carbon base	nerging world of nanoscied nanoelectronics devices	ience, kn	owledge	of single-
CO 2	Understand synthesis.	d the various top-	down and bottom-up aj	pproaches	s for nar	omaterial
<i>CO 3</i>	Apply the a	cquired knowledge	to develop novel nanomate	rials.		
CO 4	Analyse the properties of nanomaterials using various scanning probe techniques and spectroscopic techniques for material characterization					
CO 5	Evaluate the performance of nanotechnology related devices for various industrial applications					
CO 6	Apply the knowledge in developing analytical tools for nanoscale engineering.					
<u>#</u>					<u> </u>	
Unit No.	Content					Hours
Unit 1:	Introduction to Nanotechnology: Overview, Historical background, Importance of nanoscale, Bottom-Up approaches, Top-Down approaches, Functional approaches.				8	
	Nano Mate	rials:	nes, i unerionai approaenes			
Unit 2:	Fundamental concepts of nanomaterials, Allotropes of carbon, Graphene, Graphene nanoribbons, Fullerenes, Fullerites, Carbon Nanotubes (CNTs), Bucky paper.					8
Unit 3:	Nano Electronics: Approaches to nanoelectronics, Fabrication of integrated circuits, Introduction to Microelectromechanical Systems (MEMS), 10 Nanoelectromechanical Systems (NEMS), Nanowires, Nano-circuits, Quantum wire, Quantum well.					10
Unit 4:	Nano-Engineering Devices and Nano- Medicine:Lab on chip, Micromachinery, Nanomotor, Nanopore, Nano sensor, Quantum point contact, Synthetic molecular motors, Medical applications of nanomaterials.					
Unit 5:	Analytical Tools in Nanoscale Engineering and Nanolithography:Atomic Force Microscopy (AFM), Scanning Tunnelling Microscope (STM), Nanolithography: Dip-pen, Electron beam, Ion-beam Sculpting, Nanoimprint10Lithograph, Photolithography.					10
Total Hours 4						42

 Textbooks

 1.
 Shunri Oda, David Ferry, "Nanoscale Silicon Devices", CRC Press, Taylor & Francis Group, 1st Edition, 2016



2.	Robert Puers, "Nanoelectronics: Materials, Devices, Applications", Wiley, 2017.					
	Reference Books					
3.	Suprio Datta, "Lessons from nanoelectronics", World Scientific publisher, 1st Edition, 2012.					
4.	Gabriel M. Rebeiz, "RF MEMS: Theory, Design, and Technology", Wiley, 2003.					
5.	Julian W. Gardner, "Microsensors, MEMS and Smart Devices", Wiley, 2002.					

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Department of Electronics and Communication Engineering							
B. Tech in Electronics and Communication Engineering							
Semester Seventh		Subject Title	CMOS Analog Circuit	CMOS Analog Circuit Design Code		TEC 757	
Course Component		Credits		L	Т	Р	
Program Course (n Elective PEC) (IV)	03	Contact Hours	3	0	0	
Exam	ination	Theory	Weichtage, Englugtion	CWA	MSE	ESE	
Durati	on (Hrs)	03	weigniage: Evaluation	25	25	50	
	Pre-requisit	te: Electronics Devic	ces and Circuits, Analog Ir	ntegrated	Circuits		
		Cor	urse Outcomes				
Upon com	pletion of th	is course, the stude	nts will be able to				
CO 1	Recall the k	nowledge of analog	IC design in CMOS techn	ologies.			
<i>CO</i> 2	Understand	MOS transistors w	ith different configurations	8.			
<i>CO 3</i>	Apply mult	istage and differentia	al MOS amplifiers in diffe	rent elect	ronic circu	iits.	
<i>CO</i> 4	Analyse cur	rent mirror circuits.					
<i>CO</i> 5	Assess and	evaluate feedback a	mplifiers and phase locked	l loop.			
CO 6	Design and develop various CMOS analog circuits.						
	P						
Unit No.	Content				Hours		
Unit 1:	Models for Integrated Circuit Active Devices:The depletion region of a P-N junction, Depletion region capacitance andjunction breakdown, Basics of MOS transistor, Derivation of current-voltagerelationship, Analysis of MOS as an amplifier, Small signal models of MOStransistortransistorMOS transistor frequency response					8	
Unit 2:	Singlestage Amplifier: Common source stage with resistive load, CS stage with diode connected load, CS stage with current source load, CS stage with triode load, CS stage with source generation, Source follower and common gate configuration					9	
Unit 3:	Multistage Amplifier and Operational amplifier: Cascode current source, Cascode amplifier, Differential pair, Small and large signal analysis of differential amplifier, Differential amplifier with MOS loads, OPAMP Design: General consideration, One stage Op Amp.9					9	
Unit 4:	Current Mirrors, Active Loads and References: Simple current mirror, Cascode current mirror, Wilson current mirror, Common source amplifier with complementary load, Voltage and current references: Widlar and peaking current sources, Supply insensitive biasing.					9	
Unit 5:	Feedback and Non-Linear Analog Circuits: General consideration, Properties of feedback circuits, Feedback configuration, Nonlinear analog circuits: LC oscillators, Simple phase locked loop.					9	
Total Hours 44							

Textbooks					
1.	B. Razavi, "Design of analog CMOS Integrated Circuits", McGraw-Hill, 1st Edition, 2002.				
2.	Mohammed Ismail and Terri Faiz, "Analog VLSI Signal and Information Process", McGraw-				
	Hill, 1 st Edition, 1994.				
	Reference Books				



3.	Paul R. Gray and R. G. Meyer, "Analysis and Design of Analog Integrated Circuits" John
	Wiley and Sons", 4 th Edition, 2001.
4.	R. Jacob Baker, H. W. Li, and D.E. Boyce, "CMOS: Circuit Design, Layout and Simulation",
	Prentice-Hall of India, 3 rd edition, 2010.

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Department of Electronics and Communication Engineering						
B. Tech in Electronics and Communication Engineering						
Semester	rSeventhSubject TitleSpeech ProcessingCode		Code	TEC 758		
Course C	'omponent	Credits		L	Т	Р
Program Course (Elective PEC) (IV)	03	Contact Hours	3	0	0
Exam	ination	Theory		CWA	MSE	ESE
Duratio	on (Hrs)	03	Weightage: Evaluation	25	25	50
	· · ·	Pre-requisite:	Digital Signal Processing	<u></u>		
		Cor	urse Outcomes			
Upon com	pletion of th	is course, the stude	nts will be able to			
CO 1	Understand	d basic concepts of s	peech production.			
<i>CO</i> 2	Analyse the	predictive coding.				
<i>CO 3</i>	Understand	the homomorphic s	systems.			
<i>CO 4</i>	Analyse spe	eech enhancement te	chniques.			
<i>CO</i> 5	Understand	the analysis of seve	eral statistical model for sp	eech reco	gnition.	
CO 6	Develop rea	al-life applications in	the area of voice commun	nications.		
Unit No.	Content					Hours
Unit 1:	Fundamentals of the Speech Production mechanism and Digital Speech Processing: Anatomy & physiology of speech organs, The process of speech production, Acoustic phonetics, The acoustic theory of speech production, Lossless tube models, Digital models for speech signals. Time domain models for speech processing: Introduction, Window considerations, Short time energy and average magnitude short time average zero crossing rate, Speech Vs. silence discrimination using energy and zero crossing, Pitch period estimation using a parallel processing approach, The short time autocorrelation function, The short time average magnitude difference function, Pitch period estimation using the autocorrelation function				10	
Unit 2:	Linear Predictive Coding (LPC): Basic principles of linear predictive analysis: The autocorrelation method, The covariance method, Solution of LPC equations: Cholesky decomposition solution for covariance method, Durbin's recursive solution for the autocorrelation equations, Pitch detection and using LPC parameters.				8	
Unit 3:	Homomorphic Speech Processing: Introduction, Homomorphic systems for convolution: Properties of the complex cepstrum, Computational considerations, The complex cepstrum of speech, Pitch detection, Formant estimation, Mel frequency cepstrum computation, Mel frequency cepstral co-efficients (MFCC) feature extraction.				8	
Unit 4:	Speech Enhancement:Nature of interfering sounds, Speech enhancement techniques: Spectralsubtraction, Enhancement by re-synthesis, Comb filter, Wiener filter.					6
Unit 5:	<i>statistical Models for Speech Recognition:</i> <i>nit 5:</i> Introduction to speaker recognition and speech recognition. Vecto quantization model and gaussian mixture model for speaker and speech			Vector 1 speech	10	


	recognition. Discrete and continuous hidden Markov modeling for isolated	
	word and continuous speech recognition.	
Total Hou	rs	42

	Textbooks						
1.	Lawrence R. Rabiner, Ronald W. Schafer, "Introduction to Digital Speech Processing" Now						
	Publishers Inc., 1 st Edition, 2007.						
2.	Thomas F. Quatieri, "Discrete-Time Speech Signal Processing: Principles and Practice",						
	Pearson, 1 st Edition, 2008.						
	Reference Books						
3.	Sadaoki Furui, "Digital Speech Processing: Synthesis, and Recognition", CRC Press, 2 nd						
	Edition Revised and Expanded, 2000.						

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Department of Electronics and Communication Engineering								
	B. 2	Tech in Electronics	and Communication Eng	ineering				
Semester	Eighth	Subject Title	Satellite Communicat	tions	Code	TEC 851		
Course C	Component	Credits		L	Т	Р		
Program Course (n Elective (PEC) (V)	03	Contact Hours	3	0	0		
Exam	ination	Theory	Weightage, Evaluation	CWA	MSE	ESE		
Durati	on (Hrs)	03	weigniage: Evaluation	25	25	50		
	Pre-requ	visite: Wireless Com	munication and Microwav	e Engine	ering			
		Cor	urse Outcomes					
Upon com	pletion of th	is course, the stude	nts will be able to					
CO 1	Understand	basic concepts of c	orbital mechanism and laur	ch vehicl	e.			
<i>CO</i> 2	Apply the te	echnologies for satel	lite & earth station archite	cture, and	l application	ons.		
<i>CO 3</i>	Analyse the	satellite link for the	optimum link performanc	e.				
<i>CO</i> 4	Evaluate th	e modulation and co	oding schemes for a given s	satellite c	ommunica	tion link.		
<i>CO</i> 5	Understand	d various satellite sy	stems - worldwide and Ind	ian scena	rio.			
CO 6	Design prot	otype satellite comm	nunication link for given sp	pecification	ons.			
Unit No.	Content					Hours		
Unit 1:	Overview of Satellite Systems, Orbits and Launching Methods: General features, Frequency allocation, Properties of satellite communication systems, LEO, MEO and GEO Orbits, Kepler's laws, Orbital dynamics, Orbital elements, Sub-satellite point, Orbital perturbations, Orbital effects on communication system performance. Launching and positioning of satellite.							
Unit 2:	 Space Segment (Satellite Subsystems) and Earth Station: Attitude and orbit control system; Telemetry, Tracking, Command and monitoring (TTC & M); Communication subsystems, Antenna subsystem, Power system, Equipment reliability and space qualification. Different types of earth stations 							
Unit 3:	Satellite Link Design: Basic transmission theory, General link design equation, System noise temperature, Uplink/Down Link design, C/N ratio, Saturation flux density, Input/Output back off Effect of rain: Attenuation and depolarization							
Unit 4:	Satellite Multiple Access Techniques: Multiplexing and multiple access, Preassigned, Demand assigned multiple access, FDMA- Bandwidth limited and power limited TWT amplifier operation; TDMA- TDMA frame structure, Frame efficiency, Comparison of uplink power requirements for FDMA and TDMA. CDMA- Direct-sequence spread spectrum, M-sequence codes, Spectrum spreading and dispreading							
Unit 5:	Introduction VSAT System IRIDIUM, IRNSS (Nat	on of Various Satell tems, DBS, DTH; INMARSAT, ORB(vIC).	ite Systems: LEO and non-Geosysten COMM, Global Positionir	ns- RAD ng Systen	ARSAT, n (GPS),	8		
Total Hours 4								

	Textbooks
1.	Pratt and Bostian, "Satellite Communications", John Wiley & Sons. 3rd Edition, 2019.



Dennis Roddy, "*Satellite Communications*", McGraw-Hill, 4th Edition, 2017.
 Tri T. Ha, "*Digital Satellite Communications*", McGraw Hill, 2nd edition, 2009.

Mode of EvaluationTest / Quiz / Assignment / Mid Term Exam / End Term Exam.

Program Elective V

Page | 111



B. Tech in Electronics and Communication Engineering Semester Eighth Subject Title Testing of VLSI circuits Code REC Semester Eighth Subject Title Testing of VLSI circuits Code REC Program Elective 03 Contact Hours 3 0 0 Course (PEC) (V) 03 Weightage: Evaluation CWA MSE ESE Duration (Hrs) 03 Weightage: Evaluation CWA MSE ESE Duration (Hrs) 03 Weightage: Evaluation CWA MSE ESE CO T Recall the knowledge of fault modeling and fault simulation. CO 1 Recall the knowledge in understanding high-level testability Measures, SCOAP controllability and observability. CO 4 Analyse different memory testing algorithms. CO 5 Assess and evaluate scan architecture. CO 6 Design testing algorithms for VLSI components. 9 9 9 Unit No. Content Hours Hours 1 1 Defects, Errors, and Faults, Functional versus structural testing, Levels of fault models, Single stuck-at fault. Logic and Fault Simulation 9 9 9 1 Unit N		Department of Flootropics and Communication Engineering							
Semester Eighth Subject Title Testing of VLSI circuits Code TEC 852 Course Component Credits Contact Hours L T P Program Elective Course (PEC) (V) 03 Contact Hours 3 0 0 Examination Theory Weightage: Evaluation CWA MSE ESE Duration (Hrs) 03 Recall the knowledge of fault modeling and fault simulation. CO 1 Recall the knowledge of fault modeling and fault simulation. CO 2 CO 1 Recall the knowledge in understanding high-level testability Measures, SCOAP controllability and observability. CO 4 Analyse different memory testing algorithms. CO 5 CO 5 Assess and evaluate scan architecture. CO 6 Design testing, Digital and analog VLSI testing, VLSI technology trends affecting testing. 9 9 Introduction: Role of testing, Digital and analog VLSI testing, V		Department of Electronics and Communication Engineering							
Semester Eighth Subject Title Testing of VLSI circuits Code 1EC. Program Elective 03 Contact Hours 3 0 0 Course Component Theory Optimization 3 0 0 Duration (Hrs) 03 Weightage: Evaluation CWA MSE ESE Duration (Hrs) 03 Course Outcomes 23 25 50 Course Outcomes Upon completion of this course, the students will be able to CO 1 Recall the knowledge of fault modeling and fault simulation. CO 2 CO 2 Understand ATPG algorithm for combinational and sequential circuits CO 3 Apply the knowledge in understanding high-level testability Measures, SCOAP controllability and observability. CO 4 Analyse different memory testing algorithms. CO 5 Assess and evaluate scan architecture. CO 6 Design testing algorithms for VLSI components. 9 Unit No. Content Hours Introduction: Fault Modeling: 9 Unit 1: Defects, Errors, and Faults, Functional versus structural testing, Levels of fault models, A glosary of fault models, Single stuck-at fault. 10 Logic and Fault Simulation Simulation for design verification, Simulation for test ev			Tech in Electronics	ana Communication Eng	gineering		TEC		
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Program Elective Course (PEC) (V)03Contact Hours300Examination Duration (Hrs)Theory 03Weightage: Evaluation 25300Evamination Duration (Hrs)Theory 03Weightage: Evaluation 25300Course OutcomesUpon completion of this course, the students will be able to CO 1Course OutcomesUpon completion of this course, the students will be able toCourse OutcomesUnderstand ATPG algorithm for combinational and sequential circuitsCO 3Apply the knowledge in understanding high-level testability Measures, SCOAP controllability and observability.CO 4Analyse different memory testing algorithms.CO 6Design testing algorithms for VLSI components.Unit No.ContentHoursIntroduction: 	Course Co	mponent	Credits		L	Т	P		
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Examination Duration (Hrs)Theory 0.3Weightage: Evaluation CWA MSEESE 2550Pre-requisite: VLSI Technology and DesignCourse OutcomesUpon completion of this course, the students will be able toCOURSE OutcomesCOURSE OUTCOMESTINGCOURSE OUTCOMESTINGCOURSE OUTCOMESTINGCOURSE OUTCOMESTINGCOURSE OUTCOMESTINGCOURSE OUTCOMESTINGCOURSE OUTCOMESTINGCOURSE OUTCOMESTINGMale and Sequential circuitsCOOSAnalyse different memory testing algorithms.COOSAssess and evaluate scan architecture.COOSAssess and evaluate scan architecture.COOSIntroduction:Role of testing, Digital and analog VLSI testing, VLSI technology trends affecting testing.Fault Modeling:Tout Modeling:Tout Modeling:Simulation for design	Course (P	EC) (V)	03		3	0	0		
Duration (Hrs) 03 Presentage Evaluation 25 25 50 Pre-requisite: VLSI Technology and Design Course Outcomes Upon completion of this course, the students will be able to Course Outcomes CO 1 Recall the knowledge of fault modeling and fault simulation. CO 3 CO 2 Understand ATPG algorithm for combinational and sequential circuits SCOAP controllability and observability. CO 3 Apply the knowledge in understanding high-level testability Measures, SCOAP controllability and observability. Hours CO 4 Analyse different memory testing algorithms. CO 4 Hours CO 5 Assess and evaluate scan architecture. Hours Unit No. Content Hours Vinit No. Content Hours Vinit I: Defects, Errors, and Faults, Functional versus structural testing, Levels of fault models, A glossary of fault models, Single stuck-at fault. Logic and Fault Simulation: Simulation Testability Measures: S S SCOAP controllability and observability, High-level testability measures. S S Combinational Circuit Test Generation: S S	Examin	nation	Theory	Waightaga, Evaluation	CWA	MSE	ESE		
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Upon completion of this course, the students will be able to CO 1 Recall the knowledge of fault modeling and fault simulation. CO 2 Understand ATPG algorithm for combinational and sequential circuits CO 3 Apply the knowledge in understanding high-level testability Measures, SCOAP controllability and observability. CO 4 Analyse different memory testing algorithms. CO 5 Assess and evaluate scan architecture. CO 6 Design testing algorithms for VLSI components. Unit No. Content Hours Introduction: P Role of testing, Digital and analog VLSI testing, VLSI technology trends affecting testing. 9 Fault Modeling: 9 Unit 1: Defects, Errors, and Faults, Functional versus structural testing, Levels of fault models, A glossary of fault models, Single stuck-at fault. 9 Logic and Fault Simulation: Simulation for design verification, Simulation for test evaluation, Modeling circuits for simulation for design verification; Simulation (RID), Testing as a global problem, Definitions, Test generation systems, Test compaction, Significant combinational ATPG algorithms and sequential circuit test generation. 9 Unit 2: Algorithms and defect trends, Faults, Memory test levels, March test notation, Fault modeling, Memory testing. Analog and mixed signal test, Delay test and IDDQ test. 9 Un			Со	urse Outcomes					
C0 1 Recall the knowledge of fault modeling and fault simulation. C0 2 Understand ATPG algorithm for combinational and sequential circuits C0 3 Apply the knowledge in understanding high-level testability Measures, SCOAP controllability and observability. C0 4 Analyse different memory testing algorithms. C0 5 Assess and evaluate scan architecture. C0 6 Design testing algorithms for VLSI components. Unit No. Unit No. Content Hours Unit No. Content Hours Unit No. Content Hours Introduction: Fault Modeling: Paint Modeling: Introduction: Fault Modeling: Defects, Errors, and Faults, Functional versus structural testing, Levels of fault models, A glossary of fault models, Single stuck-at fault. Logic and Fault Simulation: SCOAP controllability and observability, High-level testability measures. Combinational Circuit Test Generation: <td colspan="</td> <td>Upon comp</td> <td>oletion of th</td> <td>his course, the stude</td> <td>ents will be able to</td> <td></td> <th></th> <td></td>	Upon comp	oletion of th	his course, the stude	ents will be able to					
C0 2 Understand ATPG algorithm for combinational and sequential circuits C0 3 Apply the knowledge in understanding high-level testability Measures, SCOAP controllability and observability. C0 4 Analyse different memory testing algorithms. C0 5 Assess and evaluate scan architecture. C0 6 Design testing algorithms for VLSI components. Unit No. Control Hours Hours Unit No. Control Hours Jesting algorithms for VLSI components. Unit No. Content Hours Introduction: Role of testing, Digital and analog VLSI testing, VLSI technology trends affecting testing. Fault Modeling: Defects, Errors, and Faults, Functional versus structural testing, Levels of fault models, A glossary of fault models, Single stuck-at fault. Logic and Fault Simulation Simulation for design verification, Simulation for test evaluation, Modeling circuits for simulation Testability Measures: SCOAP controllability and observability, High-level testability measures. <td cols<="" td=""><td>CO 1</td><td>Recall the</td><td>knowledge of fault n</td><td>nodeling and fault simulati</td><td>on.</td><th></th><td></td></td>	<td>CO 1</td> <td>Recall the</td> <td>knowledge of fault n</td> <td>nodeling and fault simulati</td> <td>on.</td> <th></th> <td></td>	CO 1	Recall the	knowledge of fault n	nodeling and fault simulati	on.			
C0 3 Apply the knowledge in understanding high-level testability Measures, SCOAP controllability and observability. C0 4 Analyse different memory testing algorithms. C0 5 Assess and evaluate scan architecture. C0 6 Design testing algorithms for VLSI components. Unit No. Content Hours of the testability Measures, SCOAP Content Hours of testing, algorithms for VLSI components. Unit No. Content Hours of testing, Digital and analog VLSI testing, VLSI technology trends affecting testing. Fault Modeling: Defects, Errors, and Faults, Functional versus structural testing, Levels of fault models, A glossary of fault models, Single stuck-at fault. Logic and Fault Simulation: Simulation for design verification, Simulation for test evaluation, Modeling circuits for simulation 8 Combinational Circuit Test Generation: Unit 2: Algorithms and representations, Redundancy Identification (RID), Testing as a global problem, Definitions, Test generation systems, Test compaction, Significant combinational ATPG algorithms and sequential circuit test generation. 9 Unit 3: Memory Test: notation, Fault modeling, Memory test levels, March test notation, Fault modeling, Memory te	<i>CO</i> 2	Understan	d ATPG algorithm f	for combinational and sequ	ential cir	cuits			
CO 4 Analyse different memory testing algorithms. CO 5 Assess and evaluate scan architecture. CO 6 Design testing algorithms for VLSI components. Unit No. Content Hours Introduction: 9 Role of testing, Digital and analog VLSI testing, VLSI technology trends affecting testing. 9 Unit 1: Defects, Errors, and Faults, Functional versus structural testing, Levels of fault models, A glossary of fault models, Single stuck-at fault. 9 Logic and Fault Simulation: Simulation for design verification, Simulation for test evaluation, Modeling circuits for simulation 8 Unit 2: Testability Measures: 8 SCOAP controllability and observability, High-level testability measures. 8 Combinational Circuit Test Generation: 8 Unit 2: Algorithms and representations, Redundancy Identification (RID), Testing as a global problem, Definitions, Test generation systems, Test compaction, Significant combinational ATPG algorithms and sequential circuit test generation. 9 Unit 3: Memory density and defect trends, Faults, Memory test levels, March test notation, Fault modelling, Memory testing. Analog and mixed signal test, Delay test and IDDQ test. 9 Unit 4: Euseign for test fundamentals. ATPQ fundamental, Scan architecture and technique. 8 <t< td=""><td>CO 3</td><td>Apply the controllabi</td><td>knowledge in und lity and observability</td><td>lerstanding high-level te y.</td><td>estability</td><th>Measures</th><td>, SCOAP</td></t<>	CO 3	Apply the controllabi	knowledge in und lity and observability	lerstanding high-level te y.	estability	Measures	, SCOAP		
CO 5 Assess and evaluate scan architecture. CO 6 Design testing algorithms for VLSI components. Unit No. Content Hours Introduction: Role of testing, Digital and analog VLSI testing, VLSI technology trends affecting testing. 9 Viii 1: Defects, Errors, and Faults, Functional versus structural testing, Levels of fault models, A glossary of fault models, Single stuck-at fault. 9 Unit 1: Defects, Errors, and Faults, Functional versus structural testing, Levels of fault models, A glossary of fault models, Single stuck-at fault. 8 Unit 1: Defects, Errors, and Faults, Functional versus structural testing, Modeling circuits for simulation: 8 Simulation for design verification, Simulation for test evaluation, Modeling circuits for simulation 8 SCOAP controllability and observability, High-level testability measures. 8 Combinational Circuit Test Generation: 8 Unit 2: Algorithms and representations, Redundancy Identification (RID), Testing as a global problem, Definitions, Test generation systems, Test compaction, Significant combinational ATPG algorithms and sequential circuit test generation. 9 Unit 3: Memory Test: 9 Unit 4: Fundamental Techniques for Logic Testing: 8 Delay test and IDDQ test. 8 Uni	<i>CO</i> 4	Analyse di	ifferent memory testi	ng algorithms.					
CO 6 Design testing algorithms for VLSI components. Unit No. Content Hours Introduction: 9 Role of testing, Digital and analog VLSI testing, VLSI technology trends affecting testing. 9 Fault Modeling: 9 Unit 1: Defects, Errors, and Faults, Functional versus structural testing, Levels of fault models, A glossary of fault models, Single stuck-at fault. 9 Logic and Fault Simulation: Simulation for design verification, Simulation for test evaluation, Modeling circuits for simulation 8 SCOAP controllability and observability, High-level testability measures. 8 Combinational Circuit Test Generation: 8 Unit 2: Algorithms and representations, Redundancy Identification (RID), Testing as a global problem, Definitions, Test generation systems, Test compaction, Significant combinational ATPG algorithms and sequential circuit test generation. 9 Unit 3: Memory Test: 9 Memory density and defect trends, Faults, Memory test levels, March test notation, Fault modelling, Memory testing. Analog and mixed signal test, Delay test and IDDQ test. 8 Unit 4: Design for test fundamentals, ATPQ fundamental, Scan architecture and technique. 8 Unit 5: Embedded Core Test Fundamentals: 8 Introduction to embedded core testing, Core-based	CO 5	Assess and	evaluate scan archi	tecture.					
Unit No. Content Hours Introduction: 9 Role of testing, Digital and analog VLSI testing, VLSI technology trends affecting testing. 9 Fault Modeling: Defects, Errors, and Faults, Functional versus structural testing, Levels of fault models, A glossary of fault models, Single stuck-at fault. 9 Unit 1: Defects, Errors, and Fault Simulation: Simulation for design verification, Simulation for test evaluation, Modeling circuits for simulation 8 SCOAP controllability measures: SCOAP controllability and observability, High-level testability measures. 8 SCOAP controllability and observability, High-level testability measures. 9 Unit 2: Algorithms and representations, Redundancy Identification (RID), Testing as a global problem, Definitions, Test generation systems, Test compaction, Significant combinational ATPG algorithms and sequential circuit test generation. 9 Unit 3: Memory Test: 9 Memory testi 9 Momory density and defect trends, Faults, Memory test levels, March test notation, Fault modelling, Memory testing. Analog and mixed signal test, Delay test and IDDQ test. 8 Unit 4: Design for test fundamentals, ATPQ fundamental, Scan architecture and technique. 8 Unit 5: Embedded Core Test Fundamentals: 8 Introduction to embedded core	CO 6	Design test	ting algorithms for V	LSI components.					
Unit No. Content Hours Introduction: Role of testing, Digital and analog VLSI testing, VLSI technology trends affecting testing. 9 Role of testing, Digital and analog VLSI testing, VLSI technology trends affecting testing. 9 Unit 1: Defects, Errors, and Faults, Functional versus structural testing, Levels of fault models, A glossary of fault models, Single stuck-at fault. 9 Logic and Fault Simulation: Simulation for design verification, Simulation for test evaluation, Modeling circuits for simulation 8 SCOAP controllability and observability, High-level testability measures. 8 Combinational Circuit Test Generation: 8 Unit 2: Algorithms and representations, Redundancy Identification (RID), Testing as a global problem, Definitions, Test generation systems, Test compaction, Significant combinational ATPG algorithms and sequential circuit test generation. 9 Unit 3: Memory Test: 9 Memory testing, Memory testing. Analog and mixed signal test, Delay test and IDDQ test. 8 Unit 4: Embedded Core Test Fundamentals: 8 Unit 5: Introduction to embedded core testing, Core-based design, Core DFT development, Chip design with a core, Scan testing the isolated core, Scan testing the non-core logic, Memory testing with BIST. <td></td> <td></td> <td></td> <td>•</td> <td></td> <th></th> <td></td>				•					
Introduction:9Role of testing, Digital and analog VLSI testing, VLSI technology trends affecting testing. Fault Modeling: Defects, Errors, and Faults, Functional versus structural testing, Levels of fault models, A glossary of fault models, Single stuck-at fault. Logic and Fault Simulation: Simulation for design verification, Simulation for test evaluation, Modeling circuits for simulation8Unit 1:Testability Measures: SCOAP controllability and observability, High-level testability measures. Combinational Circuit Test Generation: Algorithms and representations, Redundancy Identification (RID), Testing as a global problem, Definitions, Test generation systems, Test compaction, Significant combinational ATPG algorithms and sequential circuit test 	Unit No.	Content					Hours		
Unit 2:Testability Measures: SCOAP controllability and observability, High-level testability measures. Combinational Circuit Test Generation: Algorithms and representations, Redundancy Identification (RID), Testing as a global problem, Definitions, Test generation systems, Test compaction, Significant combinational ATPG algorithms and sequential circuit test generation.9Unit 3:Memory Test: notation, Fault modelling, Memory testing. Analog and mixed signal test, Delay test and IDDQ test.9Unit 4:Fundamental Techniques for Logic Testing: Design for test fundamentals, ATPQ fundamental, Scan architecture and technique.8Unit 5:Embedded Core Test Fundamentals: Introduction to embedded core testing, Core-based design, Core DFT development, Chip design with a core, Scan testing the isolated core, Scan testing the non-core logic, Memory testing with BIST.8	Unit 1:	Introduction: Role of testing, Digital and analog VLSI testing, VLSI technology trends affecting testing. Fault Modeling: Defects, Errors, and Faults, Functional versus structural testing, Levels of fault models, A glossary of fault models, Single stuck-at fault. Logic and Fault Simulation: Simulation for design verification, Simulation for test evaluation, Modeling							
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Unit 4: Fundamental Techniques for Logic Testing: 8 Unit 4: Design for test fundamentals, ATPQ fundamental, Scan architecture and technique. 8 Unit 5: Embedded Core Test Fundamentals: 8 Introduction to embedded core testing, Core-based design, Core DFT development, Chip design with a core, Scan testing the isolated core, Scan testing the non-core logic, Memory testing with BIST. 42	Unit 3:	Memory 1 Memory d notation, F Delay test	Fest: ensity and defect tre Fault modelling, Mer and IDDQ test.	ends, Faults, Memory test mory testing. Analog and	levels, M mixed si	larch test gnal test,	9		
Unit 5: Embedded Core Test Fundamentals: 8 Introduction to embedded core testing, Core-based design, Core DFT development, Chip design with a core, Scan testing the isolated core, Scan testing the non-core logic, Memory testing with BIST. 8	Unit 4:	Fundamen Design for technique.	test fundamentals,	Logic Testing: ATPQ fundamental, Scar	n archited	cture and	8		
	Unit 5:	Embedded Introductio developme testing the	d Core Test Fundan on to embedded co ont, Chip design with non-core logic, Mem	nentals: re testing, Core-based d a core, Scan testing the in nory testing with BIST.	esign, Co solated co	ore DFT ore, Scan	8		



	Textbooks				
1.	Viswani D. Agarval Michael L. Bushnell, "Essentials of electronic testing for digital memory				
	& mixed signal VLSI circuit", Kluwer Academic Publications, 1999.				
2.	Alfred L. Crouch, "Design for test for digital IC's and embedded core systems", PHI, 1999.				
	Reference Books				
3.	Parag. K. Lala, "Digital circuit testing and testability", Academic Press, 1997.				
4.	Ashok K. Sharma, "Semiconductor memories technology, testing and reliability", Prentice-				
	Hall of India Private Limited, New Delhi, 1st edition, 1997.				

Mode of EvaluationTest / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Department of Electronics and Communication Engineering							
	B.	Tech in Electronics	and Communication Eng	gineering				
Semester	Eighth	Subject Title	Digital System using V	/HDL	Code	TEC 853		
Course C	omponent	Credits		L	Т	Р		
Program Course (1	Elective PEC) (V)	03	Contact Hours	3	0	0		
Exami	nation	Theory		CWA	MSE	ESE		
Duratio	n (Hrs)	03	Weightage: Evaluation	25	25	50		
		Pre-requis	tite: Digital Electronics					
		Со	urse Outcomes					
Upon com	pletion of tl	nis course, the stude	ents will be able to					
CO 1	Understan	d VHDL including	code structure.					
CO 2	Describe of with SM cl	lata type operators a hart, data type, opera	and attributes for arithmeti tion and component	c's opera	tions, digi	tal design		
<i>CO 3</i>	Analyse cu	irrent code, sequenti	al code, packages and com	ponents.				
<i>CO</i> 4	Design net	work for mathematic	cs operations, digital design	n with SN	I chart			
CO 5	Analyse fl	oating-point arithme	tic and design examples.					
CO 6	Apply con	cepts of Digital syste	em design using VHDL.					
	<i>a</i>							
Unit No.	<i>Content</i>			1	1	Hours		
Unit 1:	Introduction To VHDL: Design Flow, EDA Tools, and Translation of VHDL code into a circuit. Code Structure: Fundamental VHDL Units, LIBRARY Declarations, ENTITY, ARCHITECTURE, VHDL Design Methodology.							
Unit 2:	 Data Types: Pre-Defined Data Types, User-Defined Data Types, Subtypes, Arrays, Port Array, Records, Signed and Unsigned Data Types, Data Conversion. Operators and Attributes: Operators, Attributes, User-Defined Attributes, Operator Overloading, GENERIC 							
Unit 3:	Concurrent Code: Concurrent versus Sequential, Using Operators, WHEN, GENERATE, BLOCK, Sequential Code: PROCESS, Signals and Variables, IF, WAIT, CASE, LOOP, CASE versus IF, CASE versus WHEN, Using Sequential Code to Design Combinational Circuits, Signals and Variables: CONSTANT, SIGNAL, VARIABLE, Number of Registers. Packages and Components: Introduction, PACKAGE, COMPONENT, PORT MAP, GENERIC MAP. Functions and Procedures: FUNCTION, Function Location, PROCEDURE, Procedure Location, FUNCTION versus PROCEDURE, ASSERT.							
Unit 4:	Design Of Networks For Arithmetic Operations: Design of serial adder with accumulator, state graph for control networks design of Binary Multiplier, multiplication of signed binary numbers, design of binary divider. Digital Design With SM Chart: State machine charts, derivation of SM charts, realizations of SM charts, implementation of dice game.							
Unit 5:	Floating I floating po	Point Arithmetic: int multiplication, ar	Representation of floatin	g point ations.	numbers,	7		



	Design	Examp	les:	UA	RT	design,	descri	ption	of	M	C68HC05	
	microcor	ntroller,	desig	gn	of	microcon	troller	CPU,	an	d	complete	
	microcor	nuonei u	corgn.									
Total Hours								<i>/</i> 11				

Total Hours

	Textbooks				
1.	Volnei A. Pedroni, "Circuit Design With VHDL", MIT Press, 2004.				
2.	Charles H Roth Jr, "Digital System Design using VHDL", Thomson Learning, 2002.				
3.	Jayaram Bhasker, "A VHDL Primer", III edition, Prentice Hall, 2007.				
	Reference Books				
4.	Stephen Brown & Zvonko Vranesic, "Fundamentals of digital logic design with VHDL", TMH, 2nd Ed., 2007				
5.	Douglas L. Perry, "VHDL: Programming by Example", 4 th edition, Tata Mcgraw-hill, July 2002.				
6.	Jhon F Wakerly, "Digital design", PHI, 4th Edition.				

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



Department of Electronics and Communication Engineering									
B. Tech in Electronics and Communication Engineering									
Semester	Eighth	Subject Title	Digital Image Proces	sing	Code	TEC 854			
Course C	Component	Credits		L	Т	Р			
Program Course (n Elective (PEC) (V)	03	Contact Hours	3	0	0			
Exam	ination	Theory	Weightage, Englugtion	CWA	MSE	ESE			
Durati	on (Hrs)	03	weigniage: Evaluation	25	25	50			
Pre-requisite: Signals and Systems, Digital Signal Processing									
		Сог	irse Outcomes						
Upon com	pletion of th	is course, the stude	nts will be able to						
CO 1	Recall the b	asics of images forn	nation.						
<i>CO</i> 2	Understand	the different image	transformation technique.						
<i>CO 3</i>	Apply imag	e restoration and rec	construction.						
<i>CO</i> 4	Analyse mo	orphological operation	n.						
<i>CO</i> 5	Assess and evaluate different image segmentation techniques.								
<i>CO 6</i> Design and implement algorithms for image processing.									
Unit No.	Content					Hours			
Unit 1:	 Introduction to the Digital Image Processing: Areas and applications, Elements of visual perception, Image sensing and acquisition, Image sampling and quantization, Basic relationships between pixele: Naighbourhoods. Adjacency and distances 								
Unit 2:	2: Intensity Transformations, Histogram modeling; Equalization and modification, Spatial filtering: Smoothing spatial filters and sharpening spatial filters. Image smoothing using frequency domain filters.								
Unit 3:	Image Restoration and Reconstruction:8Model of the image degradation/restoration process, Noise models, Restoration by spatial filtering, Periodic noise reduction by frequency domain filtering, Inverse filtering, Minimum mean square error (Wiener) filtering								
Unit 4:	Morpholog Erosion an transformati components	Morphological Image Processing: 8 Erosion and dilation, Duality, Opening and closing, the Hit-or-Miss transformation, Boundary extraction, Hole filling, Extraction of connected components.							
Unit 5:	Image Segn Detection o Thresholdin Fourier desc	nentation, Represent f isolated points, Li g, Region-based se criptors, and Statistic	ntation and Description: ne detection, Edge models gmentation, Chain codes, cal moments.	s, Edge d Shape 1	letection, numbers,	8			
	Total Hours 4								

	Textbooks					
1.	Rafael C. Gonzalez, Richard E. Woods, "Digital Image Processing", 3rd Edition, Prentice Hall;					
	ISBN: 013168728X, 2007.					
2.	Al Bovik editor, "Handbook of Image & Video Processing", ISBN 0-12-119790-5, Academic					
	Press, San Diego., 2000.					
	Reference Books					



- 3. Rafael C. Gonzalez, Richard E. Woods, and S. L. Eddins, "*Digital Image Processing Using MATLAB*", Prentice Hall, ISBN 0130085197, 2004.
- **4.** Anil K. Jain, "*Fundamentals of digital image processing*", Englewood Cliffs, NJ: Prentice Hall, 1989.

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Dep	artment of Electron	ics and Communication E	ngineerir	ıg				
B. Tech in Electronics and Communication Engineering									
Semester	Eighth	Subject Title	Telecommunication Sw	itching	Code	TEC 855			
Course C	omponent	Credits		L	Т	Р			
Program Course (l	Elective PEC) (VI)	03	Contact Hours	3	0	0			
Exam	ination	Theory	Weightage, Evaluation	CWA	MSE	ESE			
Duratio	on (Hrs)	03	weignlage: Evaluation	25	25	50			
Pre-requisite: Communication Systems I and Communication Systems II									
		Co	ourse Outcomes						
Upon com	pletion of t	his course, the stude	ents will be able to						
CO 1	Understar	nd modern telecomm	unication network and its l	neterogen	eous switc	ching.			
<i>CO</i> 2	Apply the	concepts of traffic er	ngineering to telecommuni	cation ne	twork.				
CO 3	Analyse S systems.	ingle stage and Mu	ltistage switch networks	& single	and dual	processor			
<i>CO</i> 4	Estimate t	he performance of te	elecommunication network	s.					
<i>CO</i> 5	Design cire	cuit switched networ	ks with packet switched ne	etworks.					
CO 6	Apply the switching	concepts of netwo networks.	ork and traffic engineerin	g in tele	communic	ation and			
	-								
Unit No.	Content					Hours			
Unit 1:	Introduction: Evolution of public switched telecommunication, Simple telephone communication, Basic of switching system, Concept of Strowger and crossbar switching								
Unit 2:	 Electronic Space Division Switching: Stored program control, Centralized and distributed SPC, Software architecture, Application software, Enhanced software, Two and three stage networks. Time Division Switching: Sampling, Quantization, Encoding, Basic time division space switching, Basic time division time switching, Time multiplexed space and time 								
Unit 3:	Switching, Combination switching. Traffic Engineering: Network traffic load and parameters, Grade of service, Modeling switching, Incoming traffic, Common channel signalling, SS7 signalling protocols. Telephone Networks: Subscriber loop system, Switching hierarchy and routing, Transmission plan, Transmission system, Signaling techniques.								
Unit 4:	Integrated Digital Network: Digital multiplexing techniques-(Time division multiplexing, Frequency division multiplexing), TDMA, FDMA and CDMA, Concept of ISDN, ISDN standards, Cellular mobile communication.								
Unit 5:	standards, Cellular mobile communication.Data Networks:Data transmission in PSTN, Switching techniques, Data communication architecture, Link to link layers, End to end layers, OSI Architecture, 8 satellite-based data networks, LAN, MAN standards, TCP/IP, Internet, Principle of ATM networks.								
		IUtal	110015			- T U			



	Textbooks			
1.	Thiagarajan Viswanathan, "Telecommunication switching systems and Networks", Prentice			
	Hall of India LTD, 2000.			
2.	Forouzen, "Data Communications and Networking", 3rd Edition, TMH, 2004.			
	Reference Books			
3.	J. E. Flood, "Telecommunications Switching, Traffic and Networks", Pearson Education,			
	2006			

Mode of Evolution	Test / Ouiz / Assignment / Mid Term Exem / End Term Exem
Nioue of Evaluation	rest / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Den	artment of Flectroni	es and Communication F	nainoorii	10	
	R R	Tech in Flectronics	and Communication Fro	inoorina	5	
		Teen in Electronics	Neural Networks & M	chine		TEC
Semester Eighth		Subject Title	Learning	ichine	Code	856
Course Component		Credits		L	Т	Р
Program Elective		03	Contact Hours	3	0	0
Evami	nation	Theory		CWA	MSE	ESE
Duratio	n (Hrs)	03	Weightage: Evaluation	25	25	50
2 11 11 10	Pro_ro	auisite · Basic Proba	hility Theory and Basic Li	near Alge	-25 hra	50
	11010	Co	urse Outcomes			
Upon com	pletion of th	nis course, the stude	ents will be able to			
CO 1	Understan	d the basics of neura	al network and its parameter	ers.		
<i>CO</i> 2	Examine t	he feed forward netw	vork and its implementation	n.		
CO 2	Analyse th	e concepts of pattern	analysis and implementat	ion of su	oport vecto	or
<i>CO</i> 3	machine.		, I			
<i>CO</i> 4	Investigat	e self-organizing ma	p and pattern clustering.			
<i>CO</i> 5	Evaluate d	lifferent feedback ne	twork, such as Hopfield, B	oltzmanr	machine.	
CO 6	Develop ne	eural network for spe	ecific applications.			
Unit No.	Content					Hours
Unit 1:	Introducti Biological tasks: Class neurons, S Unsupervis Linear Mo Polynomia models, B squares for	on to Artificial Neu neural networks, A ssification, Regressio tructures of neural sed and reinforcemer odels of Learning an l curve fitting, Bay ias-variance decomp r classification, Log	Tral Networks : NN application overview on and clustering, Comput networks, Learning princ nt learning. Id Classification : yesian curve fitting, Line position, Bayesian linear istic regression for classif	, Pattern ational n iples, Su ar basis regressio fication,	analysis nodels of pervised, function on, Least Bayesian	12
Unit 2:	Iogistic regression for classification.Feed Forward Neural Networks: Pattern classification using perceptron, Multilayer feed forward neural networks (MLFNNs), Pattern classification using MLFNNs, error and back propagation learning, Fast learning methods: Conjugate gradient method, Auto-associative neural networks, Bayesian neural networks.			8		
Unit 3:	Radial Basis Function Networks: Regularization theory, RBF networks for function approximation, RBF networks for pattern classification.3:Kernel Methods for Pattern Analysis: Statistical learning theory, Support vector machines for pattern classification, Support vector regression for function approximation, Relevance vector machines for classification and regression.8			8		
Unit 4:	Self-Organ Pattern clu Competitiv networks, A	nizing Maps: Istering, Topological ve learning, Learnir Adaptive Resonance	mapping, Kohonen's sel ng vector quantizers, Con Theory (ART).	f organiz unter pro	ing map, pagation	6
<i>Unu 3</i> :	recuback	iveural ivetworks:				U



Recurren	nt neural	netwo	orks.	порпеіа	model,	Donzinann	machine,	
Applica	tions of 1	Neura	al Network	s and Ma	chine Le	arning:		
Case stu	dies.							
			Total H	ours				40

Textbooks 1. S. Haykin, "Neural Networks – A Comprehensive Foundation", Prentice Hall of India, 2^{ed} edition, 2003 2. Satish Kumar, "Neural Networks – A Classroom Approach', McGraw Hill Education, 2nd edition, 2017. Reference Books 3. S. Haykin "Neural Networks & Learning Machines", Pearson Education India, 3rd edition, 2016. 4. L. Fausett, "Fundamentals of Neural Networks: Architectures, Algorithms and Applications", Pearson Education India, 1st edition, 2004.

Mode of Evaluation Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Dep	artment of Electroni	cs and Communication E	ngineerin	ıg	
	<u> </u>	Tech in Electronics	and Communication Eng	ineering	0	
Semester Eighth		Subject Title	Mobile Ad hoc Netw	orks	Code	TEC 857
Course Component		Credits		L	Т	Р
Program Elective Course (PEC) (VI)		03	Contact Hours	3	0	0
Examination		Theory		CWA	MSE	ESE
Duration (Hrs)		03	Weightage: Evaluation	25	25	50
Pre-requisite: Wireless Communication						
		Со	urse Outcomes			
Upon com	pletion of tl	his course, the stude	ents will be able to			
CO 1	Understan Max), Blue issues and	Id the concept of ad h etooth, IrDA, RF hor available solution.	oc wireless networking, IE ne, design and operation or	EE 802.1 f ad hoc r	1, IEEE 80 network, th	02.16 (Wi- eir design
<i>CO 2</i>	Understan	d MAC layer protoc	ols and design issues of M	AC proto	ocols.	
CO 3	Understan mechanism	id and remember pro	pactive, reactive and hybrid	l routing p	protocols a	nd routing
<i>CO</i> 4	Understan	d energy manageme	nt in ad hoc network.			
<i>CO</i> 5	Understan	d Security attacks and	nd QoS provisioning in ad	hoc netw	ork.	
CO 6	Develop an	nd design efficient w	vireless mobile ad hoc netw	vorks.		
Unit No.	Content					Hours
Unit 1:	Introduction: Ad hoc networking: An introduction. Model of operation, Symmetric links, Fundamental of wireless networks, Bluetooth, IrDA, Comparison of bluetooth and IrDA, Home RF, 802.11, 802.16(Wi-Max), Hotspot, Difference between cellular and ad hoc networks, Technical and research challenges. DoD perspective.				8	
Unit 2:	MAC Layer Protocols for Ad hoc wireless Networks:Need for Medium Access Control(MAC) Protocols, Issues and design goals of MAC protocols, Classification of MAC protocols: Contention based MAC protocols, Contention based MAC protocols with reservation mechanism, Multiple Access Collision Avoidance (MACA), Media Access Protocol for wireless (MACAW), Floor Acquisition Multiple Access Protocols (FAMA), Busy Tone Multiple Access Protocols (BTMA), Multiple Access Collision Avoidance – by Invitation(MACA-BI), Dual Busy Tone Multiple Access Protocols (DBTMA), Multichannel Carrier sense Multiple access (CSMA) MAC Protocol.10				10	
Unit 3:	Routing Protocol.Routing Protocols: Design issues of routing protocols, Ideal characteristics of routing, Classification of routing protocols: Proactive, Reactive, Hybrid. Overview of DSDV (Destination sequenced distance vector) Routing protocol, Link state, Distance vector, DSDV properties and its merits demerits, Damping fluctuations. Clustering, Hierarchical routing.12 <i>nit 3:</i> fluctuations. Clustering, Hierarchical routing. Overview of DSR (Dynamic Source Routing) protocols: DSR properties, Additional route discovery and maintenance features. Overview of AODV (Ad Hoc On Demand Distance vector) Protocols, Unicasting, Multicasting, Unicast route establishment, Multicasting route establishment, Expanding ring search. Overview of ZRP (Zone Routing Protocol). Reconfigurable			12		



	solutions. Wireless sensor networks, Issues and challenges, Sensor network architecture, Flooding gossiping, Rumor routing, Quality of sensor networks, Evolving standards.	
Unit 5:	Network Security Attacks and Quality of Service Security in Ad Hoc wireless networks, Network security requirements, Issues and challenges in security provisioning, Network security attacks. QoS in Ad Hoc wireless networks, Issues and challenges, Classification of OoS	7
Unit 4:	Energy management Energy management system in Ad Hoc networks, Power issues, Smart batteries, and Associatively based routing, Effects of beaconing of battery life, Maximum lifetime routing.	5
	wireless networks, Intrazone, Interzone routing protocols. Overview of OLSR (Optimized Link State Routing) Protocol, Multipoint relays (MPRs), Protocol functioning, Core functioning.	

	Textbooks				
1.	C. Perkins, "Ad Hoc Networking", Addison-Wesley Professional,1st Edition, 2008.				
2.	C. Siva Ram Murthy, and B. S.Manoj, "Ad Hoc Wireless Networks Architecture and				
	<i>Protocols</i> ", Pearson Education 2 nd Edition, 2004.				
	Reference Books				
3.	S. Basagni, And M. Conti, "Mobile Ad Hoc Networking: Cutting Edge Directions", John				
	Wiley & Sons, 2 nd Edition, 2013.				

Mode of Evaluation	Test / Quiz / Assignment / Mid Term Exam / End Term Exam.



	Dep	artment of Electroni	cs and Communication E	ngineerin	ıg	
	B. Tech in Electronics and Communication Engineering					
Semester Eighth		Subject Title	Adaptive Signal Proce	essing	Code	TEC 858
Course Component		Credits		L	Т	Р
Program Course (l	Elective PEC) (VI)	03	Contact Hours	3	0	0
Examination		Theory	Weichtness Fugle stiers	CWA	MSE	ESE
Duratio	on (Hrs)	03	weignlage: Evaluation	25	25	50
		Pre-requisite:	Digital Signal Processing			
		Со	urse Outcomes			
Upon com	pletion of the	nis course, the stude	ents will be able to			
CO 1	Create and	l visualize the domai	n of adaptive signal proces	ssing.		
<i>CO 2</i>	Identify a	random process and	formulate to extract desire	ed inform	ation.	
<i>CO 3</i>	Develop al	gorithms meeting ap	plication specific performation	ance crite	ria.	
<i>CO</i> 4	Implemen	t the adaptive algorit	hms in software/Hardware			
CO 5	Analyse come up w	onvergence and stab ith optimum solutior	bility issues associated wins for real life applications.	th adapti	ve filter d	esign and
CO 6 Design and implement filtering solutions for applications, such as channel equalis interference cancelling and prediction considering present day challenges.				ualisation,		
		<u> </u>	01		0	
Unit No.	Content					Hours
Unit 1:	Adaptive Systems: Definitions and characteristics - Applications – Properties-Examples - Adaptive linear combiner input signal and weight vectors - Performance function-Gradient and minimum mean square error - Introduction to filtering-Smoothing and prediction - Linear optimum filtering-Orthogonality - Wiener – Hopf equation-Performance surface			8		
Unit 2:	2: Searching Performance Surface-Stability and Rate Of Convergence: Learning curve-Gradient search - Newton's method - Method of steepest descent - Comparison - Gradient estimation - Performance penalty - Variance - Excess MSE and time constants – Mis-adjustments					
	descent - C - Excess M	curve-Gradient searc omparison - Gradien SE and time constan	ce-Stability and Rate Of h - Newton's method - N t estimation - Performance tts – Mis-adjustments	Converg lethod of penalty -	ence: steepest Variance	8
Unit 3:	descent - C - Excess M LMS algor LMS/New Adaptive F Adaptive f	curve-Gradient searc omparison - Gradien SE and time constan rithm convergence of ton algorithm - Pro Recursive filters - Ra ilters with orthogona	ce-Stability and Rate Of h - Newton's method - M t estimation - Performance its – Mis-adjustments of weight vector: perties - Sequential regre ndom-search algorithms - l signals	Converg Iethod of penalty - ession alg Lattice s	steepest Variance orithm - tructure -	8
Unit 3: Unit 4:	descent - C - Excess M LMS algor LMS/New Adaptive F Adaptive f Adaptive f Application Multipath filter synth	surve-Gradient searc omparison - Gradien (SE and time constant rithm convergence of ton algorithm - Pro- Recursive filters - Ra ilters with orthogona ns-adaptive modeli communication cha esis	ce-Stability and Rate Of h - Newton's method - N t estimation - Performance tts – Mis-adjustments of weight vector: perties - Sequential regre ndom-search algorithms - <u>l signals</u> ng and system identificat nnel, Geophysical explor	Converg Iethod of penalty - ession alg Lattice s ion: ation, FI	steepest Variance orithm - tructure - R digital	8 8 8
Unit 3: Unit 4: Unit 5:	descent - C - Excess M LMS algo LMS/New Adaptive F Adaptive f Adaptive f Applicatio Multipath filter synth Inverse ad Equalizatio channels-a	surve-Gradient searc omparison - Gradien ISE and time constan rithm convergence of ton algorithm - Pro Recursive filters - Ra ilters with orthogona ons-adaptive modelin communication cha esis aptive modeling: on, and deconvolu dapting poles and zer	tee-Stability and Rate Of h - Newton's method - M t estimation - Performance its – Mis-adjustments of weight vector: perties - Sequential regree ndom-search algorithms - l signals ng and system identificat nnel, Geophysical explor tion adaptive equalization to for IIR digital filter syn	Converg Iethod of penalty - ession alg Lattice st ion: ation, FI on of t thesis	ence: steepest Variance orithm - tructure - R digital elephone	8 8 8 8 8

	Textbooks			
1.	Simon Haykins, "Adaptive Filter Theory", Pearson Education, 5th Edition, 2013.			
2.	D. G. Manolakis, V.K. Ingle, S.M. Kogon, "Adaptive Signal Processing", McGraw-Hill, 2000.			
	Reference Books			



3.	Todd K. Moon, Wynn C. Stirling, "Mathematical Methods and Algorithms for Signal
	<i>Processing</i> " Prentice Hall, 1 st edition, 1999.
4.	John. R. Triechler, C. Richard Johnson (Jr), Michael. G. Larimore, "Theory and Design of
	Adaptive Filters", Prentice Hall India Private Limited, 2004.

Mode of EvaluationTest / Quiz / Assignment / Mid Term Exam / End Term Exam.